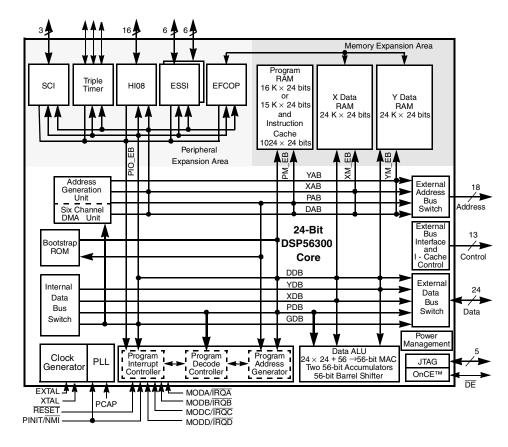
DSP56L307

24-Bit Digital Signal Processor



The DSP56L307 is intended for applications requiring a large amount of internal memory, such as networking and wireless infrastructure applications. The EFCOP can accelerate general filtering applications, such as echo-cancellation applications, correlation, and general-purpose convolutionbased algorithms.

What's New? Rev. 6 includes the following

changes:

• Adds lead-free packaging and part numbers.

Figure 1. DSP56L307 Block Diagram

The Freescale DSP56L307, a member of the DSP56300 DSP family, supports network applications with general filtering operations. The Enhanced Filter Coprocessor (EFCOP) executes filter algorithms in parallel with core operations, enhancing signal quality with no impact on channel throughput or total channels supported. The result is increased overall performance. Like the other DSP56300 family members, the DSP56L307 uses a high-performance, single-clock-cycle-per- instruction engine (DSP56000 code-compatible), a barrel shifter, 24-bit addressing, an instruction cache, and a direct memory access (DMA) controller (see **Figure 1**). The DSP56L307 performs at up to 160 million multiply-accumulates per second (MMACS), attaining up to 320 MMACS when the EFCOP is in use. It operates with an internal 160 MHz clock with a 1.8 volt core and independent 3.3 volt input/output (I/O) power.

Note: This document contains information on a new product. Specifications and information herein are subject to change without notice.



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Appendix A Power Consumption Benchmark

Data Sheet Conventions

OVERBARIndicates a signal that is active when pulled low (For example, the RESET pin is active when
low.)"asserted"Means that a high true (active high) signal is high or that a low true (active low) signal is low

"deasserted" Means that a high true (active high) signal is low or that a low true (active low) signal is high

Examples:	Signal/Symbol	Logic State	Signal State	Voltage
	PIN	True	Asserted	V _{IL} /V _{OL}
	PIN	False	Deasserted	V _{IH} /V _{OH}
	PIN	True	Asserted	V _{IH} /V _{OH}
	PIN	False	Deasserted	V _{IL} /V _{OL}
				

Note: Values for V_{IL} , V_{OL} , V_{IH} , and V_{OH} are defined by individual product specifications.



Features

 Table 1 lists the features of the DSP56L307 device.

Feature	Description							
High-Performance DSP56300 Core	 160 million multiply-accumulates per second (MMACS) (320 MMACS using the EFCOP in filtering applications) with a 160 MHz clock at 1.8 V core and 3.3 V I/O Object code compatible with the DSP56000 core with highly parallel instruction set Data arithmetic logic unit (Data ALU) with fully pipelined 24 × 24-bit parallel multiplier-accumulator (MAC), 56-bit parallel barrel shifter (fast shift and normalization; bit stream generation and parsing), conditional ALU instructions, and 24-bit or 16-bit arithmetic support under software control Program control unit (PCU) with position-independent code (PIC) support, addressing modes optimized for DSP applications (including immediate offsets), internal instruction cache controller, internal memory-expandable hardware stack, nested hardware DO loops, and fast auto-return interrupts Direct memory access (DMA) with six DMA channels supporting internal and external accesses; one-, two-and three-dimensional transfers (including circular buffering); end-of-block-transfer interrupts; and triggering from interrupt lines and all peripherals Phase-lock loop (PLL) allows change of low-power divide factor (DF) without loss of lock and output clock with skew elimination Hardware debugging support including on-chip emulation (OnCE) module, Joint Test Action Group (JTAG) test access port (TAP) 							
Enhanced Filter Coprocessor (EFCOP)	 Internal 24 × 24-bit filtering and echo-cancellation coprocessor that runs in parallel to the DSP core Operation at the same frequency as the core (up to 160 MHz) Support for a variety of filter modes, some of which are optimized for cellular base station applications: Real finite impulse response (FIR) with real taps Complex FIR with complex taps Complex FIR generating pure real or pure imaginary outputs alternately A 4-bit decimation factor in FIR filters, thus providing a decimation ratio up to 16 Direct form 1 (DFI) Infinite Impulse Response (IIR) filter Four scaling factors (1, 4, 8, 16) for IIR output Adaptive FIR filter with true least mean square (LMS) coefficient updates Adaptive FIR filter with delayed LMS coefficient updates 							
Internal Peripherals	 Enhanced 8-bit parallel host interface (HI08) supports a variety of buses (for example, ISA) and provides glueless connection to a number of industry-standard microcomputers, microprocessors, and DSPs Two enhanced synchronous serial interfaces (ESSI), each with one receiver and three transmitters (allows six-channel home theater) Serial communications interface (SCI) with baud rate generator Triple timer module Up to 34 programmable general-purpose input/output (GPIO) pins, depending on which peripherals are enabled 							
192 × 24-bit bootstrap ROM 192 K × 24-bit RAM total Program RAM, instruction cache, X data RAM, and Y data RAM sizes are programmable: Program RAM Instruction X Data RAM Y Data RAM Instruction Switch N			: MSW1	MSWO				
	Size 16 K × 24-bit	Cache Size	Size* 24 K × 24-bit	Size* 24 K × 24-bit	Cache disabled	Mode disabled	0/1	0/1
	$15 \text{ K} \times 24$ -bit	1024 × 24-bit	$24 \text{ K} \times 24$ -bit $24 \text{ K} \times 24$ -bit	$24 \text{ K} \times 24$ -bit 24 K × 24-bit	enabled	disabled		0/1
	48 K × 24-bit	0	$8 \text{ K} \times 24$ -bit	8 K × 24-bit	disabled	enabled		0
Internal Memories	47 K × 24-bit	1024 × 24-bit	8 K × 24-bit	8 K × 24-bit	enabled	enabled		0
	40 K × 24-bit	0	12 K × 24-bit	12 K × 24-bit	disabled	enabled		1
	39 K imes 24-bit	1024 imes 24-bit	$12 \text{ K} \times 24 \text{-bit}$	12 K \times 24-bit	enabled	enabled	0	1
	$32 \text{ K} \times 24 \text{-bit}$	0	16 K × 24-bit	16 K \times 24-bit	disabled	enabled	1	0
	31 K × 24-bit	1024×24 -bit	16 K × 24-bit	$16 \text{ K} \times 24 \text{-bit}$	enabled	enabled		0
	24 K × 24-bit	0	20 K × 24-bit	20 K × 24-bit	disabled	enabled		1
	23 K × 24-bit	1024 × 24-bit	20 K × 24-bit	20 K × 24-bit	enabled	enabled		1
	*Includes 4 K \times 24-bit shared memory (that is, memory shared by the core and the EFCOP)							

Table 1.	DSP56L307	Features
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Table 1.	DSP56L307 Features	(Continued)
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Feature	Description
External Memory Expansion	 Data memory expansion to two 256 K × 24-bit word memory spaces using the standard external address lines Program memory expansion to one 256 K × 24-bit words memory space using the standard external address lines External memory expansion port Chip select logic for glueless interface to static random access memory (SRAMs) Internal DRAM Controller for glueless interface to dynamic random access memory (DRAMs) up to 100 MHz operating frequency
Power Dissipation	 Very low-power CMOS design Wait and Stop low-power standby modes Fully static design specified to operate down to 0 Hz (dc) Optimized power management circuitry (instruction-dependent, peripheral-dependent, and mode-dependent)
Packaging	Molded array plastic-ball grid array (MAP-BGA) package in lead-free or lead-bearing versions.

Target Applications

- Wireless and wireline infrastructure applications
- Multi-channel wireless local loop systems
- DSP resource boards
- High-speed modem banks
- Packet telephony

Product Documentation

The documents listed in **Table 2** are required for a complete description of the DSP56L307 device and are necessary to design properly with the part. Documentation is available from a local Freescale distributor, a Freescale semiconductor sales office, or a Freescale Semiconductor Literature Distribution Center. For documentation updates, visit the Freescale DSP website. See the contact information on the back cover of this document.

Name	Description	Order Number
DSP56L307 User's Manual	Detailed functional description of the DSP56L307 memory configuration, operation, and register programming	DSP56L307UM
DSP56300 Family Manual	Detailed description of the DSP56300 family processor core and instruction set	DSP56300FM
Application Notes	Documents describing specific applications or optimized device operation including code examples	See the DSP56L307 product website

Table 2. DSP56L307 Documentation

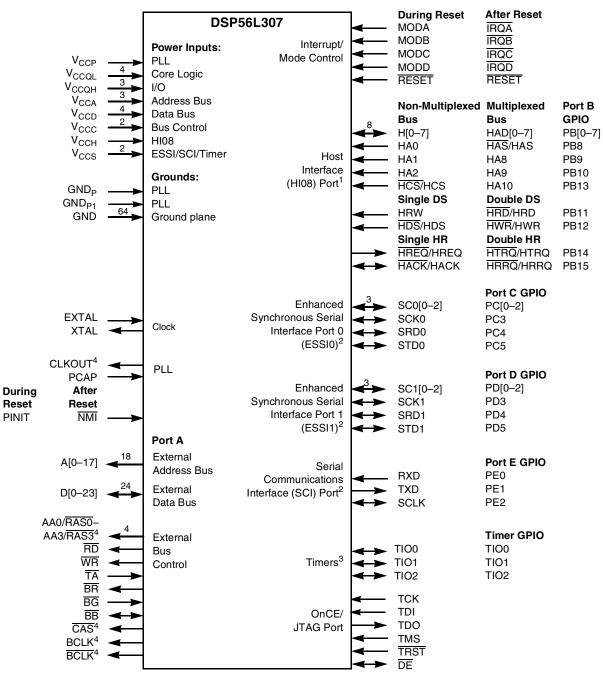
Signals/Connections

The DSP56L307 input and output signals are organized into functional groups as shown in **Table 1-1**. **Figure 1-1** diagrams the DSP56L307 signals by functional group. The remainder of this chapter describes the signal pins in each functional group.

Functional Group				
Power (V _{CC})			20	
Ground (GNI	D)		66	
Clock			2	
PLL			3	
Address bus			18	
Data bus		Port A ¹	24	
Bus control				
Interrupt and	mode control		5	
Host interfac	Host interface (HI08) Port B ²			
Enhanced synchronous serial interface (ESSI) Ports C and D ³				
Serial communication interface (SCI) Port E ⁴				
Timer			3	
OnCE/JTAG	Port		6	
Notes: 1. 2. 3. 4. 5.	Port A signals define the external memory interface port, including the external a The Clock Output (CLKOUT), BCLK, <u>BCLK</u> , <u>CAS</u> , and <u>RAS[0–3]</u> signals used by supported by the DSP56L307 at operating frequencies up to 100 MHz. DRAM a Port B signals are the HI08 port signals multiplexed with the GPIO signals. Port C and D signals are the two ESSI port signals multiplexed with the GPIO signals. Port E signals are the SCI port signals multiplexed with the GPIO signals. There are 5 signal connections that are not used. These are designated as no co Chapter 3).	y other DSP56300 family ccess is not supported at gnals.	members are bove 100 MHz.	

Note: This chapter refers to a number of configuration registers used to select individual multiplexed signal functionality. Refer to the *DSP56L307 User's Manual* for details on these configuration registers.

als/Connections



- Notes: 1. The HI08 port supports a non-multiplexed or a multiplexed bus, single or double Data Strobe (DS), and single or double Host Request (HR) configurations. Since each of these modes is configured independently, any combination of these modes is possible. These HI08 signals can also be configured alternatively as GPIO signals (PB[0–15]). Signals with dual designations (for example, HAS/HAS) have configurable polarity.
 - The ESSI0, ESSI1, and SCI signals are multiplexed with the Port C GPIO signals (PC[0–5]), Port D GPIO signals (PD[0–5]), and Port E GPIO signals (PE[0–2]), respectively.
 - **3.** TIO[0–2] can be configured as GPIO signals.
 - 4. CLKOUT, BCLK, BCLK, CAS, and RAS[0-3] are valid only for operating frequencies ≤100 MHz.

Figure 1-1. Signals Identified by Functional Group

DSP56L307 Technical Data, Rev. 6



1.1 Power

Power Name	Description			
V _{CCP}	PLL Power — V_{CC} dedicated for PLL use. The voltage should be well-regulated and the input should be provided with an extremely low impedance path to the V _{CC} power rail.			
V _{CCQL}	Quiet Core (Low) Power—An isolated power for the core processing logic. This input must be isolated externally from all other chip power inputs.			
V _{CCQH}	Quiet External (High) Power—A quiet power source for I/O lines. This input must be tied externally to all other chip power inputs, <i>except</i> V _{CCQL} .			
V _{CCA}	Address Bus Power—An isolated power for sections of the address bus I/O drivers. This input must be tied externally to all other chip power inputs, <i>except</i> V _{CCQL} .			
V _{CCD}	Data Bus Power —An isolated power for sections of the data bus I/O drivers. This input must be tied externally to all other chip power inputs, <i>except</i> V_{CCQL} .			
V _{CCC}	Bus Control Power—An isolated power for the bus control I/O drivers. This input must be tied externally to all other chip power inputs, <i>except</i> V _{CCQL} .			
V _{CCH}	Host Power—An isolated power for the HI08 I/O drivers. This input must be tied externally to all other chip power inputs, <i>except</i> V _{CCQL} .			
V _{CCS}	ESSI, SCI, and Timer Power —An isolated power for the ESSI, SCI, and timer I/O drivers. This input must be tied externally to all other chip power inputs, <i>except</i> V _{CCQL} .			
Note: The user m	ust provide adequate external decoupling capacitors for all power connections.			

Table 1-2. Power Inputs

1.2 Ground

Table 1-3. Grounds

Name	Description			
GND _P	PLL Ground —Ground-dedicated for PLL use. The connection should be provided with an extremely low-impedance path to ground. V_{CCP} should be bypassed to GND _P by a 0.47 μ F capacitor located as close as possible to the chip package.			
GND _{P1}	PLL Ground 1 —Ground-dedicated for PLL use. The connection should be provided with an extremely low-impedance path to ground.			
GND	Ground—Connected to an internal device ground plane.			
Note: The user	Note: The user must provide adequate external decoupling capacitors for all GND connections.			

1.3 Clock

Table 1-4. Clock Signals

Signal Name	Туре	State During Reset	Signal Description
EXTAL	Input	Input	External Clock/Crystal Input —Interfaces the internal crystal oscillator input to an external crystal or an external clock.
XTAL	Output	Chip-driven	Crystal Output —Connects the internal crystal oscillator output to an external crystal. If an external clock is used, leave XTAL unconnected.



1.4 PLL

Signal Name	Туре	State During Reset	Signal Description	
CLKOUT	Output	Chip-driven	Clock Output —Provides an output clock synchronized to the internal core clock phase.	
			If the PLL is enabled and both the multiplication and division factors equal one, then CLKOUT is also synchronized to EXTAL.	
			If the PLL is disabled, the CLKOUT frequency is half the frequency of EXTAL.	
			Note: At operating frequencies above 100 MHz, this signal produces a low-amplitude waveform that is not usable externally by other devices.	
PCAP	Input	Input	PLL Capacitor —An input connecting an off-chip capacitor to the PLL filter. Connect one capacitor terminal to PCAP and the other terminal to V_{CCP} .	
			If the PLL is not used, PCAP can be tied to V_{CC} , GND, or left floating.	
PINIT	Input	Input	PLL Initial —During assertion of RESET, the value of PINIT is written into the PLL enable (PEN) bit of the PLL control (PCTL) register, determining whether the PLL is enabled or disabled.	
NMI	Input		Nonmaskable Interrupt —After RESET deassertion and during normal instruction processing, this Schmitt-trigger input is the negative-edge-triggered NMI request internally synchronized to CLKOUT.	

Table 0-1. Phase-Locked Loop Signals

1.5 External Memory Expansion Port (Port A)

Note: When the DSP56L307 enters a low-power standby mode (stop or wait), it releases bus mastership and tristates the relevant Port A signals: A[0–17], D[0–23], AA0/RAS0–AA3/RAS3, RD, WR, BB, CAS.

1.5.1 External Address Bus

Signal Name	Туре	State During Reset, Stop, or Wait	Signal Description
A[0-17]	Output	Tri-stated	Address Bus—When the DSP is the bus master, A[0–17] are active-high outputs that specify the address for external program and data memory accesses. Otherwise, the signals are tri-stated. To minimize power dissipation, A[0–17] do not change state when external memory spaces are not being accessed.

 Table 1-5.
 External Address Bus Signals



1.5.2 External Data Bus

Signal Name	Туре	State During Reset	State During Stop or Wait	Signal Description
D[0–23]	Input/ Output	Ignored Input	Last state: <i>Input</i> : Ignored <i>Output</i> : Last value	Data Bus —When the DSP is the bus master, D[0–23] are active-high, bidirectional input/outputs that provide the bidirectional data bus for external program and data memory accesses. Otherwise, D[0–23] drivers are tristated. If the last state is output, these lines have weak keepers that maintain the last output state even when all drivers are tri-stated.

 Table 1-6.
 External Data Bus Signals

1.5.3 External Bus Control

Table 1-7.	External Bus Control Signals
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Signal Name	Туре	State During Reset, Stop, or Wait	Signal Description	
AA[0-3]	Output	Tri-stated	Address Attribute—When defined as AA, these signals can be used as chip selects or additional address lines. The default use defines a priority scheme under which only one AA signal can be asserted at a time. Setting the AA priority disable (APD) bit (Bit 14) of the Operating Mode Register, the priority mechanism is disabled and the lines can be used together as four external lines that can be decoded externally into 16 chip select signals.	
RD	Output	Tri-stated	Read Enable —When the DSP is the bus master, \overline{RD} is an active-low output that is asserted to read external memory on the data bus (D[0–23]). Otherwise, \overline{RD} is tri-stated.	
WR	Output	Tri-stated	Write Enable —When the DSP is the bus master, \overline{WR} is an active-low output that is asserted to write external memory on the data bus (D[0–23]). Otherwise, the signals are tri-stated.	
TA	Input	Ignored Input	Transfer Acknowledge —If the DSP56L307 is the bus master and there is no external bus activity, or the DSP56L307 is not the bus master, the TA input is ignored. The TA input is a data transfer acknowledge (DTACK) function that can extend an external bus cycle indefinitely. Any number of wait states (1, 2 infinity) can be added to the wait states inserted by the bus control register (BCR) by keeping TA deasserted. In typical operation, TA is deasserted at the start of a bus cycle, is asserted to enable completion of the bus cycle, and is deasserted before the next bus cycle. The current bus cycle completes one clock period after TA is asserted synchronous to CLKOUT. The number of wait states is determined by the TA input or by the BCR, whichever is longer. The BCR can be used to set the minimum number of wait states in external bus cycles.	



als/Connections

Signal Name	Туре	State During Reset, Stop, or Wait	Signal Description	
BR	Output	Reset: Output (deasserted) State during Stop/Wait depends on BRH bit setting: • BRH = 0: Output, deasserted • BRH = 1: Maintains last state (that is, if asserted, remains asserted)	Bus Request —Asserted when the DSP requests bus mastership. \overline{BR} is deasserted when the DSP no longer needs the bus. \overline{BR} may be asserted or deasserted independently of whether the DSP56L307 is a bus master or a bus slave. Bus "parking" allows \overline{BR} to be deasserted even though the DSP56L307 is the bus master. (See the description of bus "parking" in the \overline{BB} signal description.) The bus request hold (BRH) bit in the BCR allows \overline{BR} to be asserted under software control even though the DSP does not need the bus. \overline{BR} is typically sent to an external bus arbitrator that controls the priority, parking, and tenure of each master on the same external bus. \overline{BR} is affected only by DSP requests for the external bus, never for the internal bus. During hardware reset, \overline{BR} is deasserted and the arbitration is reset to the bus slave state.	
BG	Input	Ignored Input	Bus GrantAsserted by an external bus arbitration circuit when the DSP56L307 becomes the next bus master. When BG is asserted, the DSP56L307 must wait until BB is deasserted before taking bus mastership. When BG is deasserted, bus mastership is typically given up at the end of the current bus cycle. This may occur in the middle of an instruction that requires more than one external bus cycle for execution.To ensure proper operation, the user must set the asynchronous bus arbitration	
			enable (ABE) bit (Bit 13) in the Operating Mode Register. When this bit is set, \overline{BG} and \overline{BB} are synchronized internally. This adds a required delay between the deassertion of an initial \overline{BG} input and the assertion of a subsequent \overline{BG} input.	
BB	Input/ Output	Ignored Input	Bus Busy —Indicates that the bus is active. Only after \overline{BB} is deasserted can the pending bus master become the bus master (and then assert the signal again). The bus master may keep \overline{BB} asserted after ceasing bus activity regardless of whether \overline{BR} is asserted or deasserted. Called "bus parking," this allows the current bus master to reuse the bus without rearbitration until another device requires the bus. \overline{BB} is deasserted by an "active pull-up" method (that is, \overline{BB} is driven high and then released and held high by an external pull-up resistor). Notes: 1. See \overline{BG} for additional information.	
			2. BB requires an external pull-up resistor.	
CAS	Output	Tri-stated	Column Address Strobe —When the DSP is the bus master, CAS is an active- low output used by DRAM to strobe the column address. Otherwise, if the Bus Mastership Enable (BME) bit in the DRAM control register is cleared, the signal is tri-stated.	
			Note: DRAM access is not supported above 100 MHz.	
BCLK	Output	Tri-stated	Bus Clock When the DSP is the bus master, BCLK is active when the address trace enable (ATE) bit in the Operating Mode Register is set. When BCLK is active and synchronized to CLKOUT by the internal PLL, BCLK precedes CLKOUT by one-fourth of a clock cycle.	
			Note: At operating frequencies above 100 MHz, this signal produces a low- amplitude waveform that is not usable externally by other devices.	
BCLK	Output	Tri-stated	Bus Clock Not When the DSP is the bus master, BCLK is the inverse of the BCLK signal. Otherwise, the signal is tri-stated.	
			Note: At operating frequencies above 100 MHz, this signal produces a low- amplitude waveform that is not usable externally by other devices.	

Table 1-7. External Bus Control Signals (Continued)



1.6 Interrupt and Mode Control

The interrupt and mode control signals select the chip operating mode as it comes out of hardware reset. After **RESET** is deasserted, these inputs are hardware interrupt request lines.

Signal Name	Туре	State During Reset	Signal Description	
MODA	Input	Schmitt-trigger Input	Mode Select A —MODA, MODB, MODC, and MODD select one of 16 initial chip operating modes, latched into the Operating Mode Register when the RESET signal is deasserted.	
ĪRQĀ	Input		External Interrupt Request A —After reset, this input becomes a level- sensitive or negative-edge-triggered, maskable interrupt request input during normal instruction processing. If the processor is in the STOP or WAIT standby state and IRQA is asserted, the processor exits the STOP or WAIT state.	
MODB	Input	Schmitt-trigger Input	Mode Select B —MODA, MODB, MODC, and MODD select one of 16 initial chip operating modes, latched into the Operating Mode Register when the RESET signal is deasserted.	
ĪRQB	Input		External Interrupt Request B —After reset, this input becomes a level- sensitive or negative-edge-triggered, maskable interrupt request input during normal instruction processing. If the processor is in the WAIT standby state and IRQB is asserted, the processor exits the WAIT state.	
MODC	Input	Schmitt-trigger Input	Mode Select C —MODA, MODB, MODC, and MODD select one of 16 initial chip operating modes, latched into the Operating Mode Register when the RESET signal is deasserted.	
IRQC	Input		External Interrupt Request C —After reset, this input becomes a level- sensitive or negative-edge-triggered, maskable interrupt request input during normal instruction processing. If the processor is in the WAIT standby state and IRQC is asserted, the processor exits the WAIT state.	
MODD	Input	Schmitt-trigger Input	Mode Select D —MODA, MODB, MODC, and MODD select one of 16 initial chip operating modes, latched into the Operating Mode Register when the RESET signal is deasserted.	
ĪRQD	Input		External Interrupt Request D —After reset, this input becomes a level- sensitive or negative-edge-triggered, maskable interrupt request input during normal instruction processing. If the processor is in the WAIT standby state and IRQD is asserted, the processor exits the WAIT state.	
RESET	Input	Schmitt-trigger Input	Reset —Places the chip in the Reset state and resets the internal phase generator. The Schmitt-trigger input allows a slowly rising input (such as a capacitor charging) to reset the chip reliably. When the RESET signal is deasserted, the initial chip operating mode is latched from the MODA, MODB, MODC, and MODD inputs. The RESET signal must be asserted after powerup.	

Table 1-8.	Interrupt and Me	ode Control
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1.7 Host Interface (HI08)

The HI08 provides a fast, 8-bit, parallel data port that connects directly to the host bus. The HI08 supports a variety of standard buses and connects directly to a number of industry-standard microcomputers, microprocessors, DSPs, and DMA hardware.

1.7.1 Host Port Usage Considerations

Careful synchronization is required when the system reads multiple-bit registers that are written by another asynchronous system. This is a common problem when two asynchronous systems are connected (as they are in the Host port). The considerations for proper operation are discussed in Table 1-9.

Action	Description		
Asynchronous read of receive byte registers	When reading the receive byte registers, Receive register High (RXH), Receive register Middle (RXM), or Receive register Low (RXL), the host interface programmer should use interrupts or poll the Receive register Data Full (RXDF) flag that indicates data is available. This assures that the data in the receive byte registers is valid.		
Asynchronous write to transmit byte registers	The host interface programmer should not write to the transmit byte registers, Transmit register High (TXH), Transmit register Middle (TXM), or Transmit register Low (TXL), unless the Transmit register Data Empty (TXDE) bit is set indicating that the transmit byte registers are empty. This guarantees that the transmit byte registers transfer valid data to the Host Receive (HRX) register.		
Asynchronous write to host vector	The host interface programmer must change the Host Vector (HV) register only when the Host Command bit (HC) is clear. This practice guarantees that the DSP interrupt control logic receives a stable vector.		

Table 1-9.	Host Port Usage Considerations
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Host Port Configuration 1.7.2

HI08 signal functions vary according to the programmed configuration of the interface as determined by the 16 bits in the HI08 Port Control Register.

Signal Name	Туре	State During Reset ^{1,2}	Signal Description
H[0-7]	Input/Output	Ignored Input	Host Data —When the HI08 is programmed to interface with a non-multiplexed host bus and the HI function is selected, these signals are lines 0–7 of the bidirectional Data bus.
HAD[0-7]	Input/Output		Host Address —When the HI08 is programmed to interface with a multiplexed host bus and the HI function is selected, these signals are lines 0–7 of the bidirectional multiplexed Address/Data bus.
PB[0-7]	Input or Output		Port B 0–7 —When the HI08 is configured as GPIO through the HI08 Port Control Register, these signals are individually programmed as inputs or outputs through the HI08 Data Direction Register.

Table 1-10. Host Interface



Table 1-10.	Host Interface	(Continued)
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Signal Name	Туре	State During Reset ^{1,2}	Signal Description
HA0	Input	Ignored Input	Host Address Input 0—When the HI08 is programmed to interface with a nonmultiplexed host bus and the HI function is selected, this signal is line 0 of the host address input bus.
HAS/HAS	Input		Host Address Strobe—When the HI08 is programmed to interface with a multiplexed host bus and the HI function is selected, this signal is the host address strobe (HAS) Schmitt-trigger input. The polarity of the address strobe is programmable but is configured active-low (HAS) following reset.
PB8	Input or Output		Port B 8 —When the HI08 is configured as GPIO through the HI08 Port Control Register, this signal is individually programmed as an input or output through the HI08 Data Direction Register.
HA1	Input	Ignored Input	Host Address Input 1 —When the HI08 is programmed to interface with a nonmultiplexed host bus and the HI function is selected, this signal is line 1 of the host address (HA1) input bus.
HA8	Input		Host Address 8 —When the HI08 is programmed to interface with a multiplexed host bus and the HI function is selected, this signal is line 8 of the host address (HA8) input bus.
PB9	Input or Output		Port B 9 —When the HI08 is configured as GPIO through the HI08 Port Control Register, this signal is individually programmed as an input or output through the HI08 Data Direction Register.
HA2	Input	Ignored Input	Host Address Input 2 —When the HI08 is programmed to interface with a nonmultiplexed host bus and the HI function is selected, this signal is line 2 of the host address (HA2) input bus.
НАЭ	Input		Host Address 9 —When the HI08 is programmed to interface with a multiplexed host bus and the HI function is selected, this signal is line 9 of the host address (HA9) input bus.
PB10	Input or Output		Port B 10 —When the HI08 is configured as GPIO through the HI08 Port Control Register, this signal is individually programmed as an input or output through the HI08 Data Direction Register.
HCS/HCS	Input	Ignored Input	Host Chip Select —When the HI08 is programmed to interface with a nonmultiplexed host bus and the HI function is selected, this signal is the host chip select (HCS) input. The polarity of the chip select is programmable but is configured active-low (HCS) after reset.
HA10	Input		Host Address 10—When the HI08 is programmed to interface with a multiplexed host bus and the HI function is selected, this signal is line 10 of the host address (HA10) input bus.
PB13	Input or Output		Port B 13 —When the HI08 is configured as GPIO through the HI08 Port Control Register, this signal is individually programmed as an input or output through the HI08 Data Direction Register.
HRW	Input	Ignored Input	Host Read/Write—When the HI08 is programmed to interface with a single- data-strobe host bus and the HI function is selected, this signal is the Host Read/Write (HRW) input.
HRD/HRD	Input		Host Read Data —When the HI08 is programmed to interface with a double- data-strobe host bus and the HI function is selected, this signal is the HRD strobe Schmitt-trigger input. The polarity of the data strobe is programmable but is configured as active-low (HRD) after reset.
PB11	Input or Output		Port B 11 —When the HI08 is configured as GPIO through the HI08 Port Control Register, this signal is individually programmed as an input or output through the HI08 Data Direction Register.



als/Connections

Table 1-10.	Host Interface ((Continued)
	11000 1110011000	

Signal Name	Туре	State During Reset ^{1,2}	Signal Description
HDS/HDS	Input	Ignored Input	Host Data Strobe —When the HI08 is programmed to interface with a single- data-strobe host bus and the HI function is selected, this signal is the host data strobe (HDS) Schmitt-trigger input. The polarity of the data strobe is programmable but is configured as active-low (HDS) following reset.
HWR/HWR	Input		Host Write Data —When the HI08 is programmed to interface with a double- data-strobe host bus and the HI function is selected, this signal is the host write data strobe (HWR) Schmitt-trigger input. The polarity of the data strobe is programmable but is configured as active-low (HWR) following reset.
PB12	Input or Output		Port B 12 —When the HI08 is configured as GPIO through the HI08 Port Control Register, this signal is individually programmed as an input or output through the HI08 Data Direction Register.
HREQ/HREQ	Output	Ignored Input	Host Request —When the HI08 is programmed to interface with a single host request host bus and the HI function is selected, this signal is the host request (HREQ) output. The polarity of the host request is programmable but is configured as active-low (HREQ) following reset. The host request may be programmed as a driven or open-drain output.
HTRQ/HTRQ	Output		Transmit Host Request —When the HI08 is programmed to interface with a double host request host bus and the HI function is selected, this signal is the transmit host request (HTRQ) output. The polarity of the host request is programmable but is configured as active-low (HTRQ) following reset. The host request may be programmed as a driven or open-drain output.
PB14	Input or Output		Port B 14 —When the HI08 is configured as GPIO through the HI08 Port Control Register, this signal is individually programmed as an input or output through the HI08 Data Direction Register.
HACK/HACK	Input	Ignored Input	Host Acknowledge —When the HI08 is programmed to interface with a single host request host bus and the HI function is selected, this signal is the host acknowledge (HACK) Schmitt-trigger input. The polarity of the host acknowledge is programmable but is configured as active-low (HACK) after reset.
HRRQ/HRRQ	Output		Receive Host Request —When the HI08 is programmed to interface with a double host request host bus and the HI function is selected, this signal is the receive host request (HRRQ) output. The polarity of the host request is programmable but is configured as active-low (HRRQ) after reset. The host request may be programmed as a driven or open-drain output.
PB15	Input or Output		Port B 15 —When the HI08 is configured as GPIO through the HI08 Port Control Register, this signal is individually programmed as an input or output through the HI08 Data Direction Register.
• lf t • lf t	he Stop state, the sig he last state is input, he last state is outpu Wait processing sta	the signal is an ign t, these lines have v	ored input. weak keepers that maintain the last output state even if the drivers are tri-stated.



1.8 Enhanced Synchronous Serial Interface 0 (ESSI0)

Two synchronous serial interfaces (ESSI0 and ESSI1) provide a full-duplex serial port for serial communication with a variety of serial devices, including one or more industry-standard codecs, other DSPs, microprocessors, and peripherals that implement the Freescale serial peripheral interface (SPI).

Signal Name	Туре	State During Reset ^{1,2}	Signal Description
SC00	Input or Output	Ignored Input	Serial Control 0 —For asynchronous mode, this signal is used for the receive clock I/O (Schmitt-trigger input). For synchronous mode, this signal is used either for transmitter 1 output or for serial I/O flag 0.
PC0	Input or Output		Port C 0 —The default configuration following reset is GPIO input PC0. When configured as PC0, signal direction is controlled through the Port C Direction Register. The signal can be configured as ESSI signal SC00 through the Port C Control Register.
SC01	Input/Output	Ignored Input	Serial Control 1 —For asynchronous mode, this signal is the receiver frame sync I/O. For synchronous mode, this signal is used either for transmitter 2 output or for serial I/O flag 1.
PC1	Input or Output		Port C 1 —The default configuration following reset is GPIO input PC1. When configured as PC1, signal direction is controlled through the Port C Direction Register. The signal can be configured as an ESSI signal SC01 through the Port C Control Register.
SC02	Input/Output	Ignored Input	Serial Control Signal 2—The frame sync for both the transmitter and receiver in synchronous mode, and for the transmitter only in asynchronous mode. When configured as an output, this signal is the internally generated frame sync signal. When configured as an input, this signal receives an external frame sync signal for the transmitter (and the receiver in synchronous operation).
PC2	Input or Output		Port C 2 —The default configuration following reset is GPIO input PC2. When configured as PC2, signal direction is controlled through the Port C Direction Register. The signal can be configured as an ESSI signal SC02 through the Port C Control Register.
SCK0	Input/Output	Ignored Input	Serial Clock —Provides the serial bit rate clock for the ESSI. The SCK0 is a clock input or output, used by both the transmitter and receiver in synchronous modes or by the transmitter in asynchronous modes.
			Although an external serial clock can be independent of and asynchronous to the DSP system clock, it must exceed the minimum clock cycle time of 6T (that is, the system clock frequency must be at least three times the external ESSI clock frequency). The ESSI needs at least three DSP phases inside each half of the serial clock.
PC3	Input or Output		Port C 3 —The default configuration following reset is GPIO input PC3. When configured as PC3, signal direction is controlled through the Port C Direction Register. The signal can be configured as an ESSI signal SCK0 through the Port C Control Register.
SRD0	Input	Ignored Input	Serial Receive Data—Receives serial data and transfers the data to the ESSI Receive Shift Register. SRD0 is an input when data is received.
PC4	Input or Output		Port C 4 —The default configuration following reset is GPIO input PC4. When configured as PC4, signal direction is controlled through the Port C Direction Register. The signal can be configured as an ESSI signal SRD0 through the Port C Control Register.

Table 1-11.	Enhanced S	Synchronous	Serial	Interface 0
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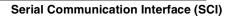
Table 4 44				(O = == 1 ¹
Table 1-11.	Ennanced Sy	/ncnronous a	Serial Interface 0	(Continuea)

Signal Name	Туре	State During Reset ^{1,2}	Signal Description
STD0	Output	Ignored Input	Serial Transmit Data—Transmits data from the Serial Transmit Shift Register. STD0 is an output when data is transmitted.
PC5	Input or Output		Port C 5 —The default configuration following reset is GPIO input PC5. When configured as PC5, signal direction is controlled through the Port C Direction Register. The signal can be configured as an ESSI signal STD0 through the Port C Control Register.
 In the Stop state, the signal maintains the last state as follows: If the last state is input, the signal is an ignored input. If the last state is output, these lines have weak keepers that maintain the last output state even if the drivers are tri-stated. The Wait processing state does not affect the signal state. 			

1.9 Enhanced Synchronous Serial Interface 1 (ESSI1)

Signal Name	Туре	State During Reset ^{1,2}	Signal Description
SC10	Input or Output	Ignored Input	Serial Control 0 —For asynchronous mode, this signal is used for the receive clock I/O (Schmitt-trigger input). For synchronous mode, this signal is used either for transmitter 1 output or for serial I/O flag 0.
PDO	Input or Output		Port D 0 —The default configuration following reset is GPIO input PD0. When configured as PD0, signal direction is controlled through the Port D Direction Register. The signal can be configured as an ESSI signal SC10 through the Port D Control Register.
SC11	Input/Output	Ignored Input	Serial Control 1 —For asynchronous mode, this signal is the receiver frame sync I/O. For synchronous mode, this signal is used either for Transmitter 2 output or for Serial I/O Flag 1.
PD1	Input or Output		Port D 1 —The default configuration following reset is GPIO input PD1. When configured as PD1, signal direction is controlled through the Port D Direction Register. The signal can be configured as an ESSI signal SC11 through the Port D Control Register.
SC12	Input/Output	Ignored Input	Serial Control Signal 2—The frame sync for both the transmitter and receiver in synchronous mode and for the transmitter only in asynchronous mode. When configured as an output, this signal is the internally generated frame sync signal. When configured as an input, this signal receives an external frame sync signal for the transmitter (and the receiver in synchronous operation).
PD2	Input or Output		Port D 2 —The default configuration following reset is GPIO input PD2. When configured as PD2, signal direction is controlled through the Port D Direction Register. The signal can be configured as an ESSI signal SC12 through the Port D Control Register.

Enhanced Serial Synchronous Interface 1 Table 1-12.





Signal Name	Туре	State During Reset ^{1,2}	Signal Description	
SCK1	Input/Output	Ignored Input	Serial Clock —Provides the serial bit rate clock for the ESSI. The SCK1 is a clock input or output used by both the transmitter and receiver in synchronous modes or by the transmitter in asynchronous modes.	
			Although an external serial clock can be independent of and asynchronous to the DSP system clock, it must exceed the minimum clock cycle time of 6T (that is, the system clock frequency must be at least three times the external ESSI clock frequency). The ESSI needs at least three DSP phases inside each half of the serial clock.	
PD3	Input or Output		Port D 3 —The default configuration following reset is GPIO input PD3. When configured as PD3, signal direction is controlled through the Port D Direction Register. The signal can be configured as an ESSI signal SCK1 through the Port D Control Register.	
SRD1	Input	Ignored Input	Serial Receive Data—Receives serial data and transfers the data to the ESSI Receive Shift Register. SRD1 is an input when data is being received.	
PD4	Input or Output		Port D 4 —The default configuration following reset is GPIO input PD4. When configured as PD4, signal direction is controlled through the Port D Direction Register. The signal can be configured as an ESSI signal SRD1 through the Port D Control Register.	
STD1	Output	Ignored Input	Serial Transmit Data—Transmits data from the Serial Transmit Shift Register. STD1 is an output when data is being transmitted.	
PD5	Input or Output		Port D 5 —The default configuration following reset is GPIO input PD5. When configured as PD5, signal direction is controlled through the Port D Direction Register. The signal can be configured as an ESSI signal STD1 through the Port D Control Register.	
• If t • If t	 If the last state is input, the signal is an ignored input. If the last state is output, these lines have weak keepers that maintain the last output state even if the drivers are tri-stated. 			

1.10 Serial Communication Interface (SCI)

The SCI provides a full duplex port for serial communication with other DSPs, microprocessors, or peripherals such as modems.

Signal Name	Туре	State During Reset ^{1,2}	Signal Description
RXD	Input	Ignored Input	Serial Receive Data—Receives byte-oriented serial data and transfers it to the SCI Receive Shift Register.
PE0	Input or Output		Port E 0 —The default configuration following reset is GPIO input PE0. When configured as PE0, signal direction is controlled through the Port E Direction Register. The signal can be configured as an SCI signal RXD through the Port E Control Register.
TXD	Output	Ignored Input	Serial Transmit Data—Transmits data from the SCI Transmit Data Register.
PE1	Input or Output		Port E 1 —The default configuration following reset is GPIO input PE1. When configured as PE1, signal direction is controlled through the Port E Direction Register. The signal can be configured as an SCI signal TXD through the Port E Control Register.

 Table 1-13.
 Serial Communication Interface



Signal Name	Туре	State During Reset ^{1,2}	Signal Description
SCLK	Input/Output	Ignored Input	Serial Clock—Provides the input or output clock used by the transmitter and/or the receiver.
PE2	Input or Output		Port E 2 —The default configuration following reset is GPIO input PE2. When configured as PE2, signal direction is controlled through the Port E Direction Register. The signal can be configured as an SCI signal SCLK through the Port E Control Register.
 In the Stop state, the signal maintains the last state as follows: If the last state is input, the signal is an ignored input. If the last state is output, these lines have weak keepers that maintain the last output state even if the drivers are tri-stated. The Wait processing state does not affect the signal state. 			

Table 1-13.	Serial Communication	Interface	(Continued)	
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1.11 Timers

The DSP56L307 has three identical and independent timers. Each timer can use internal or external clocking and can either interrupt the DSP56L307 after a specified number of events (clocks) or signal an external device after counting a specific number of internal events.

Signal Name	Туре	State During Reset ^{1,2}	Signal Description
TIO0	Input or Output	Ignored Input	Timer 0 Schmitt-Trigger Input/Output — When Timer 0 functions as an external event counter or in measurement mode, TIO0 is used as input. When Timer 0 functions in watchdog, timer, or pulse modulation mode, TIO0 is used as output.
			The default mode after reset is GPIO input. TIO0 can be changed to output or configured as a timer I/O through the Timer 0 Control/Status Register (TCSR0).
TIO1	Input or Output	Ignored Input	Timer 1 Schmitt-Trigger Input/Output — When Timer 1 functions as an external event counter or in measurement mode, TIO1 is used as input. When Timer 1 functions in watchdog, timer, or pulse modulation mode, TIO1 is used as output.
			The default mode after reset is GPIO input. TIO1 can be changed to output or configured as a timer I/O through the Timer 1 Control/Status Register (TCSR1).
TIO2	Input or Output	Ignored Input	Timer 2 Schmitt-Trigger Input/Output — When Timer 2 functions as an external event counter or in measurement mode, TIO2 is used as input. When Timer 2 functions in watchdog, timer, or pulse modulation mode, TIO2 is used as output.
			The default mode after reset is GPIO input. TIO2 can be changed to output or configured as a timer I/O through the Timer 2 Control/Status Register (TCSR2).
• If t • If t	he Stop state, the sig he last state is input, he last state is outpu Wait processing sta	the signal is an igno t, these lines have w	ored input. yeak keepers that maintain the last output state even if the drivers are tri-stated.

Table 1-14.	Triple Timer Signals
	The Third Orginalo

JTAG and OnCE Interface

1.12 JTAG and OnCE Interface

The DSP56300 family and in particular the DSP56L307 support circuit-board test strategies based on the **IEEE**® **Std.** 1149.1[™] test access port and boundary scan architecture, the industry standard developed under the sponsorship of the Test Technology Committee of IEEE and the JTAG. The OnCE module provides a means to interface nonintrusively with the DSP56300 core and its peripherals so that you can examine registers, memory, or on-chip peripherals. Functions of the OnCE module are provided through the JTAG TAP signals. For programming models, see the chapter on debugging support in the *DSP56300 Family Manual*.

Signal Name	Туре	State During Reset	Signal Description
ТСК	Input	Input	Test Clock—A test clock input signal to synchronize the JTAG test logic.
TDI	Input	Input	Test Data Input —A test data serial input signal for test instructions and data. TDI is sampled on the rising edge of TCK and has an internal pull-up resistor.
TDO	Output	Tri-stated	Test Data Output —A test data serial output signal for test instructions and data. TDO is actively driven in the shift-IR and shift-DR controller states. TDO changes on the falling edge of TCK.
TMS	Input	Input	Test Mode Select —Sequences the test controller's state machine. TMS is sampled on the rising edge of TCK and has an internal pull-up resistor.
TRST	Input	Input	Test Reset —Înitializes the test controller asynchronously. TRST has an internal pull-up resistor. TRST must be asserted during and after power-up (see EB610/D for details).
DE	Input/Output	Input	Debug Event —As an input, initiates Debug mode from an external command controller, and, as an open-drain output, acknowledges that the chip has entered Debug mode. As an input, DE causes the DSP56300 core to finish executing the current instruction, save the instruction pipeline information, enter Debug mode, and wait for commands to be entered from the debug serial input line. This signal is asserted as an output for three clock cycles when the chip enters Debug mode as a result of a debug request or as a result of meeting a breakpoint condition. The DE has an internal pull-up resistor. This signal is not a standard part of the JTAG TAP controller. The signal connects directly to the OnCE module to initiate debug mode directly or to provide a direct external indication that the chip has entered Debug mode. All other interface with the OnCE module must occur through the JTAG port.

Table 1-15.	JTAG/OnCE Interface





Specifications

The DSP56L307 is fabricated in high-density CMOS with transistor-transistor logic (TTL) compatible inputs and outputs.

Note: The DSP56L307 specifications are preliminary and are from design simulations, and may not be fully tested or guaranteed. Finalized specifications will be published after full characterization and device qualifications are complete.

2.1 Maximum Ratings

CAUTION

This device contains circuitry protecting against damage due to high static voltage or electrical fields; however, normal precautions should be taken to avoid exceeding maximum voltage ratings. Reliability is enhanced if unused inputs are tied to an appropriate logic voltage level (for example, either GND or V_{CC}).

In the calculation of timing requirements, adding a maximum value of one specification to a minimum value of another specification does not yield a reasonable sum. A maximum specification is calculated using a worst case variation of process parameter values in one direction. The minimum specification is calculated using the worst case for the same parameters in the opposite direction. Therefore, a "maximum" value for a specification never occurs in the same device that has a "minimum" value for another specification; adding a maximum to a minimum represents a condition that can never exist.



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Table 2-1.	Absolute Maximum Ratings
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Rating ¹	Symbol	Value ^{1, 2}	Unit
Supply Voltage	V _{CC}	-0.1 to 2.0	V
Input/Output Supply Voltage	V _{CCQH}	-0.3 to 4.0	V
All input voltages	V _{IN}	GND – 0.3 to V _{CCQH} + 0.3	V
Current drain per pin excluding $V_{\mbox{\scriptsize CC}}$ and GND	I	10	mA
Operating temperature range	TJ	-40 to +100	°C
Storage temperature	T _{STG}	-55 to +150	°C
Notes: 1. GND = 0 V, V_{CC} = 1.8 V ± 0.1 V, V_{CCOH}	$= 3.3 \text{ V} \pm 0.3 \text{ V}, \text{ T}_{J} = -40^{\circ}$	°C to +100°C, CL = 50 pF	•

1. GND = 0 V, V_{CC} = 1.8 V ± 0.1 V, V_{CCQH} = 3.3 V ± 0.3 V, T_{J} = -40°C to +100°C, \overline{CL} = 50 pF

Absolute maximum ratings are stress ratings only, and functional operation at the maximum is not guaranteed. Stress beyond 2. the maximum rating may affect device reliability or cause permanent damage to the device.

Power-up sequence: During power-up, and throughout the DSP56L307 operation, V_{CCQH} voltage must always be higher or 3. equal to V_{CC} voltage.

2.2 Thermal Characteristics

Thermal Resistance Characteristic	Symbol	MAP-BGA Value	Unit
Junction-to-ambient, natural convection, single-layer board (1s) ^{1,2}	$R_{ extsf{ heta}JA}$	47	°C/W
Junction-to-ambient, natural convection, four-layer board (2s2p) ^{1,3}	$R_{\theta JMA}$	25	°C/W
Junction-to-ambient, @200 ft/min air flow, single layer board (1s) ^{1,3}	$R_{\theta JMA}$	37	°C/W
Junction-to-ambient, @200 ft/min air flow, four-layer board (2s2p) ^{1,3}	R_{\thetaJMA}	22	°C/W
Junction-to-board ⁴	$R_{\theta JB}$	15	°C/W
Junction-to-case thermal resistance ⁵	$R_{ extsf{ heta}JC}$	8	°C/W
Junction-to-package-top, natural convection ⁶	$\Psi_{\rm JT}$	2	°C/W

Notes: 1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.

- Per SEMI G38-87 and JEDEC JESD51-2 with the single-layer board horizontal. 2.
- 3. Per JEDEC JESD51-6 with the board horizontal.
- 4. Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.

5. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).

6. Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2.

2.3 DC Electrical Characteristics

Characteristics	Symbol	Min	Тур	Мах	Unit
Supply voltage: • Core (V _{CCQL}) and PLL (V _{CCP}) • I/O (V _{CCQH} , V _{CCA} , V _{CCD} , V _{CCC} , V _{CCH} , and V _{CCS})		1.7 3.0	1.8 3.3	1.9 3.6	v v
Input high voltage • D[0-23], BG, BB, TA • MOD/IRQ ¹ , RESET, PINIT/NMI and all JTAG/ESSI/SCI/Timer/HI08 pins • EXTAL ⁸	V _{IH} V _{IHP} V _{IHX}	2.0 2.0 0.8 × V _{CCQH}		V _{CCQH} + 0.3 V _{CCQH} + 0.3 V _{CCQH}	v v v
Input low voltage • D[0–23], BG, BB, TA, MOD/IRQ ¹ , RESET, PINIT • All JTAG/ESSI/SCI/Timer/HI08 pins • EXTAL ⁸	V _{IL} V _{ILP} V _{ILX}	-0.3 -0.3 -0.3		0.8 0.8 0.2 × V _{CCQH}	V V V
Input leakage current	I _{IN}	-10		10	μA
High impedance (off-state) input current (@ 2.4 V / 0.4 V)	I _{TSI}	-10	_	10	μA
Output high voltage • TTL $(I_{OH} = -0.4 \text{ mA})^{5,7}$ • CMOS $(I_{OH} = -10 \mu\text{A})^5$	V _{OH}	2.4 V _{CC} – 0.01			v v
Output low voltage • TTL (I_{OL} = 3.0 mA, open-drain pins I_{OL} = 6.7 mA) ^{5,7} • CMOS (I_{OL} = 10 μ A) ⁵	V _{OL}			0.4 0.01	v v
Internal supply current ² : In Normal mode In Wait mode³ In Stop mode⁴ 	I _{CCI} I _{CCW} I _{CCS}		150 7. 5 100		mA mA μA
PLL supply current		—	1	2.5	mA
Input capacitance ⁵	C _{IN}	_	_	10	pF

Table 2-3.	DC Electrical Characteristics ⁷

2. Section 4.3 provides a formula to compute the estimated current requirements in Normal mode. To obtain these results, all inputs must be terminated (that is, not allowed to float). Measurements are based on synthetic intensive DSP benchmarks (see *Appendix A*). The power consumption numbers in this specification are 90 percent of the measured results of this benchmark. This reflects typical DSP applications. Typical internal supply current is measured with V_{CCQP} = 3.3 V, V_{CC} = 1.8 V at T_J = 100°C.

3. To obtain these results, all inputs must be terminated (that is, not allowed to float). PLL and XTAL signals are disabled during Stop state.

4. DC current in Stop mode is evaluated based on measurements. To obtain these results, all inputs not disconnected at Stop mode must be terminated (that is, not allowed to float).

5. Periodically sampled and not 100 percent tested.

6. $V_{CCQH} = 3.3 \text{ V} \pm 0.3 \text{ V}$, $V_{CC} = 1.8 \text{ V} \pm 0.1 \text{ V}$; $T_J = -40^{\circ}\text{C}$ to $+100 \text{ }^{\circ}\text{C}$, $C_L = 50 \text{ pF}$

7. This characteristic does not apply to XTAL and PCAP.

8. Driving EXTAL to the low V_{IHX} or the high V_{ILX} value may cause additional power consumption (DC current). To minimize power consumption, the minimum V_{IHX} should be no lower than

 $0.9 \times$ V_{CCQH} and the maximum V_{ILX} should be no higher than 0.1 \times V_{CCQH}.



2.4 AC Electrical Characteristics

The timing waveforms shown in the AC electrical characteristics section are tested with a V_{IL} maximum of 0.3 V and a V_{IH} minimum of 2.4 V for all pins except EXTAL, which is tested using the input levels shown in Note 6 of the previous table. AC timing specifications, which are referenced to a device input signal, are measured in production with respect to the 50 percent point of the respective input signal's transition. DSP56L307 output levels are measured with the production test machine V_{OL} and V_{OH} reference levels set at 0.4 V and 2.4 V, respectively.

Note: Although the minimum value for the frequency of EXTAL is 0 MHz, the device AC test conditions are 15 MHz and rated speed.

2.4.1 Internal Clocks

		Expression ^{1, 2}			
Characteristics	Symbol	Min	Тур	Max	
Internal operation frequency with PLL enabled	f	_	$(Ef \times MF)/$ (PDF × DF)	_	
Internal operation frequency with PLL disabled	f	—	Ef/2	_	
 Internal clock high period With PLL disabled With PLL enabled and MF ≤4 With PLL enabled and MF > 4 	Т _Н	$\begin{array}{c} - \\ 0.49 \times \text{ET}_{\text{C}} \times \\ \text{PDF} \times \text{DF/MF} \\ 0.47 \times \text{ET}_{\text{C}} \times \\ \text{PDF} \times \text{DF/MF} \end{array}$	ет _с —	$\begin{array}{c}\\ 0.51\times \text{ET}_{\text{C}}\times\\ \text{PDF}\times \text{DF/MF}\\ 0.53\times \text{ET}_{\text{C}}\times\\ \text{PDF}\times \text{DF/MF} \end{array}$	
 Internal clock low period With PLL disabled With PLL enabled and MF ≤4 With PLL enabled and MF > 4 	TL	$\begin{array}{c} - \\ 0.49 \times \text{ET}_{\text{C}} \times \\ \text{PDF} \times \text{DF/MF} \\ 0.47 \times \text{ET}_{\text{C}} \times \\ \text{PDF} \times \text{DF/MF} \end{array}$	ЕТ _С —	$\begin{array}{c}\\ 0.51 \times \text{ET}_{\text{C}} \times\\ \text{PDF} \times \text{DF/MF}\\ 0.53 \times \text{ET}_{\text{C}} \times\\ \text{PDF} \times \text{DF/MF} \end{array}$	
Internal clock cycle time with PLL enabled	т _с	_	$ET_{C} \times PDF \times DF/MF$	-	
Internal clock cycle time with PLL disabled	т _с	_	$2 \times \text{ET}_{C}$	_	
Instruction cycle time	I _{CYC}	—	Т _С	_	

Table 2-4. Internal Clocks



2.4.2 External Clock Operation

The DSP56L307 system clock is derived from the on-chip oscillator or is externally supplied. To use the on-chip oscillator, connect a crystal and associated resistor/capacitor components to EXTAL and XTAL; examples are shown in **Figure 2-1**.

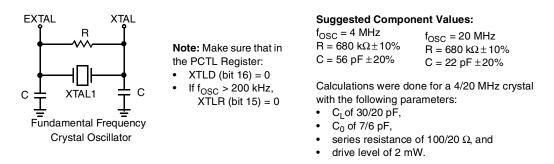
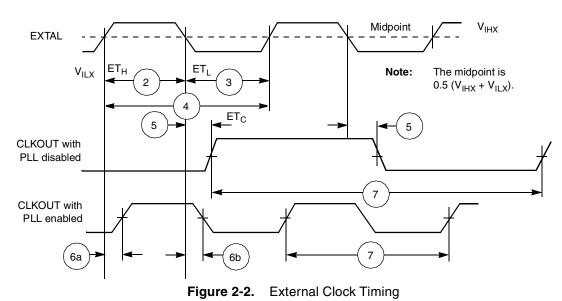


Figure 2-1. Crystal Oscillator Circuits

If an externally-supplied square wave voltage source is used, disable the internal oscillator circuit during bootup by setting XTLD (PCTL Register bit 16 = 1—see the *DSP56L307 User's Manual*). The external square wave source connects to EXTAL; XTAL is not physically connected to the board or socket. **Figure 2-2** shows the relationship between the EXTAL input and the internal clock and CLKOUT.





No.	Characteristics	Symbol	100	100 MHz		160 MHz	
NO.	Characteristics	Symbol	Min	Max	Min	Мах	
1	Frequency of EXTAL (EXTAL Pin Frequency) The rise and fall time of this external clock should be 3 ns maximum.	Ef	0	100.0	0	160.0	
2	 EXTAL input high^{1, 2} With PLL disabled (46.7%–53.3% duty cycle⁶) With PLL enabled (42.5%–57.5% duty cycle⁶) 	ET _H	4.67 ns 4.25 ns	∞ 157.0 μs	2.92 ns 2.66 ns	∞ 157.0 μs	
3	 EXTAL input low^{1, 2} With PLL disabled (46.7%–53.3% duty cycle⁶) With PLL enabled (42.5%–57.5% duty cycle⁶) 	ETL	4.67 ns 4.25 ns	∞ 157.0 μs	2.92 ns 2.66 ns	∞ 157.0 μs	
4	EXTAL cycle time ² With PLL disabled With PLL enabled 	ET _C	10.00 ns 10.00 ns	∞ 273.1 μs	6.25 ns 6.25 ns	∞ 273.1 μs	
5	Internal clock change from EXTAL fall with PLL disabled		4.3 ns	11.0 ns	4.3 ns	11.0 ns	
6	a.Internal clock rising edge from EXTAL rising edge with PLL enabled (MF = 1 or 2 or 4, PDF = 1, Ef > 15 MHz) ^{3,5}		0.0 ns	1.8 ns	0.0 ns	1.8 ns	
	b. Internal clock falling edge from EXTAL falling edge with PLL enabled (MF \leq 4, PDF \neq 1, Ef / PDF > 15 MHz) ^{3,5}		0.0 ns	1.8 ns	0.0 ns	1.8 ns	
7	Instruction cycle time = I _{CYC} = T _C ⁴ (see Figure 2-4) (46.7%–53.3% duty cycle) • With PLL disabled • With PLL enabled	I _{CYC}	20.0 ns 10.00 ns	∞ 8.53 μs	13.5 ns 6.25 ns	∞ 8.53 μs	
Notes	 Measured at 50 percent of the input transition. The maximum value for PLL enabled is given for minimum VC Periodically sampled and not 100 percent tested. The maximum value for PLL enabled is given for minimum VC 				imum MF.	I	

Table 2-5. Clock Operation

The maximum value for FLL enabled is given for min
 The skew is not guaranteed for any other MF value.

6. The indicated duty cycle is for the specified maximum frequency for which a part is rated. The minimum clock high or low time required for correction operation, however, remains the same at lower operating frequencies; therefore, when a lower clock frequency is used, the signal symmetry may vary from the specified duty cycle as long as the minimum high time and low time requirements are met.

2.4.3 Phase Lock Loop (PLL) Characteristics

Characteristics	100 MHz		160	MHz	Unit
Characteristics	Min	Min Max		Мах	Unit
Voltage Controlled Oscillator (VCO) frequency when PLL enabled (MF \times Ef \times 2/PDF)	30	200	30	320	MHz
PLL external capacitor (PCAP pin to V_{CCP}) (C_{PCAP}^{-1}) • @ MF ≤ 4 • @ MF > 4	(580 × MF) – 100 830 × MF	$\begin{array}{c} (780\times \text{ MF}){-}140 \\ 1470\times \text{ MF} \end{array}$	(580 × MF) – 100 830 × MF	(780× MF) – 140 1470× MF	pF pF
Note: C _{PCAP} is the value of the PLL capacitor (conr listed above.	nected between the I	PCAP pin and V _{CCP}) computed using the	e appropriate expres	ssion

Table 2-6. PLL Characteristics
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2.4.4 Reset, Stop, Mode Select, and Interrupt Timing

Na	Oberesteristics	Furnessian	100	MHz	160 MHz		
No.	Characteristics	Expression	Min	Мах	Min	Мах	Unit
8	Delay from RESET assertion to all pins at reset value ³	—	_	26.0	_	26.0	ns
9	 Required RESET duration⁴ Power on, external clock generator, PLL disabled Power on, external clock generator, PLL enabled Power on, internal oscillator During STOP, XTAL disabled (PCTL Bit 16 = 0) During STOP, XTAL enabled (PCTL Bit 16 = 1) During normal operation 	$\begin{array}{c} \text{Minimum:} \\ 50 \times \text{ET}_{\text{C}} \\ 1000 \times \text{ET}_{\text{C}} \\ 75000 \times \text{ET}_{\text{C}} \\ 75000 \times \text{ET}_{\text{C}} \\ 2.5 \times \text{T}_{\text{C}} \\ 2.5 \times \text{T}_{\text{C}} \end{array}$	500.0 10.0 0.75 0.75 25.0 25.0		313.06 6.25 0.47 0.47 15.6 15.6		ns µs ms ms ns ns
10	Delay from asynchronous RESET deassertion to first external address output (internal reset deassertion) ⁵ • Minimum • Maximum	$3.25 \times T_{C} + 2.0$ $20.25 \times T_{C} + 10$	34.5 —	 211.5	22.3 —	 134.0	ns ns
13	Mode select set-up time		30.0		30.0	_	ns
14	Mode select hold time		0.0		0.0	—	ns
15	Minimum edge-triggered interrupt request assertion width		6.6		6.6	—	ns
16	Minimum edge-triggered interrupt request deassertion width		6.6		6.6	_	ns
17	 Delay from IRQA, IRQB, IRQC, IRQD, NMI assertion to external memory access address out valid Caused by first interrupt instruction fetch Caused by first interrupt instruction execution 	$\begin{array}{c} \text{Minimum:} \\ 4.25 \times \ \text{T}_{\text{C}} + 2.0 \\ 7.25 \times \ \text{T}_{\text{C}} + 2.0 \end{array}$	44.5 74.5		28.6 47.3		ns ns
18	Delay from IRQA, IRQB, IRQC, IRQD, NMI assertion to general- purpose transfer output valid caused by first interrupt instruction execution	Minimum: 10 × T _C + 5.0	105.0	_	67.5	_	ns
19	Delay from address output valid caused by first interrupt instruction execute to interrupt request deassertion for level sensitive fast interrupts ^{1, 7, 8}	Maximum: (WS + 3.75) × T _C – 10.94	_	Note 8	_	Note 8	ns
20	Delay from RD assertion to interrupt request deassertion for level sensitive fast interrupts ^{1, 7, 8}	Maximum: (WS + 3.25) × T _C – 10.94	_	Note 8	_	Note 8	ns
21	Delay from \overline{WR} assertion to interrupt request deassertion for level sensitive fast interrupts ^{1, 7, 8} • DRAM for all WS • SRAM WS = 1 • SRAM WS = 2, 3 • SRAM WS \geq 4	$\begin{array}{c} \text{Maximum:} \\ (\text{WS} + 3.5) \times \text{T}_{\text{C}} - 10.94 \\ (\text{WS} + 3.5) \times \text{T}_{\text{C}} - 10.94 \\ (\text{WS} + 3) \times \text{T}_{\text{C}} - 10.94 \\ (\text{WS} + 2.5) \times \text{T}_{\text{C}} - 10.94 \end{array}$	 	Note 8 Note 8 Note 8 Note 8	 	Note 8 Note 8 Note 8 Note 8	ns ns ns ns
24	Duration for IRQA assertion to recover from Stop state		5.9	—	5.9		ns
25	 Delay from IRQA assertion to fetch of first instruction (when exiting Stop)^{2, 3} PLL is not active during Stop (PCTL Bit 17 = 0) and Stop delay is enabled (Operating Mode Register Bit 6 = 0) PLL is not active during Stop (PCTL Bit 17 = 0) and Stop delay is not enabled (Operating Mode Register Bit 6 = 1) PLL is active during Stop (PCTL Bit 17 = 1) (Implies No Stop Delay) 	$\begin{array}{l} PLC\timesET_{C}\timesPDF+(128~K\\-PLC/2)\timesT_{C}\\ PLC\timesET_{C}\timesPDF+(23.75\\\pm0.5)\timesT_{C}\\ (8.25\pm0.5)\timesT_{C} \end{array}$	1.3 232.5 ns 77.5	13.6 12.3 ms 87.5	1.3 232.5 ns 48.4	13.6 12.3 ms 54.7	ms ns
26	 Duration of level sensitive IRQA assertion to ensure interrupt service (when exiting Stop)^{2, 3} PLL is not active during Stop (PCTL Bit 17 = 0) and Stop delay is enabled (Operating Mode Register Bit 6 = 0) PLL is not active during Stop (PCTL Bit 17 = 0) and Stop delay is not enabled (Operating Mode Register Bit 6 = 1) PLL is active during Stop (PCTL Bit 17 = 1) (implies no Stop delay) 	$\begin{array}{c} \mbox{Minimum:} \\ \mbox{PLC} \times \mbox{ET}_{C} \times \mbox{PDF} + (128K - \\ \mbox{PLC}(2) \ \times \ \mbox{T}_{C} \\ \mbox{PLC} \times \mbox{ET}_{C} \times \mbox{PDF} + \\ (20.5 \pm 0.5) \times \ \mbox{T}_{C} \\ \mbox{5.5} \times \ \mbox{T}_{C} \end{array}$	13.6 12.3 55.0		13.6 12.3 34.4		ms ms ns

 Table 2-7.
 Reset, Stop, Mode Select, and Interrupt Timing⁶

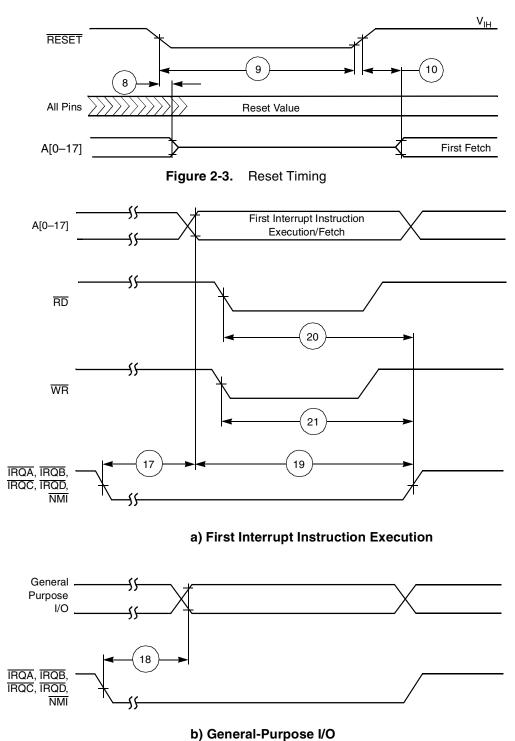


100 MHz 160 MHz No. Characteristics Expression Unit Max Min Min Max 27 Interrupt Requests Rate Maximum: HI08, ESSI, SCI, Timer $12 \times T_{C}$ 120.0 75.0 ns $8 \times T_{C}$ DMA 80.0 50.0 ns IRQ, NMI (edge trigger) $8 \times T_{C}$ 80.0 _ 50.0 ____ ns $12 \times T_{C}$ IRQ, NMI (level trigger) 120.0 75.0 ns 28 DMA Requests Rate Maximum: $6 imes T_{C}$ Data read from HI08, ESSI, SCI 60.0 37.5 ns Data write to HI08, ESSI, SCI $7 \times T_C$ 70.0 43.8 ns Timer $2 \times T_{C}$ 20.0 12.5 _ ns IRQ, NMI (edge trigger) $3 \times T_{C}$ 30.0 18.8 ns Delay from IRQA, IRQB, IRQC, IRQD, NMI assertion to external 29 Minimum: 44.0 28.6 memory (DMA source) access address out valid $4.25 \times T_{C} + 2.0$ ns When fast interrupts are used and IRQA, IRQB, IRQC, and IRQD are defined as level-sensitive, timings 19 through 21 apply to Notes: 1. prevent multiple interrupt service. To avoid these timing restrictions, the deasserted Edge-triggered mode is recommended when fast interrupts are used. Long interrupts are recommended for Level-sensitive mode. This timing depends on several settings: 2. • For PLL disable, using internal oscillator (PLL Control Register (PCTL) Bit 16 = 0) and oscillator disabled during Stop (PCTL Bit 17 = 0), a stabilization delay is required to assure that the oscillator is stable before programs are executed. Resetting the Stop delay (Operating Mode Register Bit 6 = 0) provides the proper delay. While Operating Mode Register Bit 6 = 1 can be set, it is not recommended, and these specifications do not guarantee timings for that case. • For PLL disable, using internal oscillator (PCTL Bit 16 = 0) and oscillator enabled during Stop (PCTL Bit 17=1), no stabilization delay is required and recovery is minimal (Operating Mode Register Bit 6 setting is ignored). • For PLL disable, using external clock (PCTL Bit 16 = 1), no stabilization delay is required and recovery time is defined by the PCTL Bit 17 and Operating Mode Register Bit 6 settings. • For PLL enable, if PCTL Bit 17 is 0, the PLL is shutdown during Stop. Recovering from Stop requires the PLL to get locked. The PLL lock procedure duration, PLL Lock Cycles (PLC), may be in the range of 0 to 1000 cycles. This procedure occurs in parallel with the stop delay counter, and stop recovery ends when the last of these two events occurs. The stop delay counter completes count or PLL lock procedure completion. • PLC value for PLL disable is 0. • The maximum value for ET_C is 4096 (maximum MF) divided by the desired internal frequency (that is, for 66 MHz it is 4096/66 MHz = 62 μ s). During the stabilization period, T_C, T_H, and T_L is not constant, and their width may vary, so timing may vary as well. 3. Periodically sampled and not 100 percent tested. Value depends on clock source: 4. For an external clock generator, RESET duration is measured while RESET is asserted, V_{CC} is valid, and the EXTAL input is active and valid. • For an internal oscillator, RESET duration is measured while RESET is asserted and V_{CC} is valid. The specified timing reflects the crystal oscillator stabilization time after power-up. This number is affected both by the specifications of the crystal and other components connected to the oscillator and reflects worst case conditions. • When the V_{CC} is valid, but the other "required RESET duration" conditions (as specified above) have not been yet met, the device circuitry is in an uninitialized state that can result in significant power consumption and heat-up. Designs should minimize this state to the shortest possible duration. 5. If PLL does not lose lock. V_{CCQH} = 3.3 V ±0.3 V, V_{CC} = 1.8 V ±0.1 V; T_J = –40°C to +100°C, C_L = 50 pF. 6. WS = number of wait states (measured in clock cycles, number of T_c). 7.

Table 2-7.	Reset, Stop, Mode Select, and Interrupt Timing ⁶ (Continued)
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8. Use the expression to compute a maximum value.



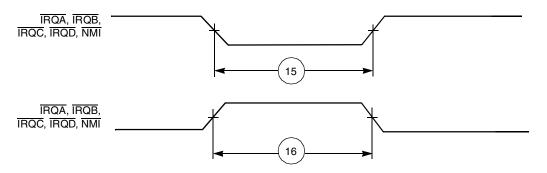


b) General-Pulpose 1/0

Figure 2-4. External Fast Interrupt Timing

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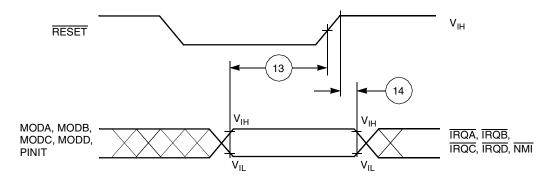


Figure 2-6. Operating Mode Select Timing

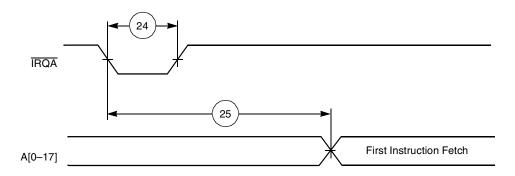


Figure 2-7. Recovery from Stop State Using IRQA

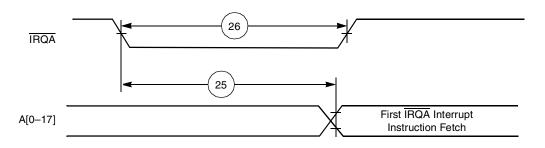


Figure 2-8. Recovery from Stop State Using IRQA Interrupt Service

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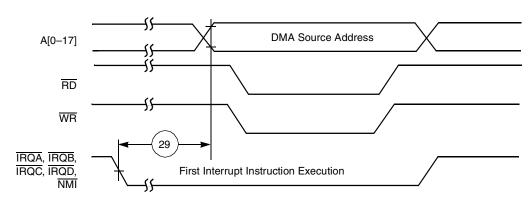


Figure 2-9. External Memory Access (DMA Source) Timing

2.4.5 External Memory Expansion Port (Port A)

2.4.5.1 SRAM Timing

No.	Characteristics	Symbol	Expression ¹	100	MHz	Unit
NO.	Characteristics	Symbol	Expression	Min	Max	Unit
100	Address valid and AA assertion pulse width ²	t _{RC} , t _{WC}	$2 \times T_{C} - 4.0$ [WS = 1]	16.0		ns
			(WS + 2) × T _C −4.0 [2 ≤WS ≤7]	36.0	—	ns
			$\begin{array}{c} (\text{WS}+3)\times\text{T}_{\text{C}}-4.0\\ [\text{WS}\geq8] \end{array}$	106.0		ns
101	Address and AA valid to \overline{WR} assertion	t _{AS}	$0.25 \times T_{C} - 2.4$ [WS = 1]	0.1		ns
			0.75 × T _C −3.0 [2 ≤WS ≤3]	4.5	—	ns
			$\begin{array}{c} 1.25 \times T_C -3.0 \\ [WS \geq 4] \end{array}$	9.5	—	ns
102	WR assertion pulse width	t _{WP}	$1.5 \times T_{C} - 4.5$ [WS = 1]	10.5	_	ns
			WS × T _C −4.0 [2 ≤WS ≤3]	16.0	—	ns
			$\begin{array}{c} (WS - 0.5) \times \ T_C - 4.0 \\ [WS \geq 4] \end{array}$	31.0		ns
103	WR deassertion to address not valid	t _{WR}	$0.25 \times T_{C} - 2.4$ [WS = 1]	0.1	—	ns
			1.25 × T _C −4.0 [2 ⊴WS ≤7]	8.5	—	ns
			$\begin{array}{c} 2.25 \times \mbox{ T}_{C}\mbox{-}4.0 \\ [WS \geq 8] \end{array}$	18.5	—	ns
104	Address and AA valid to input data valid	t _{AA} , t _{AC}	$\begin{array}{c} (WS + 0.75) \times \ T_C - 6.5 \\ [WS \geq 1] \end{array}$	-	11.0	ns
105	RD assertion to input data valid	t _{OE}	$\begin{array}{c} (WS + 0.25) \times \ T_C - 6.5 \\ [WS \geq 1] \end{array}$	_	6.0	ns
106	$\overline{\text{RD}}$ deassertion to data not valid (data hold time)	t _{OHZ}		0.0		ns
107	Address valid to \overline{WR} deassertion ²	t _{AW}	$\begin{array}{c} (WS + 0.75) \times T_C -\!4.0 \\ [WS \geq 1] \end{array}$	13.5	_	ns

Table 2-8. 100 MHz SRAM Timing



ifications

No.	Characteristics	Symbol	ol Expression ¹ -	100 MHz		- Unit
NO.	Gharacteristics	Symbol	Expression	Min	Max	Onn
108	Data valid to \overline{WR} deassertion (data set-up time)	t _{DS} (t _{DW})	$\begin{array}{c} (WS - 0.25) \times \ T_C \ -3.5 \\ [WS \geq 1] \end{array}$	4.0	—	ns
109	Data hold time from \overline{WR} deassertion	t _{DH}	0.25 × T _C –2.4 [WS = 1]	0.1	—	ns
			1.25 × T _C −4.0 [2 ≤WS ≤7]	8.5	—	ns
			$[2 \le WO \le 7]$ 2.25 × T _C -4.0 [WS ≥ 8]	18.5	—	ns
110	WR assertion to data active	_	$0.75 \times T_{C} - 4.0$ [WS = 1]	0.7	-	ns
			$0.25 \times T_{C} - 4.0$ [2 ≤WS ≤3]	-1.5	—	ns
			$-0.25 \times T_{C} - 4.0$ [WS ≥ 4]	-6.5	—	ns
111	WR deassertion to data high impedance	_	$0.25 \times T_{C}$ [WS = 1]	_	2.5	ns
			1.25 × T _C [2 ≤WS ≤7]	—	12.5	ns
			$2.25 \times T_{C}$ [WS ≥ 8]	—	22.5	ns
112	Previous RD deassertion to data active (write)	-	1.25 × T _C –4.0 [WS = 1]	8.5	—	ns
			2.25 × T _C −4.0 [2 ≤WS ≤7]	18.5	_	ns
			$[2 \le W3 \le 7]$ 3.25 × T _C -4.0 [WS ≥ 8]	28.5	—	ns
113	RD deassertion time	_	$0.75 \times T_{C} - 4.0$ [WS = 1]	3.5	—	ns
			1.75 × T _C −4.0 [2 ≤WS ≤7]	13.5	—	ns
			$2.75 \times T_{C} - 4.0$ [WS ≥ 8]	23.5	_	ns
114	WR deassertion time ⁵	_	0.5 × T _C –3.5 [WS = 1]	1.5	—	ns
			$1.5 \times T_{C} - 4.0$ [2 ≤WS ≤7]	11.0	—	ns
			$2.5 \times T_{C} - 4.0$ [WS ≥ 8]	21.0	—	ns
115	Address valid to RD assertion	—	$0.5 \times T_{C} - 2.6$	2.4	—	ns
116	RD assertion pulse width	—	$(WS+0.25)\timesT_C-4.0$	8.5	_	ns
117	RD deassertion to address not valid	-	$0.25 \times T_{C} - 4.0$ [WS = 1]	-1.5	-	ns
			1.25 × T _C −4.0 [2 ≤WS ≤7]	8.5	-	ns
			$2.25 \times T_{C} - 4.0$ [WS ≥ 8]	18.5	—	ns
118	\overline{TA} set-up before \overline{RD} or \overline{WR} deassertion ⁴	_	$0.25 \times T_{C} + 1.5$	4.0	_	ns
119	TA hold after \overline{RD} or \overline{WR} deassertion	_		0	—	ns

 Table 2-8.
 100 MHz SRAM Timing (Continued)



Table 2-8.	100 MHz SRAM Timing	(Continued)
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No.	Characteristics	Characteristics	Symbol	Evene asian1	100 MHz		Unit			
NO.		Symbol	Expression ¹	Min	Мах	Unit				
Notes: 1. WS = number of BCR-specified wait states. The value is the minimum for a given category. (for example, for a c WS ≤7] timing is specified for 2 wait states.) Two wait states is the minimum otherwise.							y of [2 ≤			
	2.	Timings 100 and 107 are guaranteed by design, not tested.								
	3.									
	4.									
	5.									

No.	Characteristics	Symbol Expression ¹	160	MHz	Unit	
NO.	Characteristics	Symbol	Expression	Min	Max	Unit
100	Address valid and AA assertion pulse width ²	t _{RC} , t _{WC}	$(WS + 2) \times T_{C} - 4.0$ [2 ≤WS ≤7] $(WS + 3) \times T_{C} - 4.0$	21.0 64.7	_	ns ns
			[WS ≥ 8]			
101	Address and AA valid to \overline{WR} assertion	t _{AS}	0.75 × T _C −3.0 [2 ≤WS ≤3]	1.7	—	ns
			$1.25 \times T_{C} - 3.0$ [WS ≥ 4]	4.8	—	ns
102	WR assertion pulse width	t _{WP}	WS × T _C −4.0 [2 ≤WS ≤3]	8.5	—	ns
			$(WS - 0.5) \times T_{C} - 4.0$ [WS \ge 4]	17.8	—	ns
103	WR deassertion to address not valid	t _{WR}	1.25 × T _C −4.0 [2 ≤WS ≤7]	3.8	—	ns
			$[2 \le WS \le 7]$ 2.25 × T _C -4.0 [WS ≥ 8]	10.0	—	ns
104	Address and AA valid to input data valid	t _{AA} , t _{AC}	$\begin{array}{c} (WS + 0.75) \times \ T_C - 6.5 \\ [WS \geq 2] \end{array}$		10.7	ns
105	RD assertion to input data valid	t _{OE}	$\begin{array}{c} (WS + 0.25) \times \ T_C -6.5 \\ [WS \geq 2] \end{array}$		7.6	ns
106	RD deassertion to data not valid (data hold time)	t _{OHZ}		0.0	_	ns
107	Address valid to \overline{WR} deassertion ²	t _{AW}	$\begin{array}{c} (WS + 0.75) \times T_C -\!$	13.2	—	ns
108	Data valid to \overline{WR} deassertion (data set-up time)	t _{DS} (t _{DW})	$\begin{array}{c} (WS - 0.25) \times \ T_C - 5.4 \\ [WS \geq 2] \end{array}$	5.5	—	ns
109	Data hold time from \overline{WR} deassertion	t _{DH}	1.25 × T _C −4.0 [2 ≤WS ≤7]	3.8	—	ns
			$2.25 \times T_{C} - 4.0$ [WS ≥ 8]	10.1	—	ns
110	WR assertion to data active	_	0.25 × T _C −4.0 [2 ≤WS ≤3]	-2.4	_	ns
			$-0.25 \times T_{C} - 4.0$ [WS ≥ 4]	-5.6	—	ns
111	WR deassertion to data high impedance	—	1.25 × T _C [2 ≤WS ≤7]	—	7.8	ns
			$[2 \le WS \le 7]$ $2.25 \times T_{C}$ $[WS \ge 8]$		14.0	

Table 2-9. 160 MHz SRAM Timing

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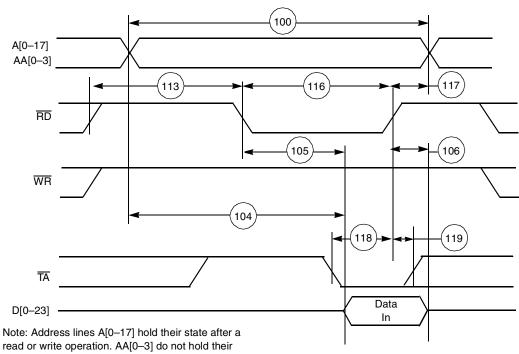
Nia	Oberneteristics	Characteristics Symbol Expression ¹		160 MHz		11	
No.	Characteristics	Symbol	Expression	Min Max 10.1 16.3 6.9 13.2 8.5 14.8 0.5 3.8 10.1	Unit		
112	Previous $\overline{\text{RD}}$ deassertion to data active (write)	_	$2.25 \times T_{C} - 4.0$ [2 \leq WS \leq 7] $3.25 \times T_{C} - 4.0$ [WS \geq 8]		_	ns ns	
113	RD deassertion time	_	$[.400 \ge 0]$ $1.75 \times T_{C} - 4.0$ $[2 \le WS \le 7]$ $2.75 \times T_{C} - 4.0$ $[WS \ge 8]$			ns ns	
114	WR deassertion time ⁵	_	$\begin{array}{c} 2.0 \times T_{C} - 4.0 \\ [2 \leq WS \leq 7] \\ 3.0 \times T_{C} - 4.0 \\ [WS \geq 8] \end{array}$		_	ns ns	
115	Address valid to RD assertion	_	$0.5 imes T_{C} - 2.6$	0.5	_	ns	
116	RD assertion pulse width	—	$(WS + 0.25) \times T_C - 4.0$	10.1	_	ns	
117	RD deassertion to address not valid	_	$\begin{array}{c} 1.25 \times T_{C} - 4.0 \\ [2 \leq WS \leq 7] \\ 2.25 \times T_{C} - 4.0 \\ [WS \geq 8] \end{array}$		_	ns ns	
118	\overline{TA} set-up before \overline{RD} or \overline{WR} deassertion ⁴	—	$0.25 \times T_{C} + 1.5$	3.1	—	ns	
119	\overline{TA} hold after \overline{RD} or \overline{WR} deassertion			0	_	ns	
Notes:							

Table 2-9. 160 MHz SRAM Timing (Continued)

4.

For \overline{TA} deassertion: timing 118 is relative to the deassertion edge of \overline{RD} or \overline{WR} if \overline{TA} is active. The WS number applies to the access in which the deassertion of \overline{WR} occurs and assumes the next access uses a minimal 5. number of wait states.





state after a read or write operation.



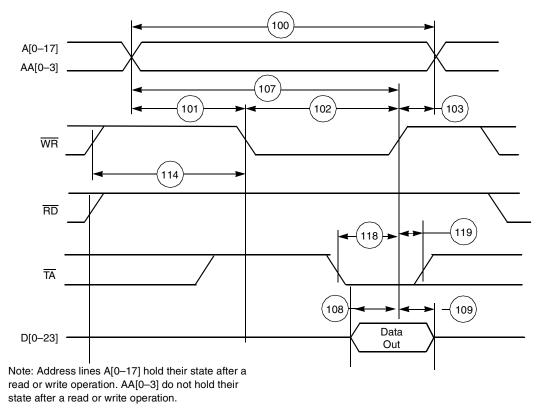


Figure 2-11. SRAM Write Access

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2.4.5.2 DRAM Timing

The selection guides in **Figure 2-12** and **Figure 2-15** are for primary selection only. Final selection should be based on the timing in the following tables. For example, the selection guide suggests that four wait states must be used for 100 MHz operation with Page Mode DRAM. However, consulting the appropriate table, a designer can evaluate whether fewer wait states might suffice by determining which timing prevents operation at 100 MHz, running the chip at a slightly lower frequency (for example, 95 MHz), using faster DRAM (if it becomes available), and manipulating control factors such as capacitive and resistive load to improve overall system performance.

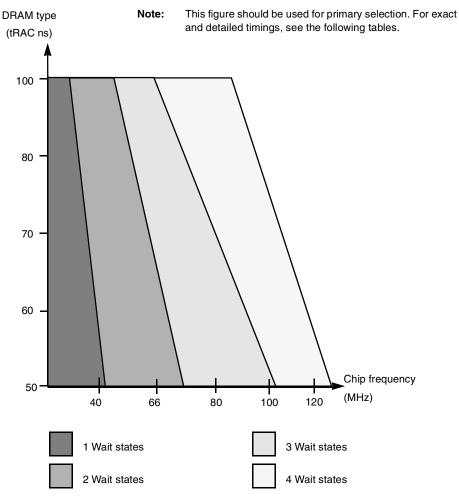


Figure 2-12. DRAM Page Mode Wait State Selection Guide



Na	Characteristics	Symbol	F	100	MHz	- Unit
No.	Characteristics		Expression ⁴	Min	Max	
131	Page mode cycle time for two consecutive accesses of the same direction		$4 \times T_C$	40.0		ns
	Page mode cycle time for mixed (read and write) accesses	t _{PC}	$3.5 imes T_{C}$	35.0	_	ns
132	CAS assertion to data valid (read)	t _{CAC}	$2 \times T_C - 5.7$	—	14.3	ns
133	Column address valid to data valid (read)	t _{AA}	$3 imes T_C$ –5.7	—	24.3	ns
134	CAS deassertion to data not valid (read hold time)	t _{OFF}		0.0	_	ns
135	Last CAS assertion to RAS deassertion	t _{RSH}	$2.5 imes T_C - 4.0$	21.0	_	ns
136	Previous CAS deassertion to RAS deassertion	t _{RHCP}	$4.5 imes T_C - 4.0$	41.0	_	ns
137	CAS assertion pulse width	t _{CAS}	$2 \times T_C - 4.0$	16.0	_	ns
138	Last CAS deassertion to RAS assertion ⁵ • BRW[1–0] = 00, 01—not applicable • BRW[1–0] = 10 • BRW[1–0] = 11	t _{CRP}	 4.75 × T _C -6.0 6.75 × T _C -6.0	 41.5 61.5		— ns ns
139	CAS deassertion pulse width	t _{CP}	$1.5 imes T_C - 4.0$	11.0	_	ns
140	Column address valid to CAS assertion	t _{ASC}	T _C -4.0	6.0	_	ns
141	CAS assertion to column address not valid	t _{CAH}	$2.5 imes T_C - 4.0$	21.0	_	ns
142	Last column address valid to RAS deassertion	t _{RAL}	$4 imes T_C - 4.0$	36.0	_	ns
143	WR deassertion to CAS assertion	t _{RCS}	$1.25 imes T_C - 4.0$	8.5	_	ns
144	CAS deassertion to WR assertion	t _{RCH}	$0.75 imes T_C$ –4.0	3.5	_	ns
145	CAS assertion to WR deassertion	t _{WCH}	$2.25 imes T_C - 4.2$	18.3	_	ns
146	WR assertion pulse width	t _{WP}	$3.5 imes T_C - 4.5$	30.5	_	ns
147	Last WR assertion to RAS deassertion	t _{RWL}	$3.75 imes T_C - 4.3$	33.2	_	ns
148	WR assertion to CAS deassertion	t _{CWL}	$3.25 imes T_C - 4.3$	28.2	_	ns
149	Data valid to CAS assertion (write)	t _{DS}	$0.5 imes T_C - 4.5$	0.5	_	ns
150	CAS assertion to data not valid (write)	t _{DH}	$2.5 imes T_C - 4.0$	21.0	_	ns
151	WR assertion to CAS assertion	t _{WCS}	$1.25 imes T_C - 4.3$	8.2	_	ns
152	Last RD assertion to RAS deassertion	t _{ROH}	$3.5 imes T_C - 4.0$	31.0	_	ns
153	RD assertion to data valid	t _{GA}	$2.5 imes T_C - 5.7$	-	19.3	ns
154	RD deassertion to data not valid ⁶	t _{GZ}		0.0	_	ns
155	WR assertion to data active		$0.75 imes T_{C} - 1.5$	6.0	_	ns
156	WR deassertion to data high impedance		$0.25 imes T_C$		2.5	ns

Table 2-10.	DRAM Page Mode Timings, Three Wait States ^{1,2,3}
	Brivier age mode minings, milee wait blates

2. The refresh period is specified in the DRAM Control Register.

The asynchronous delays specified in the expressions are valid for the DSP56L307. 3.

All the timings are calculated for the worst case. Some of the timings are better for specific cases (for example, t_{PC} equals 4 × 4. T_C for read-after-read or write-after-write sequences). An expression is used to compute the number listed as the minimum or maximum value listed, as appropriate.

BRW[1-0] (DRAM control register bits) defines the number of wait states that should be inserted in each DRAM out-of page-5. access.

RD deassertion always occurs after CAS deassertion; therefore, the restricted timing is t_{OFF} and not t_{GZ}. 6.



ifications

Na	Characteristics	Symbol	F	100 MHz		
No.	Characteristics		Expression ⁴	Min	Мах	- Unit
131	Page mode cycle time for two consecutive accesses of the same direction		$5 \times T_{C}$	50.0	_	ns
	Page mode cycle time for mixed (read and write) accesses	t _{PC}	$4.5 imes T_C$	45.0	_	ns
132	CAS assertion to data valid (read)	t _{CAC}	$2.75 imes T_{C}$ –5.7	—	21.8	ns
133	Column address valid to data valid (read)	t _{AA}	$3.75 imes T_{C}$ –5.7	—	31.8	ns
134	CAS deassertion to data not valid (read hold time)	t _{OFF}		0.0	_	ns
135	Last CAS assertion to RAS deassertion	t _{RSH}	$3.5 imes T_C - 4.0$	31.0	_	ns
136	Previous CAS deassertion to RAS deassertion	t _{RHCP}	$6 imes T_C$ –4.0	56.0	_	ns
137	CAS assertion pulse width	t _{CAS}	$2.5 imes T_C - 4.0$	21.0	_	ns
138	Last CAS deassertion to RAS assertion ⁵ • BRW[1-0] = 00, 01—Not applicable • BRW[1-0] = 10 • BRW[1-0] = 11	t _{CRP}		 46.5 66.5		— ns ns
139	CAS deassertion pulse width	t _{CP}	$2 \times T_C - 4.0$	16.0	_	ns
140	Column address valid to CAS assertion	t _{ASC}	T _C -4.0	6.0	_	ns
141	CAS assertion to column address not valid	t _{CAH}	$3.5 imes T_C - 4.0$	31.0	_	ns
142	Last column address valid to RAS deassertion	t _{RAL}	$5 imes T_C - 4.0$	46.0	_	ns
143	WR deassertion to CAS assertion	t _{RCS}	$1.25 imes T_C - 4.0$	8.5	—	ns
144	CAS deassertion to WR assertion	t _{RCH}	$1.25 imes T_C - 3.7$	8.8	_	ns
145	CAS assertion to WR deassertion	t _{WCH}	$3.25 imes T_C - 4.2$	28.3	_	ns
146	WR assertion pulse width	t _{WP}	$4.5 imes T_C - 4.5$	40.5	—	ns
147	Last WR assertion to RAS deassertion	t _{RWL}	$4.75 imes T_C$ –4.3	43.2	_	ns
148	WR assertion to CAS deassertion	t _{CWL}	$3.75 imes T_C - 4.3$	33.2	—	ns
149	Data valid to CAS assertion (write)	t _{DS}	$0.5 imes T_C - 4.5$	0.5	—	ns
150	CAS assertion to data not valid (write)	t _{DH}	$3.5 imes T_C - 4.0$	31.0	—	ns
151	WR assertion to CAS assertion	t _{WCS}	$1.25 imes T_C - 4.3$	8.2	_	ns
152	Last RD assertion to RAS deassertion	t _{ROH}	$4.5 imes T_C - 4.0$	41.0	—	ns
153	RD assertion to data valid	t _{GA}	$3.25 imes T_C$ –5.7	_	26.8	ns
154	RD deassertion to data not valid ⁶	t _{GZ}		0.0	—	ns
155	WR assertion to data active		$0.75 imes T_{C} - 1.5$	6.0	_	ns
156	WR deassertion to data high impedance		$0.25 \times T_{C}$	_	2.5	ns

DRAM Page Mode Timings, Four Wait States^{1,2,3} Table 2-11.

3. The asynchronous delays specified in the expressions are valid for the DSP56L307.

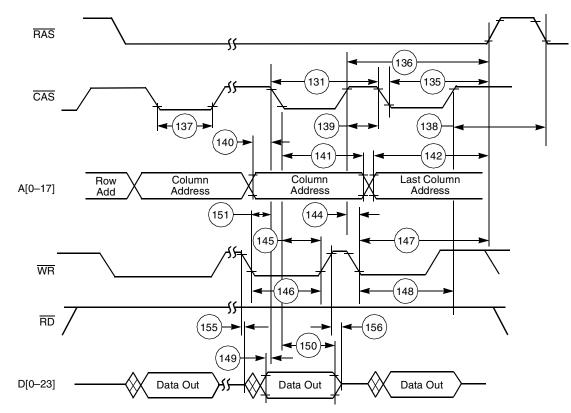
All the timings are calculated for the worst case. Some of the timings are better for specific cases (for example, t_{PC} equals 4. 3 × T_C for read-after-read or write-after-write sequences). An expressions is used to calculate the maximum or minimum value listed, as appropriate.

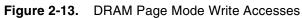
BRW[1-0] (DRAM control register bits) defines the number of wait states that should be inserted in each DRAM out-of-page 5. access.

RD deassertion always occurs after CAS deassertion; therefore, the restricted timing is t_{OFF} and not t_{GZ}. 6.



AC Electrical Characteristics





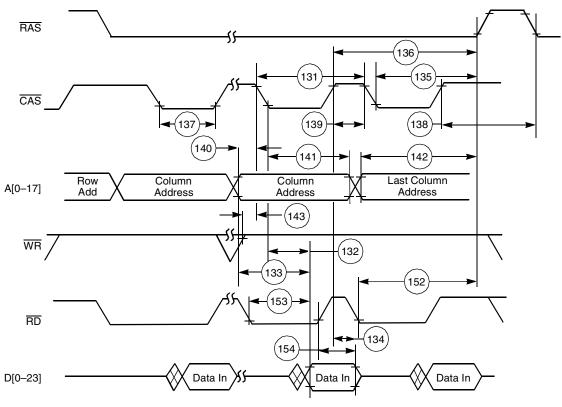
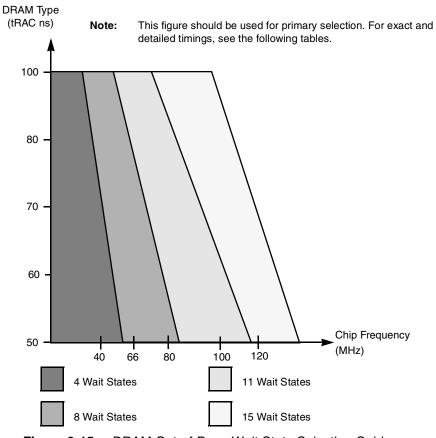
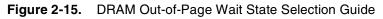


Figure 2-14. DRAM Page Mode Read Accesses







Characteristics		Expression ³	100 MHz		
Characteristics	Symbol	Expression	Min	Max	
Random read or write cycle time	t _{RC}	$12 \times T_{C}$	120.0	—	
RAS assertion to data valid (read)	t _{RAC}	$6.25 imes T_C - 7.0$	_	55.5	
CAS assertion to data valid (read)	t _{CAC}	$3.75 imes T_C - 7.0$	—	30.5	

Table 2-12.	DRAM Out-of-Page and Refresh Timings, Eleven Wait States ^{1,2}

No.	Characteristics	Symbol	Expression ³			
110.	Gharacteristics	Symbol	Expression	Min	Max	- Unit
157	Random read or write cycle time	t _{RC}	$12 \times T_{C}$	120.0	—	ns
158	RAS assertion to data valid (read)	t _{RAC}	$6.25 imes T_C - 7.0$	—	55.5	ns
159	CAS assertion to data valid (read)	t _{CAC}	$3.75 imes T_C - 7.0$	—	30.5	ns
160	Column address valid to data valid (read)	t _{AA}	$4.5 imes T_C - 7.0$	—	38.0	ns
161	CAS deassertion to data not valid (read hold time)	t _{OFF}		0.0	—	ns
162	RAS deassertion to RAS assertion	t _{RP}	$4.25\timesT_C^{}-\!4.0$	38.5		ns
163	RAS assertion pulse width	t _{RAS}	$7.75 imes T_C - 4.0$	73.5		ns
164	CAS assertion to RAS deassertion	t _{RSH}	$5.25 imes T_C - 4.0$	48.5	—	ns
165	RAS assertion to CAS deassertion	t _{CSH}	$6.25 imes T_C - 4.0$	58.5		ns
166	CAS assertion pulse width	t _{CAS}	$3.75 imes T_C - 4.0$	33.5		ns
167	RAS assertion to CAS assertion	t _{RCD}	$2.5\timesT_{C}\pm4.0$	21.0	29.0	ns
168	RAS assertion to column address valid	t _{RAD}	$1.75\timesT_{C}{\pm}4.0$	13.5	21.5	ns
169	CAS deassertion to RAS assertion	t _{CRP}	$5.75 imes T_C - 4.0$	53.5		ns
170	CAS deassertion pulse width	t _{CP}	$4.25 imes T_{C} - 6.0$	36.5		ns
171	Row address valid to RAS assertion	t _{ASR}	$4.25 imes T_C - 4.0$	38.5	—	ns



NI		0hl	-	100	100 MHz	
No.	Characteristics	Symbol	Expression ³	Min	Max	Unit
172	RAS assertion to row address not valid	t _{RAH}	$1.75 imes T_C - 4.0$	13.5	—	ns
173	Column address valid to CAS assertion	t _{ASC}	$0.75 imes T_C - 4.0$	3.5	_	ns
174	CAS assertion to column address not valid	t _{CAH}	$5.25 imes T_C - 4.0$	48.5	_	ns
175	RAS assertion to column address not valid	t _{AR}	$7.75 imes T_C - 4.0$	73.5	_	ns
176	Column address valid to RAS deassertion	t _{RAL}	$6 imes T_C - 4.0$	56.0	_	ns
177	WR deassertion to CAS assertion	t _{RCS}	$3.0 imes T_C - 4.0$	26.0	_	ns
178	\overline{CAS} deassertion to \overline{WR}^4 assertion	t _{RCH}	$1.75 \times T_{C} - 3.7$	13.8	—	ns
179	\overline{RAS} deassertion to \overline{WR}^4 assertion	t _{RRH}	$0.25 imes T_C$ –2.0	0.5	_	ns
180	CAS assertion to WR deassertion	t _{WCH}	$5 imes T_C - 4.2$	45.8	_	ns
181	RAS assertion to WR deassertion	t _{WCR}	$7.5 imes T_C - 4.2$	70.8	_	ns
182	WR assertion pulse width	t _{WP}	$11.5 imes T_C - 4.5$	110.5	—	ns
183	WR assertion to RAS deassertion	t _{RWL}	$11.75 imes T_C - 4.3$	113.2	—	ns
184	WR assertion to CAS deassertion	t _{CWL}	$10.25 \times T_C 4.3$	98.2	_	ns
185	Data valid to CAS assertion (write)	t _{DS}	$5.75 imes T_C - 4.0$	53.5	_	ns
186	CAS assertion to data not valid (write)	t _{DH}	$5.25 imes T_C - 4.0$	48.5	—	ns
187	RAS assertion to data not valid (write)	t _{DHR}	$7.75 imes T_C - 4.0$	73.5	_	ns
188	WR assertion to CAS assertion	t _{WCS}	$6.5 imes T_C - 4.3$	60.7	—	ns
189	CAS assertion to RAS assertion (refresh)	t _{CSR}	$1.5 imes T_C - 4.0$	11.0	_	ns
190	RAS deassertion to CAS assertion (refresh)	t _{RPC}	$2.75 imes T_C - 4.0$	23.5	_	ns
191	RD assertion to RAS deassertion	t _{ROH}	$11.5 imes T_C - 4.0$	111.0	_	ns
192	RD assertion to data valid	t _{GA}	$10 imes T_C$ –7.0	—	93.0	ns
193	RD deassertion to data not valid ⁵	t _{GZ}		0.0	—	ns
194	WR assertion to data active		$0.75 imes T_{C} - 1.5$	6.0	_	ns
195	WR deassertion to data high impedance		$0.25 \times T_{C}$	—	2.5	ns
Notes	 The number of wait states for an out-of-page access is speci The refresh period is specified in the DRAM Control Register Use the expression to compute the maximum or minimum va Either tech or tech must be satisfied for read cycles. 		-	cludes ±).	<u>I</u>	1

Table 2-12.	DRAM Out-of-Page and Refresh Timings, Eleven Wait States ^{1,2}	(Continued)
	DRAW Out-of-Fage and Reflesh Thinkings, Eleven Walt States	Continue

4.

Either t_{RCH} or t_{RRH} must be satisfied for read cycles. RD deassertion always occurs after CAS deassertion; therefore, the restricted timing is t_{OFF} and not t_{GZ} . 5.

Table 2-13.	DRAM Out-of-Page and Refresh Timings, Fifteen Wait States ^{1,2}
	Drivit Out of Fage and Hencesh Finnings, Fincent Walt Olaco

No.	Characteristics	Symbol	Expression ³	100 MHz		Linit
NO.	Characteristics	Зушрог	Expression	Min	Max	Unit
157	Random read or write cycle time	t _{RC}	$16 \times T_C$	160.0	_	ns
158	RAS assertion to data valid (read)	t _{RAC}	$8.25 imes T_{C}$ –5.7	—	76.8	ns
159	CAS assertion to data valid (read)	t _{CAC}	$4.75 imes T_C - 5.7$	—	41.8	ns
160	Column address valid to data valid (read)	t _{AA}	$5.5 imes T_{C}$ – 5.7	—	49.3	ns
161	CAS deassertion to data not valid (read hold time)	t _{OFF}	0.0	0.0	-	ns
162	RAS deassertion to RAS assertion	t _{RP}	$6.25 imes T_C - 4.0$	58.5	_	ns



		Symbol	- 3	100 MHz				
No.	Characteristics	Symbol	Expression ³	Min	Max	Unit		
163	RAS assertion pulse width	t _{RAS}	$9.75 imes T_{C} - 4.0$	93.5	_	ns		
164	CAS assertion to RAS deassertion	t _{RSH}	$6.25 imes T_C - 4.0$	58.5	_	ns		
165	RAS assertion to CAS deassertion	t _{CSH}	$8.25 imes T_C - 4.0$	78.5	_	ns		
166	CAS assertion pulse width	t _{CAS}	$4.75 imes T_C - 4.0$	43.5		ns		
167	RAS assertion to CAS assertion	t _{RCD}	$3.5 imes T_{C} \pm 2$	33.0	37.0	ns		
168	RAS assertion to column address valid	t _{RAD}	$2.75 imes T_{C} \pm 2$	25.5	29.5	ns		
169	CAS deassertion to RAS assertion	t _{CRP}	$7.75 imes T_{C}$ –4.0	73.5	_	ns		
170	CAS deassertion pulse width	t _{CP}	$6.25 \times T_{C} - 6.0$	56.5		ns		
171	Row address valid to RAS assertion	t _{ASR}	$6.25 imes T_{C}$ –4.0	58.5		ns		
172	RAS assertion to row address not valid	t _{RAH}	$2.75 imes T_{C}$ –4.0	23.5		ns		
173	Column address valid to CAS assertion	t _{ASC}	$0.75 imes T_{C}$ –4.0	3.5		ns		
174	CAS assertion to column address not valid	t _{CAH}	$6.25 imes T_C - 4.0$	58.5	_	ns		
175	RAS assertion to column address not valid	t _{AR}	$9.75 imes T_{C}-4.0$	93.5		ns		
176	Column address valid to RAS deassertion	t _{RAL}	$7 imes T_C - 4.0$	66.0	_	ns		
177	WR deassertion to CAS assertion	t _{RCS}	$5 imes T_{C}$ –3.8	46.2		ns		
178	\overline{CAS} deassertion to \overline{WR}^4 assertion	t _{RCH}	$1.75 imes T_{C} - 3.7$	13.8		ns		
179	RAS deassertion to WR ⁴ assertion	t _{RRH}	$0.25 imes T_{C}$ –2.0	0.5		ns		
180	CAS assertion to WR deassertion	t _{WCH}	$6 imes T_C - 4.2$	55.8		ns		
181	RAS assertion to WR deassertion	t _{WCR}	$9.5 imes T_C - 4.2$	90.8		ns		
182	WR assertion pulse width	t _{WP}	$15.5 imes T_{C}$ –4.5	150.5		ns		
183	WR assertion to RAS deassertion	t _{RWL}	$15.75 imes T_{C}$ –4.3	153.2		ns		
184	WR assertion to CAS deassertion	t _{CWL}	$14.25 imes T_C - 4.3$	138.2		ns		
185	Data valid to CAS assertion (write)	t _{DS}	$8.75 imes T_{C}$ –4.0	83.5		ns		
186	CAS assertion to data not valid (write)	t _{DH}	$6.25 imes T_C - 4.0$	58.5		ns		
187	RAS assertion to data not valid (write)	t _{DHR}	$9.75 imes T_{C}-4.0$	93.5		ns		
188	WR assertion to CAS assertion	t _{WCS}	$9.5 imes T_C - 4.3$	90.7		ns		
189	CAS assertion to RAS assertion (refresh)	t _{CSR}	$1.5 \times T_{C} - 4.0$	11.0		ns		
190	RAS deassertion to CAS assertion (refresh)	t _{RPC}	$4.75 imes T_C - 4.0$	43.5		ns		
191	RD assertion to RAS deassertion	t _{ROH}	$15.5 imes T_C - 4.0$	151.0		ns		
192	RD assertion to data valid	t _{GA}	$14 imes T_{C}$ –5.7	_	134.3	ns		
193	RD deassertion to data not valid ⁵	t _{GZ}		0.0	_	ns		
194	WR assertion to data active		$0.75 imes T_{C} - 1.5$	6.0	_	ns		
195	WR deassertion to data high impedance		$0.25 \times T_{C}$	_	2.5	ns		
Notes								

Table 2-13.	DRAM Out-of-Page and Refresh	Timings, Fifteen Wait States ^{1,2}	(Continued)

- 4.
- Either t_{RCH} or t_{RRH} must be satisfied for read cycles. RD deassertion always occurs after CAS deassertion; therefore, the restricted timing is t_{OFF} and not t_{GZ} . 5.



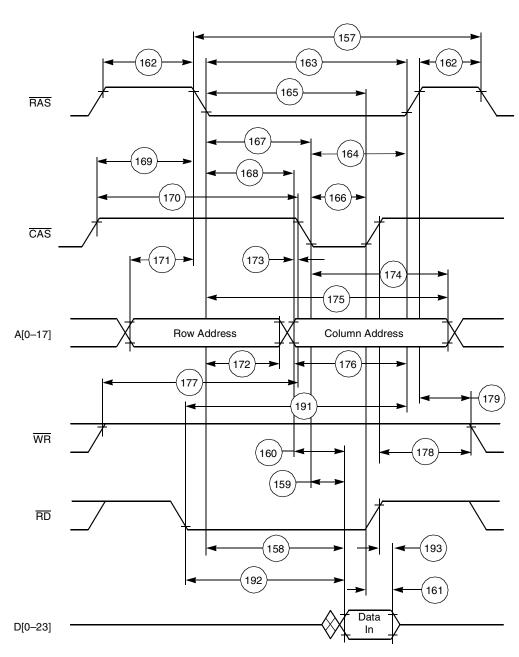
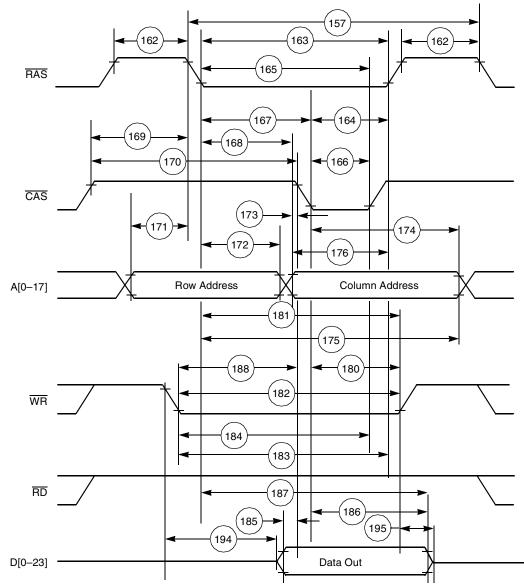
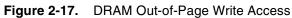


Figure 2-16. DRAM Out-of-Page Read Access







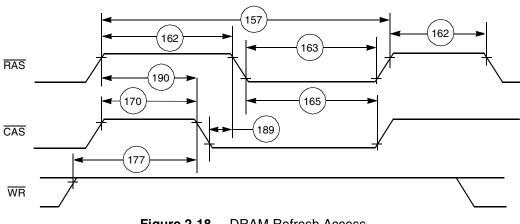


Figure 2-18. DRAM Refresh Access



2.4.5.3 Synchronous Timings

No.	Characteristics	Expression ^{3,4,5}	100 MHz		Unit
NO.	Characteristics	Expression	Min	Max	Unit
198	CLKOUT high to address, and AA valid ⁶	$0.25 \times T_{C} + 4.0$	—	6.5	ns
199	CLKOUT high to address, and AA invalid ⁶	$0.25 \times T_{C}$	2.5	—	ns
200	TA valid to CLKOUT high (set-up time)		4.0	—	ns
201	CLKOUT high to TA invalid (hold time)		0.0	—	ns
202	CLKOUT high to data out active	$0.25 \times T_{C}$	2.5	—	ns
203	CLKOUT high to data out valid	$0.25 \times T_{C} + 4.0$	_	6.5	ns
204	CLKOUT high to data out invalid	$0.25 \times T_{C}$	2.5	—	ns
205	CLKOUT high to data out high impedance	$0.25 \times T_{C}$	—	2.5	ns
206	Data in valid to CLKOUT high (set-up)		4.0	—	ns
207	CLKOUT high to data in invalid (hold)		0.0	—	ns
208	CLKOUT high to RD assertion	maximum: $0.75 \times T_{C} + 2.5$	6.7	10.0	ns
209	CLKOUT high to RD deassertion		0.0	4.0	ns
210	CLKOUT high to $\overline{\text{WR}}$ assertion ²	maximum: $0.5 \times T_{C} + 4.3$ for WS = 1 or WS ≥ 4	5.0	9.3	ns
		for 2 ≤WS ≤3	0.0	4.3	ns
211	CLKOUT high to WR deassertion		0.0	3.8	ns

Table 2-14. External Bus Synchronous Timings "	Table 2-14.	External Bus Synchronous Timings ^{1,2}	2
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3. WS is the number of wait states specified in the BCR.

If WS > 1, \overline{WR} assertion refers to the next rising edge of CLKOUT. 4.

5. An expression is used to compute the maximum or minimum value listed, as appropriate. For timing 210, the minimum is an absolute value.

T198 and T199 are valid for Address Trace mode if the ATE bit in the Operating Mode Register is set. Use the status of BR 6. (See T212) to determine whether the access referenced by A[0–17] is internal or external, when this mode is enabled.



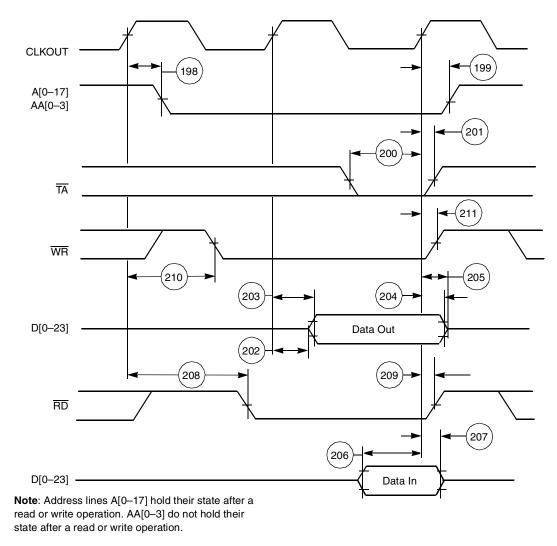


Figure 2-19. Synchronous Bus Timings 1 WS (BCR Controlled)



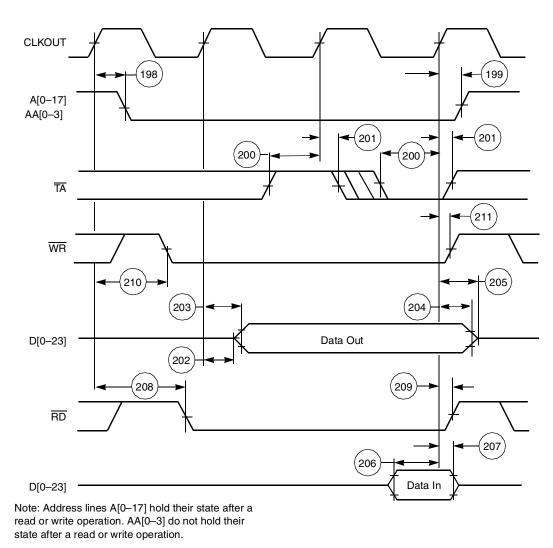


Figure 2-20. Synchronous Bus Timings 2 WS (TA Controlled)



2.4.5.4 Arbitration Timings Using CLKOUT (<100 MHz only)

Table 2-15.Arbitration Bus Timings1

Ne	Characteristics	Everacion ²	100	11	
No.	Characteristics	Expression ²	Min	Мах	Unit
212	CLKOUT high to BR assertion/deassertion ³		0.0	4.0	ns
213	BG asserted/deasserted to CLKOUT high (set-up)		4.0		ns
214	CLKOUT high to BG deasserted/asserted (hold)		0.0		ns
215	BB deassertion to CLKOUT high (input set-up)		4.0		ns
216	CLKOUT high to BB assertion (input hold)		0.0		ns
217	CLKOUT high to BB assertion (output)		0.0	4.0	ns
218	CLKOUT high to BB deassertion (output)		0.0	4.0	ns
219	BB high to BB high impedance (output)		_	4.5	ns
220	CLKOUT high to address and controls active	$0.25 \times T_{C}$	2.5		ns
221	CLKOUT high to address and controls high impedance	$0.75 imes T_{C}$	—	7.5	ns
222	CLKOUT high to AA active	$0.25 imes T_{C}$	2.5		ns
223	CLKOUT high to AA deassertion	maximum: $0.25 \times T_{C} + 4.0$	2.0	6.5	ns
224	CLKOUT high to AA high impedance	$0.75 imes T_{C}$	—	7.5	ns
Notes:	 Synchronous bus arbitration is not recommended. Use Asynchronous An expression is used to compute the maximum or minimum value lis absolute value. Doto is used in Address Trace made when the ATE bit is the Operation 	ted, as appropriate. For timing 2	-		

3. T212 is valid for Address Trace mode when the ATE bit in the Operating Mode Register is set. BR is deasserted for internal accesses and asserted for external accesses.



2.4.5.5 Asynchronous Bus Arbitration Timings

Table 2-16.

No.		Characteristics	Everacian	100 MHz		160 MHz		Unit
NO.			Expression	Min	Max	Min	Max	Unit
250	50 \overline{BB} assertion window from \overline{BG} input deassertion. 2.5 × Tc + 5 - 30 -						20.6	ns
251	Delay	from $\overline{\text{BB}}$ assertion to $\overline{\text{BG}}$ assertion	2×Tc+5	25	—	17.5	_	ns
Notes	 Notes: 1. Bit 13 in the Operating Mode Register must be set to enable Asynchronous Arbitration mode. At 160 MHz, Asynchronous Arbitration mode is recommended. To guarantee timings 250 and 251, it is recommended that you assert non-overlapping BG inputs to different DSP56300 devices (on the same bus), as shown in Figure 2-21, where BG1 is the BG signal for one DSP56300 device while BG2 is BG signal for a second DSP56300 device.) is the

Asynchronous Bus Timings

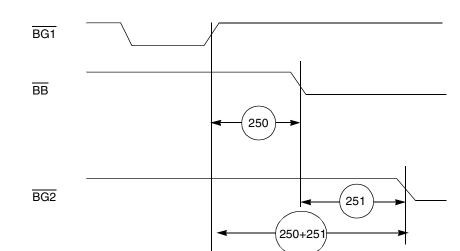


Figure 2-21. Asynchronous Bus Arbitration Timing

The asynchronous bus arbitration is enabled by internal synchronization circuits on \overline{BG} and \overline{BB} inputs. These synchronization circuits add delay from the external signal until it is exposed to internal logic. As a result of this delay, a DSP56300 part may assume mastership and assert \overline{BB} , for some time after \overline{BG} is deasserted. This is the reason for timing 250.

Once \overline{BB} is asserted, there is a synchronization delay from \overline{BB} assertion to the time this assertion is exposed to other DSP56300 components that are potential masters on the same bus. If \overline{BG} input is asserted before that time, and \overline{BG} is asserted and \overline{BB} is deasserted, another DSP56300 component may assume mastership at the same time. Therefore, some non-overlap period between one \overline{BG} input active to another \overline{BG} input active is required. Timing 251 ensures that overlaps are avoided.



2.4.6 Host Interface Timing

N	Characteristic ¹⁰	Francisco	100	MHz	160 MHz		Unit
No.	Characteristic	Expression	Min	Мах	Min	Max	Unit
317	Read data strobe assertion width ⁵ HACK assertion width	100 MHz: T _C + 9.9 160 MHz: T _C + 6.2	19.9	—	12.4	-	ns
318	Read data strobe deassertion width ⁵ HACK deassertion width		9.9	—	6.2	_	ns
319	Read data strobe deassertion width ⁵ after "Last Data Register" reads ^{8,11} , or between two consecutive CVR, ICR, or ISR reads ³ HACK deassertion width after "Last Data Register" reads ^{8,11}	100 MHz: 2.5 × T _C + 6.6	31.6	—	20.2	_	ns
320	Write data strobe assertion width ⁶		13.2	_	8.3	_	ns
321	Write data strobe deassertion width ⁸ HACK write deassertion width • after ICR, CVR and "Last Data Register" writes	100 MHz: 2.5 × T _C + 6.6 160 MHz: 2.5 × T _C + 4.1	31.6	_	19.8	_	ns
	 after IVR writes, or after TXH:TXM:TXL writes (with HLEND= 0), or after TXL:TXM:TXH writes (with HLEND = 1) 		16.5	_	10.6	_	ns
322	HAS assertion width		9.9	_	6.2	_	ns
323	HAS deassertion to data strobe assertion ⁴		0.0	_	0.0	_	ns
324	Host data input set-up time before write data strobe deassertion ⁶		9.9		6.2	—	ns
325	Host data input hold time after write data strobe deassertion ⁶		3.3	_	2.1	_	ns
326	Read data strobe assertion to output data active from high impedance ⁵ HACK assertion to output data active from high impedance		3.3	_	2.1	_	ns
327	Read data strobe assertion to output data valid ⁵ HACK assertion to output data valid		_	24.5	—	16.1	ns
328	Read data strobe deassertion to output data high impedance ⁵ HACK deassertion to output data high impedance			9.9	—	6.2	ns
329	Output data hold time after read data strobe deassertion ⁵ Output data hold time after HACK deassertion		4.1	—	2.1	_	ns
330	HCS assertion to read data strobe deassertion ⁵	100 MHz: T _C + 9.9 160 MHz: T _C + 6.2	19.9	—	12.4	-	ns
331	HCS assertion to write data strobe deassertion ⁶		9.9	_	6.2	_	ns
332	HCS assertion to output data valid		_	19.3	_	14.0	ns
333	HCS hold time after data strobe deassertion ⁴		0.0	_	0.0	_	ns
334	Address (HAD[0–7]) set-up time before HAS deassertion (HMUX=1)		4.7	_	2.9	-	ns
335	Address (HAD[0-7]) hold time after HAS deassertion (HMUX=1)		3.3	—	2.1	—	ns
336	HA[8–10] (HMUX=1), HA[0–2] (HMUX=0), HR/W set-up time before data strobe assertion ⁴ • Read • Write		0 6.6	_	0 2.9		ns ns
337	HA[8–10] (HMUX=1), HA[0–2] (HMUX=0), HR/ \overline{W} hold time after data strobe deassertion ⁴		3.3	-	2.1	-	ns

 Table 2-17.
 Host Interface Timings^{1,2,12}



Na	Characteristic ¹⁰	Everencies	100 MHz		160 MHz		Unit		
No.	Characteristic	Expression	Min	Max	Min	Max	Unit		
338	Delay from read data strobe deassertion to host request assertion for "Last Data Register" read ^{5, 7, 8}	100 MHz: T _C + 5.3 160 MHz: T _C + 3.3	15.3	—	9.6	_	ns ns		
339	Delay from write data strobe deassertion to host request assertion for "Last Data Register" write ^{6, 7, 8}	100 MHz: $1.5 \times T_{C} + 5.3$ 160 MHz: $1.5 \times T_{C} + 3.3$	20.3	—	12.7	_	ns ns		
340	Delay from data strobe assertion to host request deassertion for "Last Data Register" read or write (HROD=0) ^{4, 7, 8}		_	16.8	_	12.2	ns		
341	Delay from data strobe assertion to host request deassertion for "Last Data Register" read or write (HROD=1, open drain host request) ^{4, 7, 8, 9}		_	300.0	_	300.0	ns		
Notes									

 Table 2-17.
 Host Interface Timings^{1,2,12} (Continued)

2. In the timing diagrams below, the controls pins are drawn as active low. The pin polarity is programmable

3. This timing is applicable only if two consecutive reads from one of these registers are executed.

4. The data strobe is Host Read (HRD) or Host Write (HWR) in the Dual Data Strobe mode and Host Data Strobe (HDS) in the Single Data Strobe mode.

5. The read data strobe is HRD in the Dual Data Strobe mode and HDS in the Single Data Strobe mode.

6. The write data strobe is HWR in the Dual Data Strobe mode and HDS in the Single Data Strobe mode.

7. The host request is HREQ in the Single Host Request mode and HRRQ and HTRQ in the Double Host Request mode.

8. The "Last Data Register" is the register at address \$7, which is the last location to be read or written in data transfers. This is RXL/TXL in the Big Endian mode (HLEND = 0; HLEND is the Interface Control Register bit 7—ICR[7]), or RXH/TXH in the Little Endian mode (HLEND = 1).

9. In this calculation, the host request signal is pulled up by a 4.7 k Ω resistor in the Open-drain mode.

10. $V_{CCQH} = 3.3 \text{ V} \pm 0.3 \text{ V}$, $V_{CC} = 1.8 \text{ V} \pm 0.1 \text{ V}$; $T_J = -40^{\circ}\text{C}$ to +100 °C, $C_L = 50 \text{ pF}$

11. This timing is applicable only if a read from the "Last Data Register" is followed by a read from the RXL, RXM, or RXH registers without first polling RXDF or HREQ bits, or waiting for the assertion of the HREQ signal.

12. After the external host writes a new value to the ICR, the HI08 is ready for operation after three DSP clock cycles ($3 \times$ Tc).

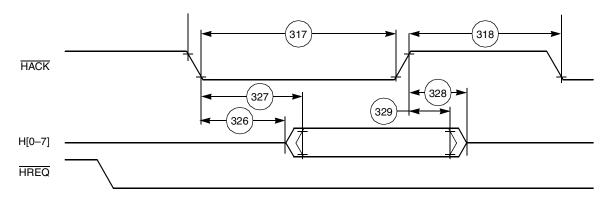
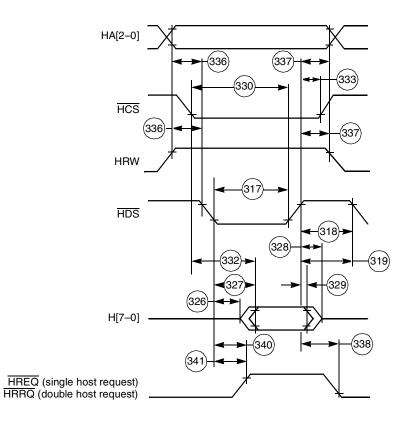


Figure 2-22. Host Interrupt Vector Register (IVR) Read Timing Diagram







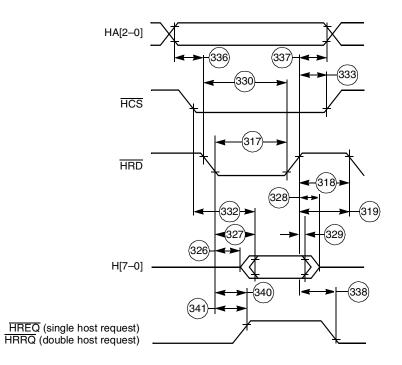
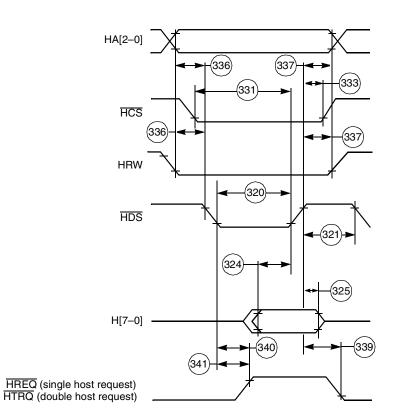
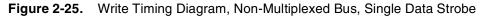


Figure 2-24. Read Timing Diagram, Non-Multiplexed Bus, Double Data Strobe







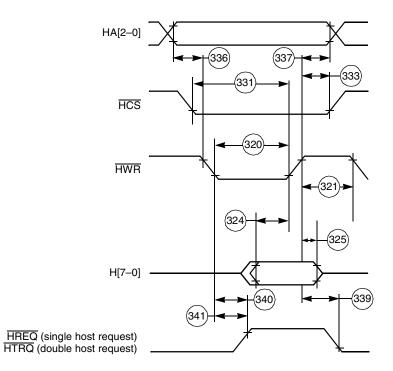


Figure 2-26. Write Timing Diagram, Non-Multiplexed Bus, Double Data Strobe



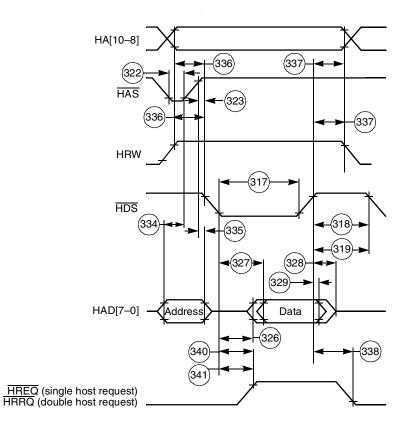


Figure 2-27. Read Timing Diagram, Multiplexed Bus, Single Data Strobe

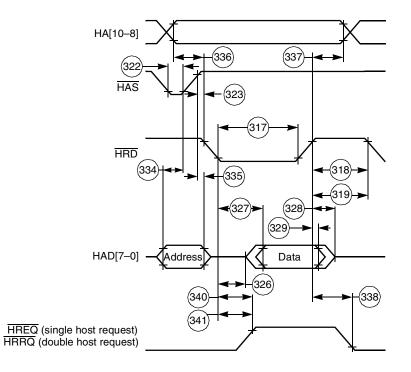


Figure 2-28. Read Timing Diagram, Multiplexed Bus, Double Data Strobe



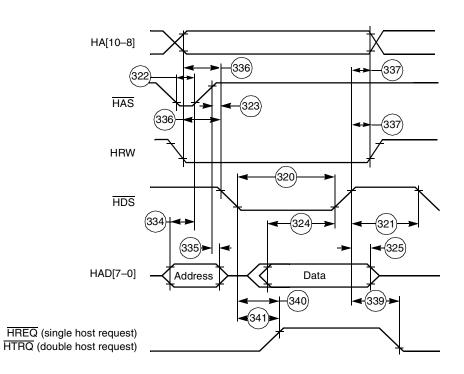


Figure 2-29. Write Timing Diagram, Multiplexed Bus, Single Data Strobe

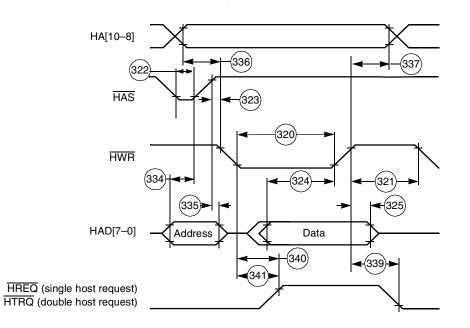


Figure 2-30. Write Timing Diagram, Multiplexed Bus, Double Data Strobe



2.4.7 SCI Timing

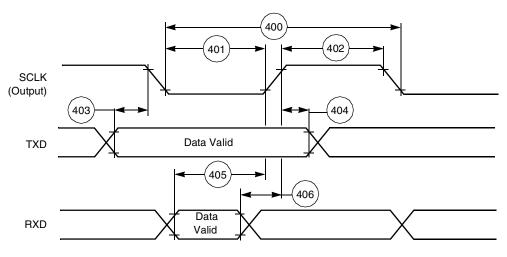
N	Observation in the 1	0	Francisco	100	MHz	160 MHz		Unit
No.	Characteristics ¹	Symbol	Expression	Min	Max	Min	Max	Uni
400	Synchronous clock cycle	t _{SCC} ²	$8 \times T_{C}$	80	_	50	_	ns
401	Clock low period		t _{SCC} /2-10.0	30.0		15.0		ns
402	Clock high period		t _{SCC} /2-10.0	30.0		15.0		ns
403	Output data set-up to clock falling edge (internal clock)		$t_{SCC}/4 + 0.5 \times T_{C} - 10.0$	8.0	—	0.0	_	ns
404	Output data hold after clock rising edge (internal clock)		$t_{SCC}/4~0.5\times~T_{C}$		_	9.4		ns
405	Input data set-up time before clock rising edge (internal clock)		$t_{SCC}/4 + 0.5 \times T_{C} + 25.0$		_	40.6		ns
406	Input data not valid before clock rising edge (internal clock)		$t_{SCC}/4 + 0.5 \times T_{C} - 5.5$		19.5	—	10.1	ns
407	Clock falling edge to output data valid (external clock)			-	32.0	—	32.0	ns
408	Output data hold after clock rising edge (external clock)		T _C + 8.0	18.0	—	14.3		ns
409	Input data set-up time before clock rising edge (external clock)			0.0	_	0.0		ns
410	Input data hold time after clock rising edge (external clock)			9.0	_	9.0		ns
411	Asynchronous clock cycle	t _{ACC} ³	$64 imes T_C$	640.0	—	400.0		ns
412	Clock low period		t _{ACC} /2-10.0	310.0		190.0		ns
413	Clock high period		t _{ACC} /2-10.0	310.0	—	190.0	-	ns
414	Output data set-up to clock rising edge (internal clock)		t _{ACC} /2 -30.0	290.0	—	170.0		ns
415	Output data hold after clock rising edge (internal clock)		t _{ACC} /2 -30.0	290.0	—	170.0		ns

Table 2-18. **SCI** Timings

2.

 t_{SCC} = synchronous clock cycle time (for internal clock, t_{SCC} is determined by the SCI clock control register and T_C). t_{ACC} = asynchronous clock cycle time; value given for 1X Clock mode (for internal clock, t_{ACC} is determined by the SCI clock control register and T_C). 3.





a) Internal Clock

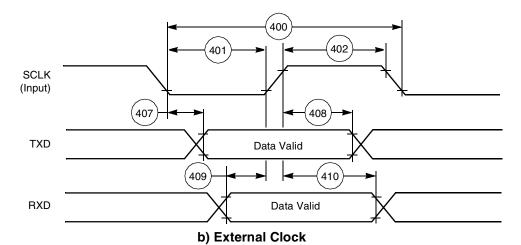


Figure 2-31. SCI Synchronous Mode Timing

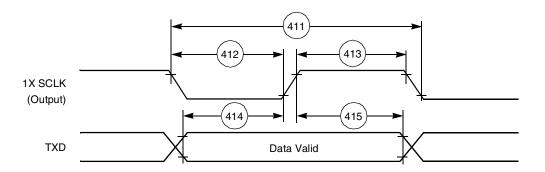


Figure 2-32. SCI Asynchronous Mode Timing



2.5 ESSI0/ESSI1 Timing

No.	Characteristics ^{1, 2, 3}	Symbol	Expression	Min	Max	Condi- tion ⁴	Unit
430	Clock cycle ⁵	t _{SSICC}	$\begin{array}{c} 3\times T_C \\ 4\times T_C \end{array}$	30.0 40.0		x ck i ck	ns
431	Clock high period For internal clock For external clock	_	$\begin{array}{c} 2\times T_{C} -10.0\\ 1.5\times T_{C} \end{array}$	10.0 15.0			ns ns
432	Clock low period For internal clock For external clock	_	$\begin{array}{c} 2\times T_{C}-10.0\\ 1.5\times T_{C}\end{array}$	10.0 15.0	_		ns ns
433	RXC rising edge to FSR out (bl) high	—	_		37.0 22.0	x ck i ck a	ns
434	RXC rising edge to FSR out (bl) low	_	—	_	37.0 22.0	x ck i ck a	ns
435	RXC rising edge to FSR out (wr) high ⁶	—	_	_	39.0 24.0	x ck i ck a	ns
436	RXC rising edge to FSR out (wr) low ⁶	_	_	_	39.0 24.0	x ck i ck a	ns
437	RXC rising edge to FSR out (wl) high	_	_	_	36.0 21.0	x ck i ck a	ns
438	RXC rising edge to FSR out (wl) low	_	—	_	37.0 22.0	x ck i ck a	ns
439	Data in set-up time before RXC (SCK in Synchronous mode) falling edge	_	_	0.0 19.0	_	x ck i ck	ns
440	Data in hold time after RXC falling edge	_	_	5.0 3.0	_	x ck i ck	ns
441	FSR input (bl, wr) high before RXC falling edge ⁶	_	—	23.0 1.0	_	x ck i ck a	ns
442	FSR input (wl) high before RXC falling edge	_	—	23.0 1.0	_	x ck i ck a	ns
443	FSR input hold time after RXC falling edge	_	_	3.0 0.0	_	x ck i ck a	ns
444	Flags input set-up before RXC falling edge	_	—	0.0 19.0	_	xck icks	ns
445	Flags input hold time after RXC falling edge	_	_	6.0 0.0	_	xck icks	ns
446	TXC rising edge to FST out (bl) high	_	—	_	29.0 15.0	x ck i ck	ns
447	TXC rising edge to FST out (bl) low	_	_	_	31.0 17.0	x ck i ck	ns
448	TXC rising edge to FST out (wr) high ⁶	_	—	_	31.0 17.0	x ck i ck	ns
449	TXC rising edge to FST out (wr) low ⁶	—	_	_	33.0 19.0	x ck i ck	ns
450	TXC rising edge to FST out (wl) high	_	_	_	30.0 16.0	x ck i ck	ns

Table 2-19.ESSI Timings at 100 MHz



No.	Characteristics ^{1, 2, 3}	Symbol	Expression	Min	Мах	Condi- tion ⁴	Unit
451	TXC rising edge to FST out (wl) low	ĺ	_		31.0 17.0	x ck i ck	ns
452	TXC rising edge to data out enable from high impedance	_	_		31.0 17.0	x ck i ck	ns
453	TXC rising edge to transmitter 0 drive enable assertion	—	_	_	34.0 20.0	x ck i ck	ns
454	TXC rising edge to data out valid	_	$35 + 0.5 imes T_C$		40.0 21.0	x ck i ck	ns
455	TXC rising edge to data out high impedance ⁷	_	—		31.0 16.0	x ck i ck	ns
456	TXC rising edge to transmitter 0 drive enable deassertion ⁷		_		34.0 20.0	x ck i ck	ns
457	FST input (bl, wr) set-up time before TXC falling edge ⁶	—	_	2.0 21.0		x ck i ck	ns
458	FST input (wl) to data out enable from high impedance	_	—	_	27.0	—	ns
459	FST input (wl) to transmitter 0 drive enable assertion	_	—	_	31.0	_	ns
460	FST input (wl) set-up time before TXC falling edge	—	_	2.0 21.0	_	x ck i ck	ns
461	FST input hold time after TXC falling edge	_	—	4.0 0.0	-	x ck i ck	ns
462	Flag output valid after TXC rising edge	_	_		32.0 18.0	x ck i ck	ns
Notes:	 V_{CCQL} = 2.5 V ±0.25 V; T_J = -40°C to +100 °C, C_L = 50 i ck = Internal Clock x ck = External Clock i ck a = Internal Clock, Asynchronous Mode (Asynchronous implies that TXC and RXC are two i ck s = Internal Clock, Synchronous Mode (Synchronous implies that TXC and RXC are the s bl = bit length wl = word length wr = word length relative TXC (SCK Pin) = Transmit Clock RXC (SC0 or SCK Pin) = Receive Clock FST (SC2 Pin) = Transmit Frame Sync FSR (SC1 or SC2 Pin) Receive Frame Sync For the internal clock, the external clock cycle is defined The word-relative frame sync signal waveform relative t waveform, but it spreads from one serial clock before fin before last bit clock of the first word in frame. Periodically sampled and not 100 per cent tested 	different clock ame clock) I by Icyc and ti o the clock ope	he ESSI control regiserates the same way	/ as the b	-	•	-

 Table 2-19.
 ESSI Timings at 100 MHz (Continued)



ifications

No.	Characteristics ^{1,2,3}	Symbol	Expression	Min	Max	Condi- tion ⁴	Unit
430	Clock cycle ⁵	t _{SSICC}	$\begin{array}{c} 8 \times T_{C} \\ 6 \times T_{C} \end{array}$	50.0 37.5	_	i ck x ck	ns
431	Clock high period For internal clock For external clock		$\begin{array}{c} 4 \times \mathrm{T_{C}} -10.0 \\ 3 \times \mathrm{T_{C}} \end{array}$	15.0 18.8			ns ns
432	Clock low period For internal clock For external clock		$\begin{array}{c} 4 \times T_{C} - 10.0 \\ 3 \times T_{C} \end{array}$	15.0 18.8			ns ns
433	RXC rising edge to FSR out (bl) high			_	37.0 22.0	x ck i ck a	ns
434	RXC rising edge to FSR out (bl) low			_	37.0 22.0	x ck i ck a	ns
435	RXC rising edge to FSR out (wr) high ⁶			_	39.0 24.0	x ck i ck a	ns
436	RXC rising edge to FSR out (wr) low ⁶			_	39.0 24.0	x ck i ck a	ns
437	RXC rising edge to FSR out (wl) high			_	36.0 21.0	x ck i ck a	ns
438	RXC rising edge to FSR out (wl) low			_	37.0 22.0	x ck i ck a	ns
439	Data in set-up time before RXC (SCK in Synchronous mode) falling edge			0.0 19.0	_	x ck i ck	ns
440	Data in hold time after RXC falling edge			5.0 3.0	_	x ck i ck	ns
441	FSR input (bl, wr) high before RXC falling edge ⁶			1.0 6.0	_	x ck i ck a	ns
442	FSR input (wl) high before RXC falling edge			1.0 6.0	_	x ck i ck a	ns
443	FSR input hold time after RXC falling edge			3.0 0.0	_	x ck i ck a	ns
444	Flags input set-up before RXC falling edge			0.0 19.0		x ck i ck s	ns
445	Flags input hold time after RXC falling edge			6.0 0.0	_	x ck i ck s	ns
446	TXC rising edge to FST out (bl) high			_	29.0 15.0	x ck i ck	ns
447	TXC rising edge to FST out (bl) low			_	31.0 17.0	x ck i ck	ns
448	TXC rising edge to FST out (wr) high ⁶			_	31.0 17.0	x ck i ck	ns
449	TXC rising edge to FST out (wr) low ⁶			-	33.0 19.0	x ck i ck	ns
450	TXC rising edge to FST out (wl) high				30.0 16.0	x ck i ck	ns
451	TXC rising edge to FST out (wl) low				31.0 17.0	x ck i ck	ns

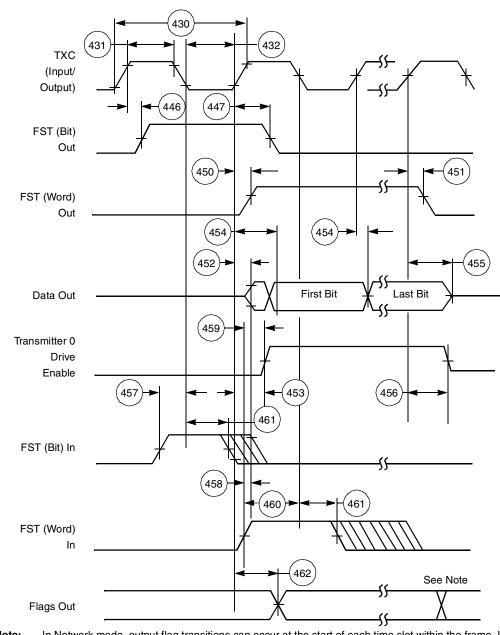
Table 2-20.ESSI Timings at 160 MHz



No.	Characteristics ^{1,2,3}	Symbol	Expression	Min	Мах	Condi- tion ⁴	Unit
452	TXC rising edge to data out enable from high impedance			—	31.0 17.0	x ck i ck	ns
453	TXC rising edge to transmitter 0 drive enable assertion				34.0 20.0	x ck i ck	ns
454	TXC rising edge to data out valid		35 + 0.5 × T _C		38.1 21.0	x ck i ck	ns
455	TXC rising edge to data out high impedance ⁷				31.0 16.0	x ck i ck	ns
456	TXC rising edge to transmitter 0 drive enable deassertion ⁷				34.0 20.0	x ck i ck	ns
457	FST input (bl, wr) set-up time before TXC falling edge ⁶			2.0 21.0	-	x ck i ck	ns
458	FST input (wl) to data out enable from high impedance			_	27.0	—	ns
459	FST input (wl) to transmitter 0 drive enable assertion			_	31.0	_	ns
460	FST input (wl) set-up time before TXC falling edge			2.0 21.0	_	x ck i ck	ns
461	FST input hold time after TXC falling edge			4.0 0.0	—	x ck i ck	ns
462	Flag output valid after TXC rising edge				32.0 18.0	x ck i ck	ns
Notes:	 V_{CCQL} = 2.5 V ±0.25 V; T_J = -40°C to +100 °C, C_L = 50 i ck = internal clock x ck = external clock i ck a = internal clock, Asynchronous mode (asynchronous implies that TXC and RXC are two i ck s = internal clock, Synchronous mode (synchronous implies that TXC and RXC are the s bl = bit length wl = word length read wr = word length relative TXC (SCK pin) = transmit clock RXC (SC0 or SCK pin) = receive clock FST (SC2 pin) = transmit frame sync FSR (SC1 or SC2 pin) receive frame sync For the internal clock, the external clock cycle is defined The word-relative frame sync signal waveform relative to signal waveform, but it spreads from one serial clock be before last bit clock of the first word in frame. Periodically sampled and not 100 per cent tested 	different clock ame clock) d by I _{CYC} and t	he ESSI Control Re erates in the same n	nanner a	s the bit-	0	

 Table 2-20.
 ESSI Timings at 160 MHz (Continued)





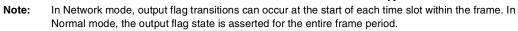


Figure 2-33.	ESSI T	ransmitter	Timing
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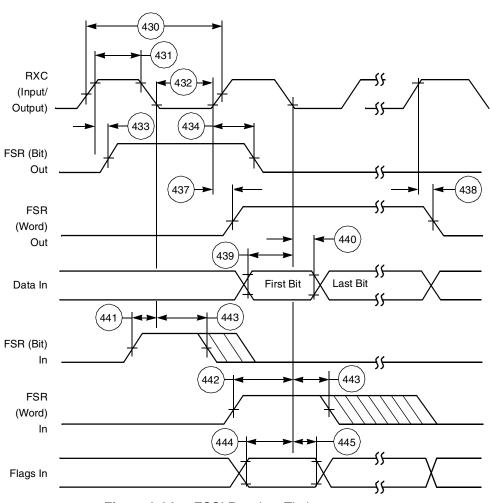


Figure 2-34. ESSI Receiver Timing



2.5.1 Timer Timing

No.	Characteristics	Expression	100 MHz		160 MHz		1114
			Min	Max	Min	Max	Unit
480	TIO Low	$2 \times T_{C} + 2.0$	22.0	_	14.5	_	ns
481	TIO High	$2 \times T_{C} + 2.0$	22.0	—	14.5		ns
482	Timer set-up time from TIO (Input) assertion to CLKOUT rising edge		9.0	10.0			1
483	Synchronous timer delay time from CLKOUT rising edge to the external memory access address out valid caused by first interrupt instruction execution	10.25 × T _C + 1.0	103.5	_			
484	CLKOUT rising edge to TIO (Output) assertion Minimum Maximum 	$0.5 \times T_{C} + 0.5$ $0.5 \times T_{C} + 19.8$	5.5 —	 24.8			
486	Synchronous delay time from Timer input rising edge to the external memory address out valid caused by the first interrupt instruction execution	$10.25 \times T_{C} + 10.0$	112.5	_	74.06		ns
Note:	$V_{CCQH} = 3.3 \text{ V} \pm 0.3 \text{ V}, V_{CC} = 1.8 \text{ V} \pm 0.1 \text{ V}; T_J = -40^{\circ}\text{C} \text{ to } +100 ^{\circ}\text{C}, C_L = 50 \text{ pF}.$						

Table 2-21.Timer Timings

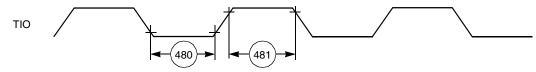


Figure 2-35. TIO Timer Event Input Restrictions

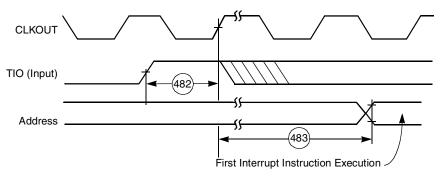


Figure 2-36. Timer Interrupt Generation

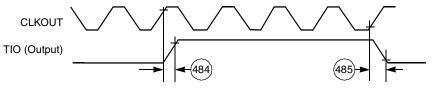
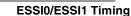
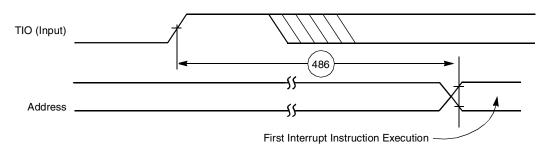
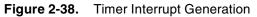


Figure 2-37. External Pulse Generation





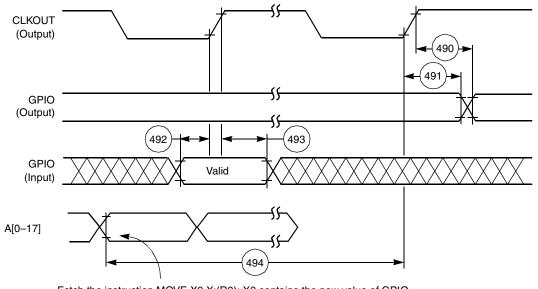




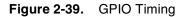
2.5.2 Considerations For GPIO Use

2.5.2.1 Operating Frequency of 100 MHz or Less

No.	Characteristics	Expression	100	Unit	
		Expression	Min	Max	Onit
490	CLKOUT edge to GPIO out valid (GPIO out delay time)		—	8.5	ns
491	CLKOUT edge to GPIO out not valid (GPIO out hold time)		0.0	_	ns
492	GPIO In valid to CLKOUT edge (GPIO in set-up time)		8.5	_	ns
493	CLKOUT edge to GPIO in not valid (GPIO in hold time)		0.0	_	ns
494	Fetch to CLKOUT edge before GPIO change	Minimum: $6.75 \times T_{C}$	67.5	_	ns
Note:	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}; \text{ T}_{\text{J}} = -40^{\circ}\text{C} \text{ to } +100 ^{\circ}\text{C}, \text{ C}_{\text{L}} = 50 \text{ pF}.$		•		



Fetch the instruction MOVE X0,X:(R0); X0 contains the new value of GPIO and R0 contains the address of the GPIO data register.





2.5.2.2 With an Operating Frequency above 100 MHz

The following considerations can be helpful when GPIO is used for output or input with an operating frequency above 100 MHz (that is, when CLKOUT is not available).

- GPIO as Output:
 - The time from fetch of the instruction that changes the GPIO pin to the actual change is seven core clock cycles. This is true, assuming that the instruction is a one-cycle instruction and that there are no pipeline stalls or any other pipeline delays.
 - The maximum rise or fall time of a GPIO pin is 13 ns (TTL levels, assuming that the maximum of 50 pF load limit is met).
- *GPIO as Input*—GPIO inputs are not synchronized with the core clock. When only one GPIO bit is polled, this lack of synchronization presents no problem, since the read value can be either the previous value or the new value of the corresponding GPIO pin. However, there is the risk of reading an intermediate state if:
 - Two or more GPIO bits are treated as a coupled group (for example, four possible status states encoded in two bits).
 - The read operation occurs during a simultaneous change of GPIO pins (for example, the change of 00 to 11 may happen through an intermediate state of 01 or 10).

Therefore, when GPIO bits are read, the recommended practice is to poll continuously until two consecutive read operations have identical results.

2.5.3 JTAG Timing

Na	Ob any sharks in the	All freq			
No.	Characteristics	Min	Max	Unit	
500	TCK frequency of operation (1/($T_{C} \times 3$); maximum 22 MHz)	0.0	22.0	MHz	
501	TCK cycle time in Crystal mode	45.0	_	ns	
502	TCK clock pulse width measured at 1.5 V	20.0	_	ns	
503	TCK rise and fall times	0.0	3.0	ns	
504	Boundary scan input data set-up time	5.0	_	ns	
505	Boundary scan input data hold time	24.0	_	ns	
506	TCK low to output data valid	0.0	40.0	ns	
507	TCK low to output high impedance	0.0	40.0	ns	
508	TMS, TDI data set-up time	5.0	_	ns	
509	TMS, TDI data hold time	25.0	_	ns	
510	TCK low to TDO data valid	0.0	44.0	ns	
511	TCK low to TDO high impedance	0.0	44.0	ns	
512	TRST assert time	100.0	—	ns	
513	TRST set-up time to TCK low	40.0	—	ns	
Notes:	1. $V_{CCQH} = 3.3 V \pm 0.3 V$, $V_{CC} = 1.8 V \pm 0.1 V$; $T_J = -40^{\circ}C$ to +100 °C, $C_L = 50 \text{ pF}$. 2. All timings apply to OnCE module data transfers because it uses the JTAG port as				

Table	2-23.	JTAG	Timing

ESSI0/ESSI1 Timing



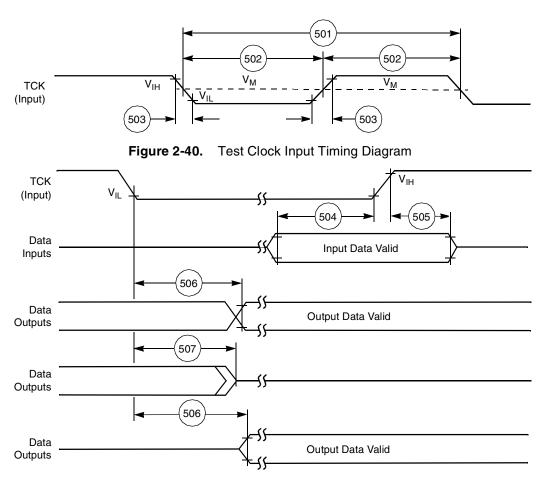


Figure 2-41. Boundary Scan (JTAG) Timing Diagram

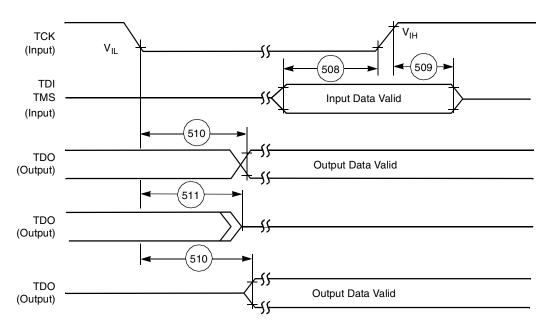


Figure 2-42. Test Access Port Timing Diagram



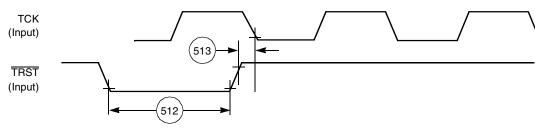


Figure 2-43. TRST Timing Diagram

2.5.4 OnCE Module TimIng

 Table 2-24.
 OnCE Module Timing

No.	Characteristics	Expression	Min	Max	Unit
500	TCK frequency of operation	Max 22.0 MHz	0.0	22.0	MHz
514	DE assertion time in order to enter Debug mode	$1.5 imes T_{C} + 10.0$	20.0	—	ns
515	Response time when DSP56L307 is executing NOP instructions from internal memory	5.5 × T _C + 30.0	—	67.0	ns
516	Debug acknowledge assertion time	$3 \times T_{C} + 5.0$	25.0	—	ns
Note:	te: $V_{CCQH} = 3.3 \text{ V} \pm 0.3 \text{ V}, V_{CC} = 1.8 \text{ V} \pm 0.1 \text{ V}; T_{J} = -40^{\circ}\text{C} \text{ to } +100 ^{\circ}\text{C}, C_{L} = 50 \text{ pF}$				

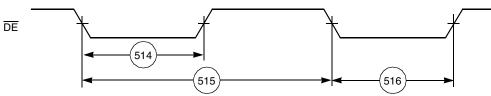


Figure 2-44. OnCE—Debug Request



Packaging

This section includes diagrams of the DSP56L307 package pin-outs and tables showing how the signals described in **Chapter 1** are allocated for the package. The DSP56L307 is available in a 196-pin molded array plastic-ball grid array (MAP-BGA) package.



3.1 Package Description

Top and bottom views of the MAP-BGA packages are shown in Figure 3-1 and Figure 3-2 with their pin-outs.

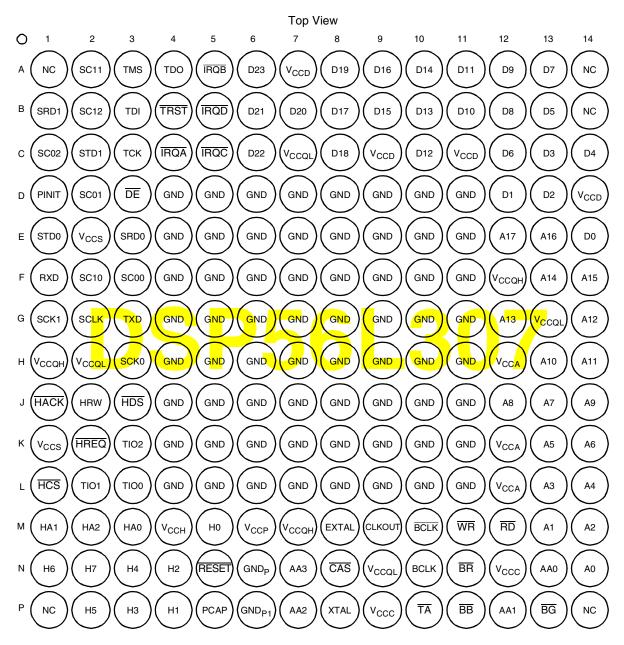


Figure 3-1. DSP56L307 MAP-BGA Package, Top View



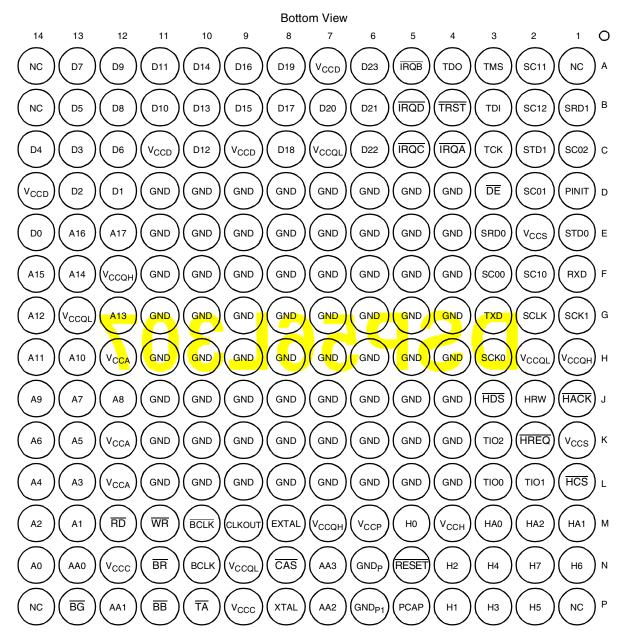


Figure 3-2. DSP56L307 MAP-BGA Package, Bottom View



Ball No.	Signal Name	Ball No.	Signal Name	Ball No.	Signal Name
A1	Not Connected (NC), reserved	B12	D8	D9	GND
A2	SC11 or PD1	B13	D5	D10	GND
A3	TMS	B14	NC	D11	GND
A4	TDO	C1	SC02 or PC2	D12	D1
A5	MODB/IRQB	C2	STD1 or PD5	D13	D2
A6	D23	C3	ТСК	D14	V _{CCD}
A7	V _{CCD}	C4	MODA/IRQA	E1	STD0 or PC5
A8	D19	C5	MODC/IRQC	E2	V _{CCS}
A9	D16	C6	D22	E3	SRD0 or PC4
A10	D14	C7	V _{CCQL}	E4	GND
A11	D11	C8	D18	E5	GND
A12	D9	C9	V _{CCD}	E6	GND
A13	D7	C10	D12	E7	GND
A14	NC	C11	V _{CCD}	E8	GND
B1	SRD1 or PD4	C12	D6	E9	GND
B2	SC12 or PD2	C13	D3	E10	GND
B3	TDI	C14	D4	E11	GND
B4	TRST	D1	PINIT/NMI	E12	A17
B5	MODD/IRQD	D2	SC01 or PC1	E13	A16
B6	D21	D3	DE	E14	D0
B7	D20	D4	GND	F1	RXD or PE0
B8	D17	D5	GND	F2	SC10 or PD0
B9	D15	D6	GND	F3	SC00 or PC0
B10	D13	D7	GND	F4	GND
B11	D10	D8	GND	F5	GND

Table 3-1. Signal List by Ball Number



Package Description

Ball No.	Signal Name	Ball No.	Signal Name	Ball No.	Signal Name
F6	GND	H3	SCK0 or PC3	J14	A9
F7	GND	H4	GND	K1	V _{CCS}
F8	GND	H5	GND	K2	HREQ/HREQ, HTRQ/HTRQ, or PB14
F9	GND	H6	GND	КЗ	TIO2
F10	GND	H7	GND	K4	GND
F11	GND	H8	GND	K5	GND
F12	V _{CCQH}	H9	GND	K6	GND
F13	A14	H10	GND	K7	GND
F14	A15	H11	GND	K8	GND
G1	SCK1 or PD3	H12	V _{CCA}	K9	GND
G2	SCLK or PE2	H13	A10	K10	GND
G3	TXD or PE1	H14	A11	K11	GND
G4	GND	J1	HACK/HACK, HRRQ/HRRQ, or PB15	K12	V _{CCA}
G5	GND	J2	HRW, HRD/HRD, or PB11	K13	A5
G6	GND	JЗ	HDS/HDS, HWR/HWR, or PB12	K14	A6
G7	GND	J4	GND	L1	HCS/HCS, HA10, or PB13
G8	GND	J5	GND	L2	TIO1
G9	GND	J6	GND	L3	TIO0
G10	GND	J7	GND	L4	GND
G11	GND	J8	GND	L5	GND
G12	A13	J9	GND	L6	GND
G13	V _{CCQL}	J10	GND	L7	GND
G14	A12	J11	GND	L8	GND
H1	V _{CCQH}	J12	A8	L9	GND
H2	V _{CCQL}	J13	A7	L10	GND

 Table 3-1.
 Signal List by Ball Number



Ball No.	Signal Name	Ball No.	Signal Name	Ball No.	Signal Name	
L11	GND	M13	A1	P1	NC	
L12	V _{CCA}	M14	A2	P2	H5, HAD5, or PB5	
L13	A3	N1	H6, HAD6, or PB6	P3	H3, HAD3, or PB3	
L14	A4	N2	H7, HAD7, or PB7	P4	H1, HAD1, or PB1	
M1	HA1, HA8, or PB9	N3	H4, HAD4, or PB4	P5	PCAP	
M2	HA2, HA9, or PB10	N4	H2, HAD2, or PB2	P6	GND _{P1}	
M3	HA0, HAS/HAS, or PB8	N5	RESET	P7	AA2/RAS2	
M4	V _{CCH}	N6	GND _P	P8	XTAL	
M5	H0, HAD0, or PB0	N7	AA3/RAS3	P9	V _{CCC}	
M6	V _{CCP}	N8	CAS	P10	TA	
M7	V _{CCQH}	N9	V _{CCQL}	P11	BB	
M8	EXTAL	N10	BCLK ²	P12	AA1/RAS1	
M9	CLKOUT ²	N11	BR	P13	BG	
M10	BCLK ²	N12	V _{CCC}	P14	NC	
M11	WR	N13	AA0/RAS0			
M12	RD	N14	AO			
Notes:	Notes: 1. Signal names are based on configured functionality. Most connections supply a single signal. Some connections provide a signal with dual functionality, such as the MODx/IRQx pins that select an operating mode after RESET is deasserted but act as interrupt lines during operation. Some signals have configurable polarity; these names are shown with and without overbars,					

 Table 3-1.
 Signal List by Ball Number

Signal names are based on configured functionality. Most connections supply a single signal. Some connections provide a signal with dual functionality, such as the MODx/IRQx pins that select an operating mode after RESET is deasserted but act as interrupt lines during operation. Some signals have configurable polarity; these names are shown with and without overbars, such as HAS/HAS. Some connections have two or more configurable functions; names assigned to these connections indicate the function for a specific configuration. For example, connection N2 is data line H7 in non-multiplexed bus mode, data/address line HAD7 in multiplexed bus mode, or GPIO line PB7 when the GPIO function is enabled for this pin. Most of the GND pins are connected internally in the center of the connection array and act as heat sink for the chip. Therefore, except for GND_P and GND_{P1} that support the PLL, other GND signals do not support individual subsystems in the chip.
 CLKOUT, BCLK, and BCLK are available only if the operating frequency is ≤100 MHz.



Signal Name	Ball No.	Signal Name	Ball No.	Signal Name	Ball No.
A0	N14	BR	N11	D9	A12
A1	M13	CAS	N8	DE	D3
A10	H13	CLKOUT	M9	EXTAL	M8
A11	H14	D0	E14	GND	D4
A12	G14	D1	D12	GND	D5
A13	G12	D10	B11	GND	D6
A14	F13	D11	A11	GND	D7
A15	F14	D12	C10	GND	D8
A16	E13	D13	B10	GND	D9
A17	E12	D14	A10	GND	D10
A2	M14	D15	B9	GND	D11
A3	L13	D16	A9	GND	E4
A4	L14	D17	B8	GND	E5
A5	K13	D18	C8	GND	E6
A6	K14	D19	A8	GND	E7
A7	J13	D2	D13	GND	E8
A8	J12	D20	B7	GND	E9
A9	J14	D21	B6	GND	E10
AA0	N13	D22	C6	GND	E11
AA1	P12	D23	A6	GND	F4
AA2	P7	D3	C13	GND	F5
AA3	N7	D4	C14	GND	F6
BB	P11	D5	B13	GND	F7
BCLK	M10	D6	C12	GND	F8
BCLK	N10	D7	A13	GND	F9
BG	P13	D8	B12	GND	F10

 Table 3-2.
 Signal List by Signal Name



Signal Name	Ball No.	Signal Name	Ball No.	Signal Name	Ball No.
GND	F11	GND	K4	H7	N2
GND	G4	GND	K5	HA0	M3
GND	G5	GND	K6	HA1	M1
GND	G6	GND	K7	HA10	L1
GND	G7	GND	K8	HA2	M2
GND	G8	GND	K9	HA8	M1
GND	G9	GND	K10	HA9	M2
GND	G10	GND	K11	HACK/HACK	J1
GND	G11	GND	L4	HAD0	M5
GND	H4	GND	L5	HAD1	P4
GND	H5	GND	L6	HAD2	N4
GND	H6	GND	L7	HAD3	P3
GND	H7	GND	L8	HAD4	N3
GND	H8	GND	L9	HAD5	P2
GND	H9	GND	L10	HAD6	N1
GND	H10	GND	L11	HAD7	N2
GND	H11	GND _P	N6	HAS/HAS	M3
GND	J4	GND _{P1}	P6	HCS/HCS	L1
GND	J5	H0	M5	HDS/HDS	J3
GND	J6	H1	P4	HRD/HRD	J2
GND	J7	H2	N4	HREQ/HREQ	K2
GND	J8	H3	P3	HRRQ/HRRQ	J1
GND	J9	H4	N3	HRW	J2
GND	J10	H5	P2	HTRQ/HTRQ	K2
GND	J11	H6	N2	HWR/HWR	J3

Table 3-2. Signal List by Signal Name

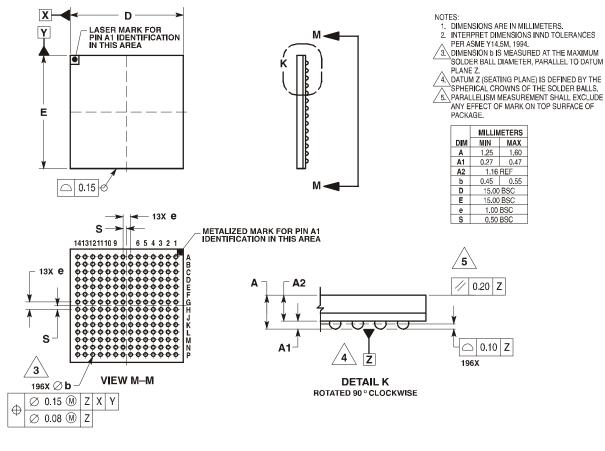


Signal Name	Ball No.	Signal Name	Ball No.	Signal Name	Ball No.
ĪRQĀ	C4	PC3	H3	STD1	C2
IRQB	A5	PC4	E3	TA	P10
IRQC	C5	PC5	E1	ТСК	C3
IRQD	B5	PCAP	P5	TDI	B3
MODA	C4	PD0	F2	TDO	A4
MODB	A5	PD1	A2	TIO0	L3
MODC	C5	PD2	B2	TIO1	L2
MODD	B5	PD3	G1	TIO2	K3
NC	A1	PD4	B1	TMS	A3
NC	A14	PD5	C2	TRST	B4
NC	B14	PE0	F1	TXD	G3
NC	P1	PE1	G3	V _{CCA}	H12
NC	P14	PE2	G2	V _{CCA}	K12
NMI	D1	PINIT	D1	V _{CCA}	L12
PB0	M5	RAS0	N13	V _{CCC}	N12
PB1	P4	RAS1	P12	V _{CCC}	P9
PB10	M2	RAS2	P7	V _{CCD}	A7
PB11	J2	RAS3	N7	V _{CCD}	C9
PB12	J3	RD	M12	V _{CCD}	C11
PB13	L1	RESET	N5	V _{CCD}	D14
PB14	K2	RXD	F1	V _{CCH}	M4
PB15	J1	SC00	F3	V _{CCP}	M6
PB2	N4	SC01	D2	V _{CCQH}	F12
PB3	P3	SC02	C1	V _{CCQH}	H1
PB4	N3	SC10	F2	V _{CCQH}	M7
PB5	P2	SC11	A2	V _{CCQL}	C7
PB6	N1	SC12	B2	V _{CCQL}	G13
PB7	N2	SCK0	H3	V _{CCQL}	H2
PB8	M3	SCK1	G1	V _{CCQL}	N9
PB9	M1	SCLK	G2	V _{CCS}	E2
PC0	F3	SRD0	E3	V _{CCS}	K1
PC1	D2	SRD1	B1	WR	M11
PC2	C1	STD0	E1	XTAL	P8

 Table 3-2.
 Signal List by Signal Name



3.2 MAP-BGA Package Mechanical Drawing



CASE 1128C-01 ISSUE O

DATE 07/28/98

Figure 3-3. DSP56L307 Mechanical Information, 196-pin MAP-BGA Package



Design Considerations

This section describes various areas to consider when incorporating the DSP56L307 device into a system design.

4.1 Thermal Design Considerations

An estimate of the chip junction temperature, T_J , in $^\circ C$ can be obtained from this equation:

Equation 1: $T_J = T_A + (P_D \times R_{\theta JA})$

Where:

T _A	=	ambient temperature °C
$R_{\theta JA}$	=	package junction-to-ambient thermal resistance °C/W
P _D		= power dissipation in package

Historically, thermal resistance has been expressed as the sum of a junction-to-case thermal resistance and a case-to-ambient thermal resistance, as in this equation:

Equation 2: $R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$

Where:

$R_{\theta JA}$	=	package junction-to-ambient thermal resistance °C/W
$R_{\theta JC}$	=	package junction-to-case thermal resistance °C/W
$R_{\theta CA}$	=	package case-to-ambient thermal resistance °C/W

 $R_{\theta JC}$ is device-related and cannot be influenced by the user. The user controls the thermal environment to change the case-to-ambient thermal resistance, $R_{\theta CA}$. For example, the user can change the air flow around the device, add a heat sink, change the mounting arrangement on the printed circuit board (PCB) or otherwise change the thermal dissipation capability of the area surrounding the device on a PCB. This model is most useful for ceramic packages with heat sinks; some 90 percent of the heat flow is dissipated through the case to the heat sink and out to the ambient environment. For ceramic packages, in situations where the heat flow is split between a path to the case and an alternate path through the PCB, analysis of the device thermal performance may need the additional modeling capability of a system-level thermal simulation tool.

The thermal performance of plastic packages is more dependent on the temperature of the PCB to which the package is mounted. Again, if the estimates obtained from $R_{\theta JA}$ do not satisfactorily answer whether the thermal performance is adequate, a system-level model may be appropriate. A complicating factor is the existence of three common ways to determine the junction-to-case thermal resistance in plastic packages.

- To minimize temperature variation across the surface, the thermal resistance is measured from the junction to the outside surface of the package (case) closest to the chip mounting area when that surface has a proper heat sink.
- To define a value approximately equal to a junction-to-board thermal resistance, the thermal resistance is measured from the junction to the point at which the leads attach to the case.

on Considerations

• If the temperature of the package case (T_T) is determined by a thermocouple, thermal resistance is computed from the value obtained by the equation $(T_J - T_T)/P_D$.

As noted earlier, the junction-to-case thermal resistances quoted in this data sheet are determined using the first definition. From a practical standpoint, that value is also suitable to determine the junction temperature from a case thermocouple reading in forced convection environments. In natural convection, the use of the junction-to-case thermal resistance to estimate junction temperature from a thermocouple reading on the case of the package will yield an estimate of a junction temperature slightly higher than actual temperature. Hence, the new thermal metric, thermal characterization parameter or Ψ_{JT} , has been defined to be $(T_J - T_T)/P_D$. This value gives a better estimate of the junction temperature in natural convection when the surface temperature of the package is used. Remember that surface temperature readings of packages are subject to significant errors caused by inadequate attachment of the sensor to the surface and to errors caused by heat loss to the sensor. The recommended technique is to attach a 40-gauge thermocouple wire and bead to the top center of the package with thermally conductive epoxy.

4.2 Electrical Design Considerations

CAUTION
This device contains protective circuitry to guard against damage due to high static voltage or electrical fields. However, normal precautions are advised to avoid application of any voltages higher than maximum rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (for example, either GND or V_{CC}).

Use the following list of recommendations to ensure correct DSP operation.

- Provide a low-impedance path from the board power supply to each V_{CC} pin on the DSP and from the board ground to each GND pin.
- Use at least six 0.01–0.1 μ F bypass capacitors positioned as close as possible to the four sides of the package to connect the V_{CC} power source to GND.
- Ensure that capacitor leads and associated printed circuit traces that connect to the chip V_{CC} and GND pins are less than 0.5 inch per capacitor lead.
- Use at least a four-layer PCB with two inner layers for V_{CC} and GND.
- Because the DSP output signals have fast rise and fall times, PCB trace lengths should be minimal. This recommendation particularly applies to the address and data buses as well as the IRQA, IRQB, IRQC, IRQD, TA, and BG pins. Maximum PCB trace lengths on the order of 6 inches are recommended.
- Consider all device loads as well as parasitic capacitance due to PCB traces when you calculate capacitance. This is especially critical in systems with higher capacitive loads that could create higher transient currents in the V_{CC} and GND circuits.



- All inputs must be terminated (that is, not allowed to float) by CMOS levels except for the three pins with internal pull-up resistors (TRST, TMS, DE).
- Take special care to minimize noise levels on the V_{CCP} , GND_P , and GND_{P1} pins.
- The following pins must be asserted during power-up: RESET and TRST. A stable EXTAL signal should be supplied before deassertion of RESET. If the V_{CC} reaches the required level before EXTAL is stable or other "required RESET duration" conditions are met (see **Table 2-7**), the device circuitry can be in an uninitialized state that may result in significant power consumption and heat-up. Designs should minimize this condition to the shortest possible duration.
- Ensure that during power-up, and throughout the DSP56L307 operation, V_{CCQH} is always higher or equal to the V_{CC} voltage level.
- If multiple DSP devices are on the same board, check for cross-talk or excessive spikes on the supplies due to synchronous operation of the devices.
- The Port A data bus (D[0–23]), HI08, ESSI0, ESSI1, SCI, and timers all use internal keepers to maintain the last output value even when the internal signal is tri-stated. Typically, no pull-up or pull-down resistors should be used with these signal lines. However, if the DSP is connected to a device that requires pull-up resistors (such as an MPC8260), the recommended resistor value is 10 K Ω or less. If more than one DSP must be connected in parallel to the other device, the pull-up resistor value requirement changes as follows:
 - 2 DSPs = 7 K Ω or less
 - -3 DSPs = 4 K Ω or less
 - 4 DSPs = 3 K Ω or less
 - 5 DSPs = 2 K Ω or less
 - 6 DSPs = $1.5 \text{ K}\Omega \text{ or less}$

4.3 Power Consumption Considerations

Power dissipation is a key issue in portable DSP applications. Some of the factors affecting current consumption are described in this section. Most of the current consumed by CMOS devices is alternating current (ac), which is charging and discharging the capacitances of the pins and internal nodes.

Current consumption is described by this formula:

Equation 3: $I = C \times V \times f$

Where:

villere.		
С	=	node/pin capacitance
V	=	voltage swing
f	=	frequency of node/pin toggle

Example 4-1.	Current Consumption
--------------	---------------------

For a Port A address pin loaded with 50 pF capacitance, operating at 3.3 V, with a 66 MHz clock, toggling at its maximum possible rate (33 MHz), the current consumption is expressed in **Equation 4**.

Equation 4: $I = 50 \times 10^{-12} \times 3.3 \times 33 \times 10^{6} = 5.48 \ mA$



3n Considerations

The maximum internal current (I_{CCI} max) value reflects the typical possible switching of the internal buses on bestcase operation conditions—not necessarily a real application case. The typical internal current (I_{CCItyp}) value reflects the average switching of the internal buses on typical operating conditions.

Perform the following steps for applications that require very low current consumption:

- 1. Set the EBD bit when you are not accessing external memory.
- 2. Minimize external memory accesses, and use internal memory accesses.
- **3.** Minimize the number of pins that are switching.
- **4.** Minimize the capacitive load on the pins.
- 5. Connect the unused inputs to pull-up or pull-down resistors.
- 6. Disable unused peripherals.
- 7. Disable unused pin activity (for example, CLKOUT, XTAL).

One way to evaluate power consumption is to use a current-per-MIPS measurement methodology to minimize specific board effects (that is, to compensate for measured board current not caused by the DSP). A benchmark power consumption test algorithm is listed in **Appendix A**. Use the test algorithm, specific test current measurements, and the following equation to derive the current-per-MIPS value.

Equation 5: ' MIPS = I/ MHz = $(I_{typF2} - I_{typF1})$ / (F2 - F1

Where:

I _{typF2}	=	current at F2
I _{typF1}	=	current at F1
F2	=	high frequency (any specified operating frequency)
F1	=	low frequency (any specified operating frequency lower than F2)

Note: F1 should be significantly less than F2. For example, F2 could be 66 MHz and F1 could be 33 MHz. The degree of difference between F1 and F2 determines the amount of precision with which the current rating can be determined for an application.

4.4 PLL Performance Issues

The following explanations should be considered as general observations on expected PLL behavior. There is no test that replicates these exact numbers. These observations were measured on a limited number of parts and were not verified over the entire temperature and voltage ranges.

4.4.1 Phase Skew Performance

The phase skew of the PLL is defined as the time difference between the falling edges of EXTAL and CLKOUT for a given capacitive load on CLKOUT, over the entire process, temperature and voltage ranges. As defined in **Figure 2**-2, *External Clock Timing*, on page 2-5 for input frequencies greater than 15 MHz and the MF \leq 4, this skew is greater than or equal to 0.0 ns and less than 1.8 ns; otherwise, this skew is not guaranteed. However, for MF < 10 and input frequencies greater than 10 MHz, this skew is between -1.4 ns and +3.2 ns.





4.4.2 Phase Jitter Performance

The phase jitter of the PLL is defined as the variations in the skew between the falling edges of EXTAL and CLKOUT for a given device in specific temperature, voltage, input frequency, MF, and capacitive load on CLKOUT. These variations are a result of the PLL locking mechanism. For input frequencies greater than 15 MHz and MF \leq 4, this jitter is less than \pm 0.6 ns; otherwise, this jitter is not guaranteed. However, for MF < 10 and input frequencies greater than 10 MHz, this jitter is less than \pm 2 ns.

4.4.3 Frequency Jitter Performance

The frequency jitter of the PLL is defined as the variation of the frequency of CLKOUT. For small MF (MF < 10) this jitter is smaller than 0.5 percent. For mid-range MF (10 < MF < 500) this jitter is between 0.5 percent and approximately 2 percent. For large MF (MF > 500), the frequency jitter is 2–3 percent.

4.5 Input (EXTAL) Jitter Requirements

The allowed jitter on the frequency of EXTAL is 0.5 percent. If the rate of change of the frequency of EXTAL is slow (that is, it does not jump between the minimum and maximum values in one cycle) or the frequency of the jitter is fast (that is, it does not stay at an extreme value for a long time), then the allowed jitter can be 2 percent. The phase and frequency jitter performance results are valid only if the input jitter is less than the prescribed values.



gn Considerations



Power Consumption Benchmark

The following benchmark program evaluates DSP56L307 power use in a test situation. It enables the PLL, disables the external clock, and uses repeated multiply-accumulate (MAC) instructions with a set of synthetic DSP application data to emulate intensive sustained DSP operation.

```
****
          *****
;**
;*
;*
                  CHECKS Typical Power Consumption
                                                              *
;*
                                                              *
*****
     page
           200,55,0,0,0
     nolist
I_VEC EQU $000000
                            ; Interrupt vectors for program debug only
START EQU $8000
                            ; MAIN (external) program starting address
INT_PROG EQU $100
                            ; INTERNAL program memory starting address
INT_XDAT EQU $0
                            ; INTERNAL X-data memory starting address
INT_YDAT EQU $0
                             ; INTERNAL Y-data memory starting address
     INCLUDE "ioequ.asm"
     INCLUDE "intequ.asm"
      list
     org
           P:START
;
     movep #$0243FF,x:M_BCR ; ; BCR: Area 3 = 2 w.s (SRAM)
                             ; Default: 2w.s (SRAM)
;
     movep #$0d0000,x:M_PCTL
                             ; XTAL disable
                              ; PLL enable
                              ; CLKOUT disable
;
                              ; Load the program
;
           #INT_PROG,r0
     move
           #PROG_START,r1
     move
           #(PROG_END-PROG_START), PLOAD_LOOP
     do
           p:(r1)+,x0
     move
     move
           x0,p:(r0)+
     nop
PLOAD_LOOP
;
                              ; Load the X-data
;
           #INT_XDAT,r0
     move
           #XDAT_START,r1
     move
           #(XDAT_END-XDAT_START), XLOAD_LOOP
     do
           p:(r1)+,x0
     move
     move
           x0,x:(r0)+
```

Pr Consumption Benchmark

XLOAD	LOOP		
	d the Y-	data	
;	move move do move	<pre>#INT_YDAT,r0 #YDAT_START,r1 #(YDAT_END-YDAT_STA) p:(r1)+,x0 </pre>	RT),YLOAD_LOOP
YLOAD_	move _LOOP	x0,y:(r0)+	
;			
	jmp	INT_PROG	
PROG_S	START		
	move	#\$0,r0	
	move	#\$0,r4	
	move	#\$3f,m0	
	move	#\$3f,m4	
;	clr	a	
	clr	b	
	move	#\$0,x0	
	move	#\$0,x1	
	move	#\$0,y0	
	move bset	#\$0,y1 #4,omr	; ebd
;	DBCC		, cbu
sbr	dor	#60,_end	
	mac	x0,y0,ax:(r0)+,x1	y:(r4)+,y1
	mac	x1,y1,ax:(r0)+,x0	y:(r4)+,y0
	add	a,b	
	mac mac	x0,y0,ax:(r0)+,x1 x1,y1,a	y:(r4)+,y0
	move	bl,x:\$ff	À.(T.T.), ÀO
_end			
	bra	sbr	
	nop		
	nop		
	nop nop		
PROG_I			
	nop		
	nop		
XDAT_S	ናጥልጽጥ		
;	org	x:0	
-	dc	\$262EB9	
	dc	\$86F2FE	
	dc	\$E56A5F	
	dc dc	\$616CAC \$8FFD75	
	dc dc	\$9210A	
	dc	\$A06D7B	
	dc	\$CEA798	
	dc	\$8DFBF1	
	dc	\$A063D6	
	dc dc	\$6C6657 \$C2A544	
	dc dc	\$A3662D	
	dc	\$A4E762	
	dc	\$84F0F3	



dc $\xi E6F1B0$ dc $\xi B3829$ dc $\xi 8BF7AE$ dc $\xi 63A94F$ dc $\xi EF78DC$ dc $\xi 242DE5$ dc $\xi 8740DA$ dc $\xi 8746C8$ dc $\xi 2F6E86$ dc $\xi 4BE774$ dc $\xi 8F349D$ dc $\xi 4BFCE3$ dc $\xi 2D7D99$ dc $\xi 4BA85E$ dc $\xi 27A43F$ dc $\xi 25EC6A$ dc $\xi 25EC6A$ dc $\xi 25EC6A$ dc $\xi 2426D1$ dc $\xi 63BEC2$ dc $\xi 63BEC2$ dc $\xi 63BEC2$ dc $\xi 63BEC2$ dc $\xi 60E50E$ dc $\xi 60E50E$ dc $\xi 60E50E$ dc $\xi 25EC6A$ dc $\xi 25EC6A$ dc $\xi 2426D1$ dc $\xi 63BEC2$ dc $\xi 63BEC2$ dc $\xi 60E50E$ dc $\xi 60E50E$ dc $\xi 25E74D3$ dc $\xi 20A928$ dc $\xi 20A928$ dc $\xi 482FD4$ dc $\xi 7257D$ dc $\xi 482FD4$ dc $\xi 7257D$ dc $\xi 1A8C3$ dc $\xi 1A8C3$ dc $\xi 1A8C3$
--

YDAT_START

;

IL_DIANI	
org	y:0
dc	\$5B6DA
dc	\$C3F70B
dc	\$6A39E8
dc	\$81E801
dc	\$C666A6
dc	\$46F8E7
dc	\$AAEC94
dc	\$24233D
dc	\$802732
dc	\$2E3C83



Pr Consumption Benchmark

	dc	\$A43E00
	dc	\$C2B639
	dc	\$85A47E
	dc	
		\$ABFDDF
	dc	\$F3A2C
	dc	\$2D7CF5
	dc	\$E16A8A
	dc	\$ECB8FB
	dc	\$4BED18
	dc	\$43F371
	dc	\$83A556
	dc	\$E1E9D7
	dc	\$ACA2C4
	dc	\$8135AD
	dc	\$2CE0E2
	dc	\$8F2C73
	dc	\$432730
	dc	\$A87FA9
	dc	\$4A292E
	dc	\$A63CCF
	dc	\$6BA65C
	dc	\$E06D65
	dc	\$1AA3A
	dc	\$A1B6EB
	dc	\$48AC48
	dc	\$EF7AE1
	dc	\$6E3006
	dc	\$62F6C7
	dc	\$6064F4
	dc	\$87E41D
	dc	\$CB2692
	dc	\$2C3863
	dc	\$C6BC60
	dc	\$43A519
	dc	\$6139DE
	dc	\$ADF7BF
	dc	\$4B3E8C
	dc	\$6079D5
	dc	\$E0F5EA
	dc	\$8230DB
	dc	\$A3B778
	dc	\$2BFE51
	dc	\$E0A6B6
	dc	\$68FFB7
	dc	\$28F324
	dc	\$8F2E8D
	dc	\$667842
	dc	\$83E053
		•
	dc	\$A1FD90
	dc	\$6B2689
	dc	\$85B68E
	dc	\$622EAF
	dc	\$6162BC
	dc	\$E4A245
YDAT_	END	
-	-	
. * * * *	*******	***************************************
'		
;	DOTT	
;	EQUATES	S for DSP56L307 I/O registers and ports
;		
;	Last u <u>p</u>	pdate: June 11 1995
;		
;****	*******	***************************************



page 132,55,0,0,0 opt mex ioequ ident 1,0 ;------; EQUATES for I/O Port Programming ; Register Addresses ; ; Host port GPIO data Register M_HDR EQU \$FFFFC9 M_HDDR EQU \$FFFFC8 ; Host port GPIO direction Register ; Port C Control Register M_PCRC EQU \$FFFFBF ; Port C Direction Register M_PRRC EQU \$FFFFBE M_PDRC EQU \$FFFFBD ; Port C GPIO Data Register M_PCRD EQU \$FFFFAF ; Port D Control register M_PRRD EQU \$FFFFAE ; Port D Direction Data Register M_PDRD EQU \$FFFFAD ; Port D GPIO Data Register M_PCRE EQU \$FFFF9F ; Port E Control register M_PRRE EQU \$FFFF9E ; Port E Direction Register M_PDRE EQU \$FFFF9D ; Port E Data Register M_OGDB_EQU_\$FFFFFC ; OnCE GDB Register ;------; EQUATES for Host Interface ; ; ;-----Register Addresses ; M_HCR EQU \$FFFFC2 ; Host Control Register ; Host Status Register M_HSR EQU \$FFFFC3 ; Host Polarity Control Register ; Host Base Address Register M_HPCR_EQU_\$FFFFC4 M_HBAR EQU \$FFFFC5 ; Host Receive Register M_HRX EQU \$FFFFC6 M_HTX EQU \$FFFFC7 ; Host Transmit Register HCR bits definition M_HRIE EQU \$0 ; Host Receive interrupts Enable M_HTIE EQU \$1 ; Host Transmit Interrupt Enable M_HCIE EQU \$2 ; Host Command Interrupt Enable M_HF2 EQU \$3 ; Host Flag 2 M_HF3 EQU \$4 ; Host Flag 3 HSR bits definition M_HRDF_EQU \$0 ; Host Receive Data Full M_HTDE EQU \$1 ; Host Receive Data Empty ; Host Command Pending M_HCP EQU \$2 M_HF0 EQU \$3 ; Host Flag O M_HF1 EQU \$4 ; Host Flag 1 HPCR bits definition M_HGEN EQU \$0 ; Host Port GPIO Enable M_HA8EN EQU \$1 ; Host Address 8 Enable ; Host Address 9 Enable M_HA9EN EQU \$2 M_HCSEN EQU \$3 ; Host Chip Select Enable



Pr Consumption Benchmark

M HREN EOU \$4 ; Host Request Enable M HAEN EQU \$5 ; Host Acknowledge Enable M_HEN EQU \$6 ; Host Enable M_HOD EQU \$8 ; Host Request Open Drain mode ; Host Data Strobe Polarity ; Host Address Strobe Polarity ; Host Multiplexed bus select M_HDSP EQU \$9 M_HASP EQU \$A M_HMUX EQU \$B M HD HS EOU \$C ; Host Double/Single Strobe select M_HCSP EQU \$D ; Host Chip Select Polarity M_HRP_EQU \$E ; Host Request Polarity M_HAP EQU \$F ; Host Acknowledge Polarity ;------; EQUATES for Serial Communications Interface (SCI) ; ; ;------; SCI Transmit Data Register (high) ; SCI Transmit Data Register (middle) ; SCI Transmit Data Register (low) ; SCI Receive Data Register (high) ; SCI Receive Data Register (middle) ; SCI Receive Data Register (low) ; SCI Transmit Address Register ; SCI Control Register ; SCI State Register Addresses ; M_STXH EQU \$FFFF97 M_STXM EQU \$FFFF96 M_STXL EQU \$FFFF95 M_SRXH EQU \$FFFF9A M_SRXM EQU \$FFFF99 M_SRXL EQU \$FFFF98 M_STXA EQU \$FFFF94 M_SCR EQU \$FFFF9C M_SSR EQU \$FFFF93 ; SCI Status Register M_SCCR EQU \$FFFF9B ; SCI Clock Control Register ; SCI Control Register Bit Flags M_WDS EQU \$7 ; Word Select Mask (WDS0-WDS3) M_WDS0 EQU 0 ; Word Select 0 M_WDS1 EQU 1 ; Word Select 1 M_WDS2 EQU 2 ; Word Select 2 M_SSFTD EQU 3 ; SCI Shift Direction M_SBK EQU 4 ; Send Break M_WAKE EQU 5 ; Wakeup Mode Select M_RWU EQU 6 ; Receiver Wakeup Enable M_WOMS EQU 7 ; Wired-OR Mode Select M_SCRE EQU 8 ; SCI Receiver Enable M_SCTE EQU 9 ; SCI Transmitter Enable M_ILIE EQU 10 ; Idle Line Interrupt Enable ; SCI Receive Interrupt Enable M_SCRIE EQU 11 M_SCTIE EQU 12 ; SCI Transmit Interrupt Enable M_TMIE EQU 13 ; Timer Interrupt Enable M_TIR EQU 14 ; Timer Interrupt Rate M_SCKP EQU 15 ; SCI Clock Polarity M_REIE EQU 16 ; SCI Error Interrupt Enable (REIE) SCI Status Register Bit Flags ; M_TRNE EQU 0 ; Transmitter Empty M_TDRE EQU 1 ; Transmit Data Register Empty ; Receive Data Register Full M_RDRF EQU 2 M_IDLE EQU 3 ; Idle Line Flag M_OR EQU 4 ; Overrun Error Flag M_PE EQU 5 ; Parity Error M_FE EQU 6 ; Framing Error Flag M_R8 EQU 7 ; Received Bit 8 (R8) Address

SCI Clock Control Register ; M CD EOU \$FFF ; Clock Divider Mask (CD0-CD11) ; Clock Out Divider M_COD EQU 12 M_SCP EQU 13 ; Clock Prescaler M_RCM EQU 14 ; Receive Clock Mode Source Bit M_TCM EQU 15 ; Transmit Clock Source Bit ;------; EQUATES for Synchronous Serial Interface (SSI) ; ; ;-----; Register Addresses Of SSIO ; Register Addresses Of SSI0 M_TX00 EQU \$FFFFBC ; SSI0 Transmit Data Register 0 M_TX01 EQU \$FFFFBB ; SSI0 Transmit Data Register 1 M_TX02 EQU \$FFFFBA ; SSI0 Transmit Data Register 2 M_TSR0 EQU \$FFFFB9 ; SSI0 Time Slot Register M_RX0 EQU \$FFFFB8 ; SSI0 Receive Data Register M_CRB0 EQU \$FFFFB6 ; SSI0 Control Register B M_CRA0 EQU \$FFFFB5 ; SSI0 Control Register A M_TSMA0 EQU \$FFFFB4 ; SSI0 Transmit Slot Mask Register A M_RSMA0 EQU \$FFFFB2 ; SSI0 Receive Slot Mask Register A M_RSMB0 EQU \$FFFFB1 ; SSI0 Receive Slot Mask Register B Register Addresses Of SSI1 M_RSMB1 EQU \$FFFFA1 ; SSI1 Receive Slot Mask Register B SSI Control Register A Bit Flags ; M_PM EQU \$FF ; Prescale Modulus Select Mask (PM0-PM7) M_PSR EQU 11 ; Prescaler Range M_DC EQU \$1F000 ; Frame Rate Divider Control Mask (DC0-DC7) M_ALC EQU 18 ; Alignment Control (ALC) M_WL EQU \$380000 ; Word Length Control Mask (WL0-WL7) M_SSC1 EQU 22 ; Select SC1 as TR #0 drive enable (SSC1) SSI Control Register B Bit Flags ; M_OF EQU \$3 ; Serial Output Flag Mask M_OF0 EQU 0 ; Serial Output Flag 0 M_OF1 EQU 1 ; Serial Output Flag 1 ; Serial Control Direction Mask M_SCD EQU \$1C M_SCD0 EQU 2 ; Serial Control 0 Direction M_SCD1 EQU 3 ; Serial Control 1 Direction ; Serial Control 2 Direction M_SCD2 EQU 4 M_SCKD EQU 5 ; Clock Source Direction



M_SHFD E	QU 6	;	Shift Direction
M_FSL EQ	<u>U</u> \$180	;	Frame Sync Length Mask (FSL0-FSL1)
M_FSL0 E	:QU 7	;	Frame Sync Length 0
M_FSL1 E	QU 8	;	Frame Sync Length 1
M_FSR EQ	<u>1</u> U 9	;	Frame Sync Relative Timing
M_FSP EQ	<u>10</u>	;	Frame Sync Polarity
M_CKP EQ	<u>U</u> U 11	;	Clock Polarity
M_SYN EQ	<u>1</u> 2	;	Sync/Async Control
M_MOD EQ	U 13	;	SSI Mode Select
M_SSTE E	QU \$1C000	;	SSI Transmit enable Mask
M_SSTE2	EQU 14	;	SSI Transmit #2 Enable
M_SSTE1	EQU 15	;	SSI Transmit #1 Enable
M_SSTE0	EQU 16	;	SSI Transmit #0 Enable
M_SSRE E	QU 17	;	SSI Receive Enable
M_SSTIE	EQU 18		SSI Transmit Interrupt Enable
M_SSRIE			SSI Receive Interrupt Enable
M_STLIE			SSI Transmit Last Slot Interrupt Enable
M_SRLIE			SSI Receive Last Slot Interrupt Enable
M_STEIE			SSI Transmit Error Interrupt Enable
M_SREIE			SI Receive Error Interrupt Enable
		'	bi Receive hitor meeriupe mabie
;	SSI Status Register Bit Flag	S	
M_IF EQU	ı \$3	;	Serial Input Flag Mask
M_IF0 EQ			Serial Input Flag 0
M_IF1 EQ			Serial Input Flag 1
M_TFS EQ			Transmit Frame Sync Flag
M_RFS EQ			Receive Frame Sync Flag
M_TUE EQ	-		Transmitter Underrun Error FLag
			5
M_ROE EQ			Receiver Overrun Error Flag
M_TDE EQ			Transmit Data Register Empty
M_RDF EQ	<u>i</u> 0 7	;	Receive Data Register Full
;	SSI Transmit Slot Mask Regis	te	r A
M_SSTSA	EQU \$FFFF	;	SSI Transmit Slot Bits Mask A (TSO-TS15)
;	SSI Transmit Slot Mask Regis	te	r B
M_SSTSB	EQU ŞFFFF	;	SSI Transmit Slot Bits Mask B (TS16-TS31)
;	SSI Receive Slot Mask Regist	er	A
M_SSRSA	EQU \$FFFF	;	SSI Receive Slot Bits Mask A (RS0-RS15)
;	SSI Receive Slot Mask Regist	er	В
M_SSRSB	EQU \$FFFF	;	SSI Receive Slot Bits Mask B (RS16-RS31)
;			
;	EQUATES for Exception Proces		ng
;	Register Addresses		
	QU \$FFFFFF QU \$FFFFFE		Interrupt Priority Register Core Interrupt Priority Register Peripheral



;

Interrupt Priority Register Core (IPRC)

M IAL EOU \$7 ; IRQA Mode Mask M_IALO EQU O ; IRQA Mode Interrupt Priority Level (low) M_IAL1 EQU 1 ; IRQA Mode Interrupt Priority Level (high) M_IAL2 EQU 2 ; IRQA Mode Trigger Mode M IBL EOU \$38 ; IRQB Mode Mask M IBLO EOU 3 ; IRQB Mode Interrupt Priority Level (low) M_IBL1 EQU 4 ; IRQB Mode Interrupt Priority Level (high) ; IRQB Mode Trigger Mode M IBL2 EOU 5 ; IRQC Mode Mask M ICL EOU \$1C0 M ICLO EOU 6 ; IRQC Mode Interrupt Priority Level (low) M ICL1 EOU 7 ; IRQC Mode Interrupt Priority Level (high) ; IRQC Mode Trigger Mode M ICL2 EOU 8 M_IDL EQU \$E00 ; IRQD Mode Mask ; IRQD Mode Interrupt Priority Level (low) M_IDL0 EQU 9 M_IDL1 EQU 10 ; IRQD Mode Interrupt Priority Level (high) ; IRQD Mode Trigger Mode M_IDL2 EQU 11 M_D0L EQU \$3000 ; DMA0 Interrupt priority Level Mask M_DOLO EQU 12 ; DMA0 Interrupt Priority Level (low) M_DOL1 EQU 13 ; DMA0 Interrupt Priority Level (high) M_D1L EQU \$C000 ; DMA1 Interrupt Priority Level Mask M_D1L0 EQU 14 ; DMA1 Interrupt Priority Level (low) M_D1L1 EQU 15 ; DMA1 Interrupt Priority Level (high) M_D2L EQU \$30000 ; DMA2 Interrupt priority Level Mask M_D2L0 EQU 16 ; DMA2 Interrupt Priority Level (low) M D2L1 EOU 17 ; DMA2 Interrupt Priority Level (high) M_D3L EQU \$C0000 ; DMA3 Interrupt Priority Level Mask ... EQU 20 M_D4L1 EQU 21 M_D5L EQU \$C00000 M_D5L0 EQU 22 M_D5L1 EQU 23 M_D3L0 EQU 18 ; DMA3 Interrupt Priority Level (low) ; DMA3 Interrupt Priority Level (high) ; DMA4 Interrupt priority Level Mask ; DMA4 Interrupt Priority Level (low) ; DMA4 Interrupt Priority Level (high) ; DMA5 Interrupt priority Level Mask ; DMA5 Interrupt Priority Level (low) ; DMA5 Interrupt Priority Level (high) Interrupt Priority Register Peripheral (IPRP) ; M_HPL EQU \$3 ; Host Interrupt Priority Level Mask M_HPL0 EQU 0 ; Host Interrupt Priority Level (low) M_HPL1 EQU 1 ; Host Interrupt Priority Level (high) M_SOL EQU \$C ; SSIO Interrupt Priority Level Mask M_SOLO EQU 2 ; SSIO Interrupt Priority Level (low) M_SOL1 EQU 3 ; SSIO Interrupt Priority Level (high) M_S1L EQU \$30 ; SSI1 Interrupt Priority Level Mask M_S1L0 EQU 4 ; SSI1 Interrupt Priority Level (low) M_S1L1 EQU 5 ; SSI1 Interrupt Priority Level (high) M_SCL EQU \$C0 ; SCI Interrupt Priority Level Mask M_SCL0 EQU 6 ; SCI Interrupt Priority Level (low) M_SCL1 EQU 7 ; SCI Interrupt Priority Level (high) ; TIMER Interrupt Priority Level Mask M_TOL EQU \$300 M_TOLO EQU 8 ; TIMER Interrupt Priority Level (low) M_TOL1 EQU 9 ; TIMER Interrupt Priority Level (high) ;------; EQUATES for TIMER ; ;



er Consumption Benchmark

```
Register Addresses Of TIMER0
 ;
 M_TCSR0 EQU $FFFF8F
                                       ; Timer 0 Control/Status Register
M_TCSRU EQU $FFFF8F
M_TLR0 EQU $FFFF8E
M_TCPR0 EQU $FFFF8D
M_TCR0 EQU $FFFF8C
                                       ; TIMER0 Load Reg
                                       ; TIMER0 Compare Register
                                         ; TIMER0 Count Register
        Register Addresses Of TIMER1
 ;
M_TCSR1 EQU $FFFF8B; TIMER1 Control/Status RegisterM_TLR1 EQU $FFFF8A; TIMER1 Load RegM_TCPR1 EQU $FFFF89; TIMER1 Compare RegisterM_TCR1 EQU $FFFF88; TIMER1 Count Register
         Register Addresses Of TIMER2
 ;
M_TCSR2 EQU $FFFF87; TIMER2 Control/Status RegisterM_TLR2 EQU $FFFF86; TIMER2 Load RegM_TCPR2 EQU $FFFF85; TIMER2 Compare RegisterM_TCR2 EQU $FFFF84; TIMER2 Count RegisterM_TPLR EQU $FFFF83; TIMER Prescaler Load RegisterM_TPCR EQU $FFFF82; TIMER Prescalar Count Period
         Timer Control/Status Register Bit Flags
 ;
M_TE EQU 0
                                       ; Timer Enable
M_TOIE EQU 1
                                       ; Timer Overflow Interrupt Enable
M_TCIE EQU 2
                                       ; Timer Compare Interrupt Enable
M_TC EQU $F0
                                       ; Timer Control Mask (TC0-TC3)
M_INV EQU 8
                                       ; Inverter Bit
M_TRM EQU 9
                                       ; Timer Restart Mode
M_DIR EQU 11
                                       ; Direction Bit
M_DI EQU 12
                                       ; Data Input
                                       ; Data Output
M_DO EQU 13
M_PCE EQU 15
                                        ; Prescaled Clock Enable
M_TOF EQU 20
                                       ; Timer Overflow Flag
M_TCF EQU 21
                                         ; Timer Compare Flag
         Timer Prescaler Register Bit Flags
 ;
M_PS EQU $600000
                                       ; Prescaler Source Mask
M_PS0 EQU 21
M_PS1 EQU 22
       Timer Control Bits
M_TC0 EQU 4
                                       ; Timer Control 0
                                       ; Timer Control 1
M_TC1 EQU 5
M_TC1 EQU 5
M_TC2 EQU 6
                                       ; Timer Control 2
M_TC3 EQU 7
                                        ; Timer Control 3
 ;-----
 ;
        EQUATES for Direct Memory Access (DMA)
 ;
 ;
 Register Addresses Of DMA
M_DSTR EQU FFFFF4 ; DMA Status Register
M_DOR0 EQU $FFFFF3 ; DMA Offset Register
M_DOR1 EQU $FFFFF2 ; DMA Offset Register
                                       ; DMA Offset Register 0
                                       ; DMA Offset Register 1
```



M DOR2 EOU \$FFFFF1 ; DMA Offset Register 2 ; DMA Offset Register 3 M_DOR3 EQU \$FFFFF0 Register Addresses Of DMA0 ; M DSR0 EOU \$FFFFEF ; DMA0 Source Address Register M_DSR0 EQU \$FFFFEF M_DDR0 EQU \$FFFFEE M_DCC0 EQU \$FFFFED M_DCR0 EQU \$FFFFEC ; DMA0 Destination Address Register ; DMA0 Counter ; DMA0 Control Register Register Addresses Of DMA1 : M DSR1 EOU SFFFFEB ; DMA1 Source Address Register M_DDR1 EQU \$FFFFEA ; DMA1 Destination Address Register M_DCO1 EQU \$FFFFE9 ; DMA1 Counter M_DCR1 EQU \$FFFFE8 ; DMA1 Control Register Register Addresses Of DMA2 ; M_DSR2 EQU \$FFFFE7 ; DMA2 Source Address Register M_DDR2 EQU \$FFFFE6 M_DCO2 EQU \$FFFFE5 ; DMA2 Destination Address Register ; DMA2 Counter M_DCR2 EQU \$FFFFE4 ; DMA2 Control Register Register Addresses Of DMA4 ; M_DSR3 EQU \$FFFFE3 ; DMA3 Source Address Register M_DDR3 EQU \$FFFFE2 M_DCO3 EQU \$FFFFE1 ; DMA3 Destination Address Register ; DMA3 Counter M_DCR3 EQU \$FFFFE0 ; DMA3 Control Register ; Register Addresses Of DMA4 M_DSR4 EQU \$FFFFDF ; DMA4 Source Address Register M_DDR4 EQU \$FFFFDE M DCO4 EOU \$FFFFDD ; DMA4 Destination Address Register M_DCO4 EQU \$FFFFDD ; DMA4 Counter M_DCR4 EQU \$FFFFDC ; DMA4 Control Register Register Addresses Of DMA5 ; M_DSR5 EQU \$FFFFDB; DMA5 Source Address RegisterM_DDR5 EQU \$FFFFDA; DMA5 Destination Address RegisterM_DC05 EQU \$FFFFD9; DMA5 Counter M_DCR5 EQU \$FFFFD8 ; DMA5 Control Register ; DMA Control Register M_DSS EQU \$3 ; DMA Source Space Mask (DSS0-Dss1) M_DSS0 EQU 0 ; DMA Source Memory space 0 ; DMA Source Memory space 1 M_DSS1 EQU 1 ; DMA Destination Space Mask (DDS-DDS1) M_DDS EQU \$C M_DDS0 EQU 2 ; DMA Destination Memory Space 0 ; DMA Destination Memory Space 1 M_DDS1 EQU 3 ; DMA Address Mode Mask (DAM5-DAM0) M_DAM EQU \$3f0 ; DMA Address Mode 0 M_DAMO EQU 4 ; DMA Address Mode 1 M_DAM1 EQU 5 ; DMA Address Mode 2 M_DAM2 EQU 6 ; DMA Address Mode 3 M_DAM3 EQU 7 M_DAM4 EQU 8 ; DMA Address Mode 4 ; DMA Address Mode 5 M_DAM5 EQU 9 M_D3D EQU 10 ; DMA Three Dimensional Mode



er Consumption Benchmark

```
M DRS EOU $F800
                                    ; DMA Request Source Mask (DRS0-DRS4)
M_DCON EQU 16
                                    ; DMA Continuous Mode
M_DPR EQU $60000
                                   ; DMA Channel Priority
M_DPR0 EQU 17
                                   ; DMA Channel Priority Level (low)
                                   ; DMA Channel Priority Level (high)
M_DPR1_EQU_18
M_DTM EQU $380000
                                   ; DMA Transfer Mode Mask (DTM2-DTM0)
                                   ; DMA Transfer Mode 0
M_DTM0 EQU 19
M_DTM1 EQU 20
                                   ; DMA Transfer Mode 1
M_DTM2_EQU_21
                                    ; DMA Transfer Mode 2
                                    ; DMA Interrupt Enable bit
M_DIE EQU 22
M DE EOU 23
                                    ; DMA Channel Enable bit
      DMA Status Register
;
M_DTD EQU $3F
                                   ; Channel Transfer Done Status MASK (DTD0-DTD5)
M_DTD0 EQU 0
                                   ; DMA Channel Transfer Done Status 0
M_DTD1 EQU 1
                                  ; DMA Channel Transfer Done Status 1
M_DTD2_EQU_2
                                   ; DMA Channel Transfer Done Status 2
M_DTD3 EQU 3
                                  ; DMA Channel Transfer Done Status 3
M_DTD4 EQU 4
                                  ; DMA Channel Transfer Done Status 4
M_DTD5 EQU 5
                                  ; DMA Channel Transfer Done Status 5
M_DACT_EQU_8
                                  ; DMA Active State
M_DCH EQU $E00
                                  ; DMA Active Channel Mask (DCH0-DCH2)
M_DCH0 EQU 9
                                  ; DMA Active Channel 0
M_DCH1 EQU 10
                                   ; DMA Active Channel 1
M_DCH2 EQU 11
                                   ; DMA Active Channel 2
;------
;
        EQUATES for Enhanced Filter Co-Processor (EFCOP)
;
;
;------
M_FDIREQU$FFFFB0; EFCOP Data Input RegisterM_FDOREQU$FFFFB1; EFCOP Data Output RegisterM_FKIREQU$FFFFB2; EFCOP K-Constant RegisterM_FCNTEQU$FFFFB3; EFCOP Filter CounterM_FCSREQU$FFFFB4; EFCOP Control Status RegisterM_FACREQU$FFFFB5; EFCOP ALU Control RegisterM_FDBAEQU$FFFFB6; EFCOP Data Base AddressM_FCBAEQU$FFFFB7; EFCOP Coefficient Base AddressM_FDCHEQU$FFFFB8; EFCOP Decimation/Channel Register
;------
;
        EQUATES for Phase Locked Loop (PLL)
;
;-----
        Register Addresses Of PLL
;
M_PCTL EQU $FFFFFD
                                  ; PLL Control Register
       PLL Control Register
;
M_MF EQU $FFF : Multiplication Factor Bits Mask (MF0-MF11)
                  ; Division Factor Bits Mask (DF0-DF2)
M_DF EQU $7000
                                   ; XTAL Range select bit
M_XTLR EQU 15
M_XTLD EQU 16
                                   ; XTAL Disable Bit
                                   ; STOP Processing State Bit
M_PSTP EQU 17
M_PEN EQU 18
                                    ; PLL Enable Bit
```



M PCOD EOU 19 ; PLL Clock Output Disable Bit M_PD EQU \$F00000 ; PreDivider Factor Bits Mask (PD0-PD3) ;------; EQUATES for BIU ; ; ;------Register Addresses Of BIU ; M_BCR EQU \$FFFFFB ; Bus Control Register ; DRAM Control Register M_DCR EQU \$FFFFFA ; Address Attribute Register 0 M_AARO EQU \$FFFFF9 M_AAR1 EQU \$FFFFF8 ; Address Attribute Register 1 M_AAR2 EQU \$FFFFF7 ; Address Attribute Register 2 M_AAR3 EQU \$FFFFF6 ; Address Attribute Register 3 M_IDR EQU \$FFFFF5 ; ID Register ; Bus Control Register M_BAOW EQU \$1F ; Area 0 Wait Control Mask (BA0W0-BA0W4) M_BA1W EQU \$3E0 ; Area 1 Wait Control Mask (BA1W0-BA14) M_BA2W EQU \$1C00 ; Area 2 Wait Control Mask (BA2W0-BA2W2) M_BA3W EQU \$E000 ; Area 3 Wait Control Mask (BA3W0-BA3W3) M_BDFW EQU \$1F0000 ; Default Area Wait Control Mask (BDFW0-BDFW4) M_BBS EQU 21 ; Bus State M_BLH EQU 22 ; Bus Lock Hold M_BRH EQU 23 ; Bus Request Hold DRAM Control Register ; M_BCW EQU \$3 ; In Page Wait States Bits Mask (BCW0-BCW1) M_BRW EQU \$C ; Out Of Page Wait States Bits Mask (BRW0-BRW1) M_BPS EQU \$300 ; DRAM Page Size Bits Mask (BPS0-BPS1) M_BPLE EQU 11 ; Page Logic Enable M_BME EQU 12 ; Mastership Enable M_BRE EQU 13 ; Refresh Enable M_BSTR EQU 14 ; Software Triggered Refresh M_BRF EQU \$7F8000 ; Refresh Rate Bits Mask (BRF0-BRF7) M_BRP EQU 23 ; Refresh prescaler Address Attribute Registers ; M_BAT EQU \$3 ; Ext. Access Type and Pin Def. Bits Mask (BAT0-BAT1) M_BAAP EQU 2 ; Address Attribute Pin Polarity M_BPEN EQU 3 ; Program Space Enable M BXEN EQU 4 ; X Data Space Enable M_BYEN EQU 5 ; Y Data Space Enable M BAM EQU 6 ; Address Muxing ; Packing Enable M_BPAC_EQU_7 M_BNC EQU \$F00 ; Number of Address Bits to Compare Mask (BNC0-BNC3) M_BAC EQU \$FFF000 ; Address to Compare Bits Mask (BAC0-BAC11) control and status bits in SR ; M_CP EQU \$c00000 ; mask for CORE-DMA priority bits in SR M CA EQU 0 ; Carry ; Overflow M_V EQU 1



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M_Z EQU 2	Zero
	Negative
	Unnormalized
- ~ ·	Extension
M_L EQU 6	: Limit
= ~	Scaling Bit
M_IO EQU 8	-
	Interupt Mask Bit 1
M_S0 EQU 10	Scaling Mode Bit 0
= ~	Scaling Mode Bit 1
	Sixteen_Bit Compatibility
M_DM EQU 14	Double Precision Multiply
M_LF EQU 15	DO-Loop Flag
M_FV EQU 16	DO-Forever Flag
M_SA EQU 17	Sixteen-Bit Arithmetic
M_CE EQU 19	Instruction Cache Enable
M_SM EQU 20	Arithmetic Saturation
M_RM EQU 21	Rounding Mode
M_CPO EQU 22	bit 0 of priority bits in SR
M_CP1 EQU 23	bit 1 of priority bits in SR
; control and status bits in OM	_
, concror and search bres in on	R
	R • mask for CORE-DMA priority bits in OMR
M_CDP EQU \$300	
M_CDP EQU \$300 M_MA equ0	mask for CORE-DMA priority bits in OMR
M_CDP EQU \$300 M_MA equ0 M_MB equ1	mask for CORE-DMA priority bits in OMR Operating Mode A
M_CDP EQU \$300 M_MA equ0 M_MB equ1 M_MC equ2	: mask for CORE-DMA priority bits in OMR : Operating Mode A : Operating Mode B
M_CDP EQU \$300 M_MA equ0 M_MB equ1 M_MC equ2	mask for CORE-DMA priority bits in OMR Operating Mode A Operating Mode B Operating Mode C
M_CDP EQU \$300 M_MA equ0 M_MB equ1 M_MC equ2 M_MD equ3 M_EBD EQU 4	mask for CORE-DMA priority bits in OMR Operating Mode A Operating Mode B Operating Mode C Operating Mode D
M_CDP EQU \$300 M_MA equ0 M_MB equ1 M_MC equ2 M_MD equ3 M_EBD EQU 4 M_SD EQU 6	 mask for CORE-DMA priority bits in OMR Operating Mode A Operating Mode B Operating Mode C Operating Mode D External Bus Disable bit in OMR
M_CDP EQU \$300 M_MA equ0 M_MB equ1 M_MC equ2 M_MD equ3 M_EBD EQU 4 M_SD EQU 6 M_MS EQU 7	 mask for CORE-DMA priority bits in OMR Operating Mode A Operating Mode B Operating Mode C Operating Mode D External Bus Disable bit in OMR Stop Delay
M_CDP EQU \$300 M_MA equ0 M_MB equ1 M_MC equ2 M_MD equ3 M_EBD EQU 4 M_SD EQU 6 M_MS EQU 7	 mask for CORE-DMA priority bits in OMR Operating Mode A Operating Mode B Operating Mode C Operating Mode D External Bus Disable bit in OMR Stop Delay Memory Switch bit in OMR
M_CDP EQU \$300 M_MA equ0 M_MB equ1 M_MC equ2 M_MD equ3 M_EBD EQU 4 M_SD EQU 6 M_MS EQU 7 M_CDP0 EQU 8 M_CDP1 EQU 9	 mask for CORE-DMA priority bits in OMR Operating Mode A Operating Mode B Operating Mode C Operating Mode D External Bus Disable bit in OMR Stop Delay Memory Switch bit in OMR bit 0 of priority bits in OMR bit 1 of priority bits in OMR
M_CDP EQU \$300 M_MA equ0 M_MB equ1 M_MC equ2 M_MD equ3 M_EBD EQU 4 M_SD EQU 6 M_MS EQU 7 M_CDP0 EQU 8 M_CDP1 EQU 9	 mask for CORE-DMA priority bits in OMR Operating Mode A Operating Mode B Operating Mode C Operating Mode D External Bus Disable bit in OMR Stop Delay Memory Switch bit in OMR bit 0 of priority bits in OMR
M_CDP EQU \$300 M_MA equ0 M_MB equ1 M_MC equ2 M_MD equ3 M_EBD EQU 4 M_SD EQU 6 M_MS EQU 7 M_CDP0 EQU 8 M_CDP1 EQU 9 M_BEN EQU 10 M_TAS EQU 11	<pre>mask for CORE-DMA priority bits in OMR Operating Mode A Operating Mode B Operating Mode C Operating Mode D External Bus Disable bit in OMR Stop Delay Memory Switch bit in OMR bit 0 of priority bits in OMR bit 1 of priority bits in OMR Burst Enable TA Synchronize Select</pre>
M_CDP EQU \$300 M_MA equ0 M_MB equ1 M_MC equ2 M_MD equ3 M_EBD EQU 4 M_SD EQU 6 M_MS EQU 7 M_CDP0 EQU 8 M_CDP1 EQU 9 M_BEN EQU 10 M_TAS EQU 11 M_BRT EQU 12	<pre>mask for CORE-DMA priority bits in OMR Operating Mode A Operating Mode B Operating Mode C Operating Mode D External Bus Disable bit in OMR Stop Delay Memory Switch bit in OMR bit 0 of priority bits in OMR bit 1 of priority bits in OMR Burst Enable TA Synchronize Select Bus Release Timing</pre>
M_CDP EQU \$300 M_MA equ0 M_MB equ1 M_MC equ2 M_MD equ3 M_EBD EQU 4 M_SD EQU 6 M_MS EQU 7 M_CDP0 EQU 8 M_CDP1 EQU 9 M_BEN EQU 10 M_TAS EQU 11 M_BRT EQU 12 M_ATE EQU 15	<pre>mask for CORE-DMA priority bits in OMR Operating Mode A Operating Mode B Operating Mode C Operating Mode D External Bus Disable bit in OMR Stop Delay Memory Switch bit in OMR bit 0 of priority bits in OMR bit 1 of priority bits in OMR Burst Enable TA Synchronize Select Bus Release Timing Address Tracing Enable bit in OMR.</pre>
M_CDP EQU \$300 M_MA equ0 M_MB equ1 M_MC equ2 M_MD equ3 M_EBD EQU 4 M_SD EQU 6 M_MS EQU 7 M_CDP0 EQU 8 M_CDP1 EQU 9 M_BEN EQU 10 M_TAS EQU 11 M_BRT EQU 12 M_ATE EQU 15 M_XYS EQU 16	<pre>mask for CORE-DMA priority bits in OMR Operating Mode A Operating Mode B Operating Mode C Operating Mode D External Bus Disable bit in OMR Stop Delay Memory Switch bit in OMR bit 0 of priority bits in OMR bit 1 of priority bits in OMR bit 1 of priority bits in OMR Burst Enable TA Synchronize Select Bus Release Timing Address Tracing Enable bit in OMR. </pre>
M_CDP EQU \$300 M_MA equ0 M_MB equ1 M_MC equ2 M_MD equ3 M_EBD EQU 4 M_SD EQU 6 M_MS EQU 7 M_CDP0 EQU 8 M_CDP1 EQU 9 M_BEN EQU 10 M_TAS EQU 11 M_BRT EQU 12 M_ATE EQU 15 M_XYS EQU 16 M_EUN EQU 17	<pre>mask for CORE-DMA priority bits in OMR Operating Mode A Operating Mode B Operating Mode C Operating Mode D External Bus Disable bit in OMR Stop Delay Memory Switch bit in OMR bit 0 of priority bits in OMR bit 1 of priority bits in OMR bit 1 of priority bits in OMR Burst Enable TA Synchronize Select Bus Release Timing Address Tracing Enable bit in OMR. Extensed stack UNderflow flag in OMR.</pre>
M_CDP EQU \$300 M_MA equ0 M_MB equ1 M_MC equ2 M_MD equ3 M_EBD EQU 4 M_SD EQU 6 M_MS EQU 7 M_CDP0 EQU 8 M_CDP1 EQU 9 M_BEN EQU 10 M_TAS EQU 11 M_BRT EQU 12 M_ATE EQU 15 M_XYS EQU 16 M_EUN EQU 17 M_EOV EQU 18	<pre>mask for CORE-DMA priority bits in OMR Operating Mode A Operating Mode B Operating Mode C Operating Mode D External Bus Disable bit in OMR Stop Delay Memory Switch bit in OMR bit 0 of priority bits in OMR bit 1 of priority bits in OMR Burst Enable TA Synchronize Select Bus Release Timing Address Tracing Enable bit in OMR. Extensed stack UNderflow flag in OMR. Extended stack OVerflow flag in OMR.</pre>
M_CDP EQU \$300 M_MA equ0 M_MB equ1 M_MC equ2 M_MD equ3 M_EBD EQU 4 M_SD EQU 6 M_MS EQU 7 M_CDP0 EQU 8 M_CDP1 EQU 9 M_BEN EQU 10 M_TAS EQU 11 M_BRT EQU 12 M_ATE EQU 15 M_XYS EQU 16 M_EUN EQU 17 M_EOV EQU 18	<pre>mask for CORE-DMA priority bits in OMR Operating Mode A Operating Mode B Operating Mode C Operating Mode D External Bus Disable bit in OMR Stop Delay Memory Switch bit in OMR bit 0 of priority bits in OMR bit 1 of priority bits in OMR bit 1 of priority bits in OMR Burst Enable TA Synchronize Select Bus Release Timing Address Tracing Enable bit in OMR. Extensed stack UNderflow flag in OMR.</pre>

```
;
  EQUATES for DSP56L307 interrupts
;
;
  Last update: June 11 1995
;
;
page 132,55,0,0,0
   opt
       mex
intequ ident 1,0
   if
       @DEF(I_VEC)
                  ;leave user definition as is.
   else
```



I_VEC EQU \$0 endif •_____ ; Non-Maskable interrupts I_RESET EQU I_VEC+\$00 I_STACK EQU I_VEC+\$02 I_ILL EQU I_VEC+\$04 I_DBG EQU I_VEC+\$06 I TRAP EOU I VEC+\$08 I NMI EOU I VEC+\$0A

; Hardware RESET ; Stack Error ; Illegal Instruction ; Debug Request ; Trap ; Non Maskable Interrupt :-----; Interrupt Request Pins ;------I_IRQA EQU I_VEC+\$10 ; IRQA I_IRQB EQU I_VEC+\$12 ; IRQB I_IRQC EQU I_VEC+\$14 ; IRQC I_IRQD EQU I_VEC+\$16 ; IRQD ; DMA Interrupts ;------I_DMA0 EQU I_VEC+\$18 ; DMA Channel 0 ; DMA Channel 1 I_DMA1 EQU I_VEC+\$1A I_DMA2 EQU I_VEC+\$1C ; DMA Channel 2 I_DMA3 EQU I_VEC+\$1E I_DMA4 EQU I_VEC+\$20 ; DMA Channel 3 ; DMA Channel 4 ; DMA Channel 5 I_DMA5 EQU I_VEC+\$22 ;------; Timer Interrupts ;------I_TIMOC EQU I_VEC+\$24 ; TIMER 0 compare I_TIM0OF EQU I_VEC+\$26 ; TIMER 0 overflow I_TIM1C EQU I_VEC+\$28 ; TIMER 1 compare I_TIM1OF EQU I_VEC+\$2A ; TIMER 1 overflow I_TIM2C EQU I_VEC+\$2C ; TIMER 2 compare I_TIM2OF EQU I_VEC+\$2E ; TIMER 2 overflow ;-----; ESSI Interrupts ;-----; ESSIO Receive Data ; ESSIO Receive Data w/ exception Status ; ESSIO Receive last slot I_SIORD EQU I_VEC+\$30 I_SIORDE EQU I_VEC+\$32 I_SIORLS EQU I_VEC+\$34 I_SIOTD EQU I_VEC+\$36 ; ESSIO Transmit data ; ESSI0 Transmit Data w/ exception Status ; ESSI0 Transmit last slot I_SIOTDE EQU I_VEC+\$38 I_SIOTLS EQU I_VEC+\$3A ; ESSI1 Receive Data I_SI1RD EQU I_VEC+\$40 ; ESSI1 Receive Data w/ exception Status I_SI1RDE EQU I_VEC+\$42 I_SI1RLS EQU I_VEC+\$44 ; ESSI1 Receive last slot I_SI1TD EQU I_VEC+\$46 ; ESSI1 Transmit data ; ESSI1 Transmit Data w/ exception Status I_SI1TDE EQU I_VEC+\$48

; ESSI1 Transmit last slot I_SI1TLS EQU I_VEC+\$4A :-----; SCI Interrupts I_SCIRD EQU I_VEC+\$50 ; SCI Receive Data I_SCIRDE EQU I_VEC+\$52 ; SCI Receive Data With Exception Status I_SCITD EQU I_VEC+\$54 ; SCI Receive Data With Exception Status ; SCI Transmit Data I_SCITD EQU I_VEC+\$54

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I_SCIIL EQU I_VEC+\$56 I_SCITM EQU I_VEC+\$58	; SCI Idle Line ; SCI Timer
;; HOST Interrupts :	
I_HRDF EQU I_VEC+\$60 I_HTDE EQU I_VEC+\$62 I_HC EQU I_VEC+\$64	; Host Receive Data Full ; Host Transmit Data Empty ; Default Host Command
;; EFCOP Filter Interrupts ;	
I_FDIIE EQU I_VEC+\$68 I_FDOIE EQU I_VEC+\$6A	; EFilter input buffer empty ; EFilter output buffer full
;; INTERRUPT ENDING ADDRESS	
, I_INTEND EQU I_VEC+\$FF	; last address of interrupt vector space









Ordering Information

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Part	Supply Voltage	Package Type	Pin Count	Core Frequency (MHz)	Solder Spheres	Order Number
DSP56L307	1.8 V core	Molded Array Process-Ball Grid Array	196	160	Lead-free	XC56L307VL160
	3.3 V I/O	(MAP-BGA)			Lead-bearing	XC56L307VF160

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